

NUREG/CR-6268
Vol. 4
INEEL/EXT-97-00696

Common-Cause Failure Database and Analysis System: Software Reference Manual

Prepared by
K. J. Kvarfordt, M. J. Cebull, S. T. Wood/INEEL
A. Mosleh/Univ. of MD

Idaho National Engineering and Environmental Laboratory
University of Maryland

U.S. Nuclear Regulatory Commission



AVAILABILITY NOTICE

Availability of Reference Materials Cited in NRC Publications

Most documents cited in NRC publications will be available from one of the following sources:

1. The NRC Public Document Room, 2120 L Street, NW., Lower Level, Washington, DC 20555-0001
2. The Superintendent of Documents, U.S. Government Printing Office, P. O. Box 37082, Washington, DC 20402-9328
3. The National Technical Information Service, Springfield, VA 22161-0002

Although the listing that follows represents the majority of documents cited in NRC publications, it is not intended to be exhaustive.

Referenced documents available for inspection and copying for a fee from the NRC Public Document Room include NRC correspondence and internal NRC memoranda; NRC bulletins, circulars, information notices, inspection and investigation notices; licensee event reports; vendor reports and correspondence; Commission papers; and applicant and licensee documents and correspondence.

The following documents in the NUREG series are available for purchase from the Government Printing Office: formal NRC staff and contractor reports, NRC-sponsored conference proceedings, international agreement reports, grantee reports, and NRC booklets and brochures. Also available are regulatory guides, NRC regulations in the *Code of Federal Regulations*, and *Nuclear Regulatory Commission Issuances*.

Documents available from the National Technical Information Service include NUREG-series reports and technical reports prepared by other Federal agencies and reports prepared by the Atomic Energy Commission, forerunner agency to the Nuclear Regulatory Commission.

Documents available from public and special technical libraries include all open literature items, such as books, journal articles, and transactions. *Federal Register* notices, Federal and State legislation, and congressional reports can usually be obtained from these libraries.

Documents such as theses, dissertations, foreign reports and translations, and non-NRC conference proceedings are available for purchase from the organization sponsoring the publication cited.

Single copies of NRC draft reports are available free, to the extent of supply, upon written request to the Office of Administration, Distribution and Mail Services Section, U.S. Nuclear Regulatory Commission, Washington, DC 20555-0001.

Copies of industry codes and standards used in a substantive manner in the NRC regulatory process are maintained at the NRC Library, Two White Flint North, 11545 Rockville Pike, Rockville, MD 20852-2738, for use by the public. Codes and standards are usually copyrighted and may be purchased from the originating organization or, if they are American National Standards, from the American National Standards Institute, 1430 Broadway, New York, NY 10018-3308.

DISCLAIMER NOTICE

This report was prepared as an account of work sponsored by an agency of the United States Government. Neither the United States Government nor any agency thereof, nor any of their employees, makes any warranty, expressed or implied, or assumes any legal liability or responsibility for any third party's use, or the results of such use, of any information, apparatus, product, or process disclosed in this report, or represents that its use by such third party would not infringe privately owned rights.

NUREG/CR-6268
Vol. 4
INEEL/EXT-97-00696

Common-Cause Failure Database and Analysis System: Software Reference Manual

Manuscript Completed: June 1998
Date Published: June 1998

Prepared by
K. J. Kvarfordt, M. J. Cebull, S. T. Wood/INEEL
A. Mosleh/Univ. of MD

Idaho National Engineering and Environmental Laboratory
Lockheed Martin Idaho Technologies Company
Idaho Falls, ID 83415

Subcontractor:
Department of Materials and Nuclear Engineering
University of Maryland
College Park, MD 20742-2115

Prepared for
Safety Programs Division
Office for Analysis and Evaluation of Operational Data
U.S. Nuclear Regulatory Commission
Washington, DC 20555-0001
NRC Job Code E8247



1911

THE UNIVERSITY OF CHICAGO

PHYSICS DEPARTMENT

REPORT ON THE PROGRESS OF WORK

BY

ROBERT A. MILLER

1911

CHICAGO, ILL.

UNIVERSITY OF CHICAGO PRESS

ABSTRACT

This volume of the Common-Cause Failure Database and Analysis System report provides an overview of common cause failure methods for use in the U.S. commercial nuclear power industry. It summarizes how data (on common cause failure events) are gathered, evaluated, and coded. It then describes the process for estimating probabilistic risk assessment (PRA) common cause failure parameters. It also references other volumes of this report for specific details.

Equipment failures that contribute to common cause failure events are identified through searches of Licensee Event Reports (LERs) and Nuclear Plant Reliability Data System (NPRDS) failure reports. Once common cause failure events are identified by reviewing reports of equipment failures, INEEL staff enters the event information into a personal computer data analysis system (CCF system) using the method presented in this and companion volumes. The events stored in the CCF system are utilized for common cause failure PRA parameter estimations using common cause failure quantification methods.

MEMORANDUM

TO : SAC, [illegible]

FROM : [illegible]

SUBJECT: [illegible]

[illegible text]

[illegible text]

CONTENTS

ABSTRACT	iii
EXECUTIVE SUMMARY	xi
ACRONYMS	xiii
1. INTRODUCTION	1
1.1 Hardware Software and Requirements	1
1.1.1 CCFDOS Software Requirements	1
1.1.2 CCFWIN Software Requirements	1
1.1.3 CCFDOS Hardware Requirements	1
1.1.4 CCFWIN Hardware Requirements	2
1.2 Installing CCF	2
1.2.1 Installing CCFDOS	2
1.2.2 Installing CCFWIN	3
1.3 Starting CCF	3
1.3.1 Starting CCFDOS	3
1.3.2 Starting CCFWIN	4
1.4 Function Keys	5
1.5 CCF Windows Version	5
1.5.1 Exiting CCFWIN	5
1.5.2 The Windows Interface	5
1.6 NPRDS Conditions of Use	6
2. SEARCH	7
2.1 Search Fields	9
2.2 Using Wildcards	11
2.3 Saving Search Results	11
2.4 Saving Results in Application	12

2.5	Search Reports	12
3.	GENERIC	17
3.1	Editing Applications	18
3.1.1	Modifying an Application	19
3.1.2	Adding an Application	20
3.2	Event Analysis	21
3.2.1	GENERIC Event Analysis	23
3.3	Copy Application	25
3.4	Application Summary	25
3.4.1	Alpha-Factor Model	28
3.4.2	Multiple Greek Letter Model	36
3.5	Generic Report Options	36
3.5.1	Application Report (Generic Unmapped)	38
3.5.2	Event Summary Statistics Report	39
3.5.3	Application Report (Generic Mapped Impact)	40
3.5.4	Application Summary Report (Generic Mapped Impact)	42
3.5.5	Detailed Events (Generic Mapped)	43
3.5.6	Event Summary Statistics (Generic Mapped)	44
3.5.7	Application Event Report	46
4.	SPECIFIC	49
4.1	Event Analysis	50
4.1.1	SPECIFIC Event Impact Vector Analysis	52
4.2	Application Summary	54
4.2.1	Alpha-Factor Model	56
4.2.2	Multiple Greek Letter Model	64
4.3	Search Reports	64
5.	REPORT	65
5.1	Applications	65

5.2	Events	68
5.3	Event Text	69
5.4	Plants	69
5.5	Other Report Options	70
6.	UTILITY	71
6.1	Rebuild	71
	6.1.1 Database Option	71
	6.1.2 Indexes Only Option	72
6.2	Monitor Type	73
6.3	Constants-Prior Distribution	73
6.4	Calculator	73
6.5	Conversions	75
6.6	NPRDS Agreement	77
6.7	Change Password	77
7.	REFERENCES	79
	GLOSSARY	81

FIGURES

1.	CCF main menu.	4
2.	Initial Search Database screen.	7
3.	Exit prompt.	9
4.	Search Criteria screen.	10
5.	Failure mode selection list.	11
6.	Select Application screen to store events.	12
7.	Replace duplicate events prompt.	13

8. Search Reports screen.	13
9. Search—Report Options screen.	13
10. Example of Qualified Events Report—long report format.	14
11. Example of Qualified Events Report—short report format.	15
12. Generic—Application list.	17
13. Generic—Edit Applications screen.	18
14. Generic—Modify Application screen.	19
15. Generic—Add Application screen.	20
16. Generic—Event Analysis screen.	21
17. Generic—Event Analysis screen.	24
18. Generic—Copy Application screen.	26
19. Generic—CCF Summary Statistics screen.	26
20. Generic—Breakdown of independent event total.	27
21. Generic—Breakdown of independent event totals by plant.	28
22. Generic—Alpha-Factor Model menu.	29
23. Generic—Alpha-Factor Model Point Estimate screen.	29
24. Generic—Nonhomogeneous Model menu.	30
25. Generic—Constrained Noninformative Prior Results.	30
26. Generic—Full distribution of the constrained noninformative prior results.	31
27. Generic—Hierarchical Bayesian Method menu.	32
28. Generic—Hierarchical Bayesian Method results.	32
29. Generic—Hierarchical Bayesian Method—Run new calculation initial screen.	33
30. Generic—Homogeneous Bayesian Distributions.	34
31. Generic—Bayesian uncertainty summary.	35

32. Generic—Multiple Greek Factor Parametric Model.	36
33. Generic—Unmapped—event, Search Reports screen.	37
34. Generic—Mapped—event, Search Reports screen.	37
35. Generic—Report Options screen.	38
36. Generic—Example of a Generic Impact Estimation report.	39
37. Generic—Example of a Generic Event Summary Statistics Report.	41
38. Generic—Example of a Generic Application report.	42
39. Generic—Example of a Generic Application Summary report.	43
40. Generic—Example of Mapped Detailed Event report.	45
41. Generic—Example of Mapped Event Summary Statistics report.	46
42. Specific—Application list for the Specific option.	49
43. Specific—Event Analysis screen.	50
44. Specific—Application Specific Event Analysis screen.	53
45. Specific—CCF Summary Statistics screen.	54
46. Specific—Breakdown of independent event total.	55
47. Specific—Breakdown of independent event totals by plant.	56
48. Specific—Alpha-Factor Model menu.	57
49. Specific—Alpha-Factor Model Point Estimate screen.	57
50. Specific—Nonhomogeneous Model menu.	58
51. Specific—Constrained Noninformative Prior Results.	58
52. Specific—Full distribution of the Alpha-Factor model.	59
53. Specific—Hierarchical Bayesian Method menu.	60
54. Specific—Hierarchical Bayesian Method results.	60
55. Specific—Hierarchical Bayesian Method—Run new calculation initial screen.	61

56. Specific—Homogeneous Bayesian Distribution.	62
57. Specific—Bayesian Uncertainty Summary	63
58. Specific—Multiple Greek Factor Parametric Model.	64
59. Reports main menu.	65
60. Application Reports menu.	66
61. Application Reports options menu.	66
62. Select applications to report.	67
63. Report Options screen—Applications Listing.	68
64. Select sort order for Events Report.	68
65. Select Event Report.	69
66. Select sort order for Plants Report.	70
67. Utility main menu.	71
68. Database Recovery screen.	72
69. Index Recovery screen	72
70. Prior Distribution constants.	73
71. Calculator screen.	74
72. Select Conversion Type screen.	75
73. CCCG Level screen.	75
74. MGL to Alpha Conversion screen.	76
75. Scaled Basic to Alpha Model Conversion screen.	76
76. NPRDS Agreement screen.	77
77. NPRDS Agreement screen (cont.).	78
78. Password Change Utility screen.	78

EXECUTIVE SUMMARY

The U.S. Nuclear Regulatory Commission's (NRC's) Office for Analysis and Evaluation of Operational Data (AEOD) and the Idaho National Engineering and Environmental Laboratory (INEEL) have developed and maintain a common cause failure (CCF) database for the U.S. commercial nuclear power industry. Previous studies documented methods for identifying and quantifying CCFs. This report extends previous methods by introducing a method for identifying CCF events, a collection of events from industry failure data, and a computerized system for quantifying probabilistic risk assessment (PRA) parameters and uncertainties.

A CCF event consists of component failures that meet four criteria: (1) two or more individual components fail or are degraded, including failures during demand, in-service testing, or from deficiencies that would have resulted in a failure if a demand signal had been received; (2) components fail within a selected period of time, such that success of the PRA mission would be uncertain; (3) component failures result from a single shared cause and coupling mechanism; and (4) a component failure is not due to the failure of equipment outside the established component boundary.

Two data sources are used to select equipment failure reports to be reviewed for CCF event identification: the Nuclear Plant Reliability Data System (NPRDS), which contains component failure information, and the Sequence Coding and Search System (SCSS), which contains Licensee Event Reports (LERs). These sources served as the developmental basis for the CCF data collection and analysis system. The CCF data collection and analysis system consists of (1) CCF event identification methodology, (2) event coding guidance, and (3) a software system to estimate CCF parameters.

The CCF event identification process includes reviewing failure data to identify CCF events and counting independent failure events. The process allows the analyst to consistently screen failures and identify CCF events. The CCF event coding process provides guidance for the analyst to consistently code CCF events. Sufficient information is recorded to ensure accuracy and consistency. Additionally, the CCF events are stored in a format that allows PRA analysts to review the events and develop an understanding of how they occurred.

A software system stores CCF events, independent failure counts, and automates PRA parameter estimations. The system employs two quantification models: alpha factor and multiple Greek letter. These models are used throughout the nuclear industry. In addition, these parameter estimations can be utilized in a PRA to estimate basic event probability and uncertainty.

SECRET

The report of the... (faint text)

The report of the... (faint text)

The report of the... (faint text)

The report of the... (faint text)

The report of the... (faint text)

ACRONYMS

AEOD	Nuclear Regulatory Commission's (NRCs) Office for the Analysis and Evaluation of Operational Data	NPRDS	Nuclear Plant Reliability Data System
CCF	Common Cause Failure	NRC	Nuclear Regulatory Commission
CD-ROM	Compact Disk Read Only Memory	PRA	Probabilistic Risk Assessment
DOS	Disk Operating System	Windows NT	A 32 bit operating system created by Microsoft for high end computers.
INEEL	Idaho National Engineering and Environmental Laboratory	Windows 95	A 32 bit operating system created by Microsoft for smaller computers.
INPO	Institute of Nuclear Power Operations		

MEMORANDUM FOR THE RECORD

DATE: 10/15/54

TO: SAC, NEW YORK

FROM: SAC, NEW YORK

SUBJECT: [Illegible]

Reference is made to [Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

[Illegible]

Common Cause Failure Database and Analysis System Volume 4—Software Reference Manual

1. INTRODUCTION

The Nuclear Regulatory Commission (NRC) Office for the Analysis and Evaluation of Operational Data (AEOD) and the Idaho National Engineering and Environmental Laboratory (INEEL) have developed and maintain a common cause failure (CCF) database for the U.S. commercial nuclear power industry. This database contains the events known as common cause failures that have occurred in commercial nuclear power plants throughout the United States. Common cause failure events are characterized by failure or degradation of multiple (typically redundant) components owing to a same shared cause within a short period of time. The CCF events have been obtained from review of the Nuclear Plant Reliability Data System (NPRDS) failure reports and Licensee Event Reports (LERs) obtained from the Sequence Coding and Search System (SCSS) database. Volumes 2 and 3 of this report contain more detailed discussion about CCF event definition and classification.

For this project, the INEEL also developed computer software to enable probabilistic risk assessment (PRA) analysts to obtain CCF parameter estimations for use in reliability and risk analysis studies. This software is based on the impact vector method described in Reference 2. This volume of the report describes in detail how to use the software, including how to search the database for events of interest, and how to use the event information to obtain the parameter estimates.

1.1 Hardware and Software Requirements

The purpose of this section is give the user an overview of the hardware and software requirements to use the CCF Disk Operating System (DOS) (CCFDOS) application and/or CCF Windows (CCFWIN) application.

1.1.1 CCFDOS Software Requirements

To run CCFDOS you must have MS-DOS 5.0 or higher.

1.1.2 CCFWIN Software Requirements

To run CCFWIN you must have Windows 95 or Windows NT 3.41 or 4.0.

1.1.3 CCFDOS Hardware Requirements

To run CCFDOS you must have the minimum hardware configuration outlined below:

- IBM-PC compatible computer with at least a 386 processor
- 8 MB RAM
- 15 MB free disk space.

1.1.4 CCFWIN Hardware Requirements

To run CCFWIN you must have the minimum hardware configuration outlined below:

- IBM-PC compatible computer with at least a 486 processor
- 8 MB RAM (Windows 95)
- 16 MB RAM (Windows NT)
- 15 MB free disk space.

1.2 Installing CCF

This section will provide the user an overview of how to install the CCFDOS and CCFWIN programs.

1.2.1 Installing CCFDOS

This software package contains installation floppy disks and/or a CD-ROM that allows you to easily install CCFDOS on your system. To install from the floppy diskette set:

1. Insert CCF Installation Disk #1 into drive A (or drive B)
2. Type the following DOS command at the DOS prompt:

A:INSTALL C: (or B:INSTALL C:),

where

A (or B) = drive with the installation disk

C = drive where CCFDOS will be installed.

To install from the CD-ROM:

1. Insert CCF CD-ROM into the CD-ROM drive (D:)
2. Type the following DOS command at the DOS prompt:

D:INSTALL C: (or E:INSTALL C:),

where

D (or E) = drive with the installation CD-ROM

C = drive where CCFDOS will be installed.

1.2.2 Installing CCFWIN

CCFWIN can be installed from the floppy diskette set or CD-ROM. To install from the floppy disk:

1. Insert the disk labeled CCF Disk 1 into the floppy drive.
2. From the Start Bar, click **Run**.
3. Type `a:\setup`.
4. The Setup program will guide you through the installation process. Follow the instructions on the screen.

To install from CD-ROM:

1. Insert the CCF CD-ROM into the CD-ROM drive.
2. From the Start Bar, click **Run**.
3. Type `x:\setup` where x is the drive letter of your CD-ROM drive.
4. The Setup program will guide you through the installation process. Follow the instructions on the screen.

1.3 Starting CCF

The CCF system software allows you to search events and create applications in the CCF database.

1.3.1 Starting CCFDOS

To start CCFDOS, at the DOS prompt type `CCFDOS` and press `<Enter>`. The CCF title screen appears. Press `<Enter>` to continue. Type your password to proceed to the main menu screen (Figure 1).

NOTE: You have three chances to enter your password correctly. If you fail to enter your password correctly or you bypass this screen, CCF will deny access to the software system and you will be back at the DOS prompt. If your password has been corrupted, or a password has not been obtained, contact Ted Wood (INEEL) at (208) 526-8729 or Dale Rasmuson (AEOD, NRC) at (301) 415-7571.

The CCF main menu has the following options:

SEARCH—Searches for events and assigns the events to an application. An application is simply a collective list of events interpreted for a specific situation, such as a plant or system. **SEARCH** has extensive search capabilities including wildcard searches. (See Section 2 for details.)

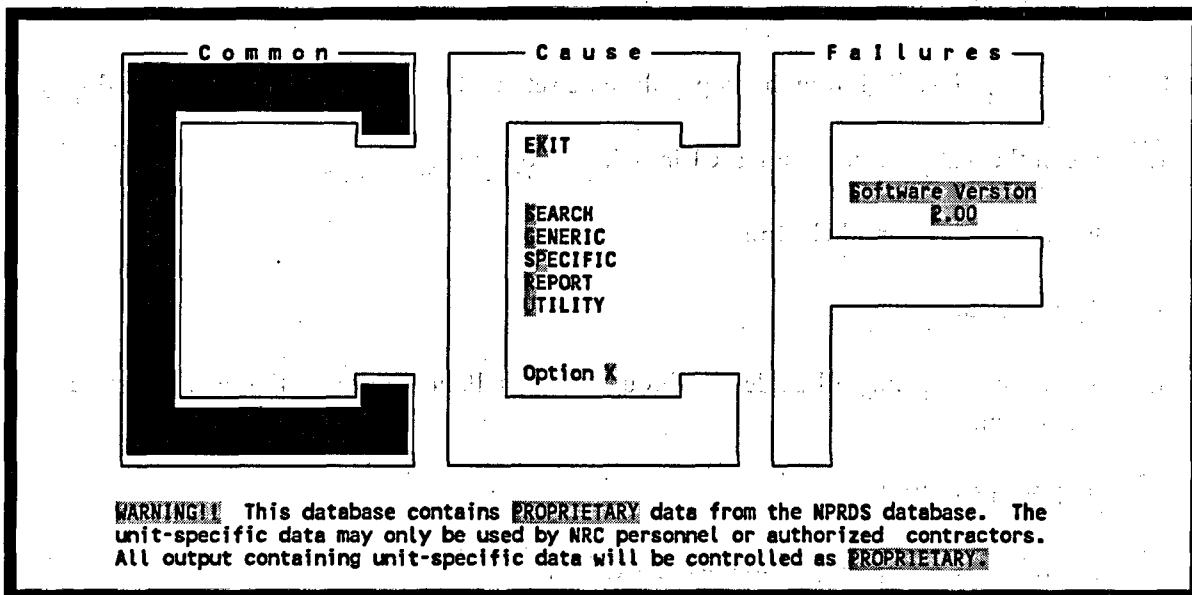


Figure 1. CCF main menu.

GENERIC—Generically analyzes individual events, estimates CCF model parameters, and summarizes the results of an application. You can also perform mapped and unmapped calculations on generic models. (See Section 3 for details.)

SPECIFIC—Specifically analyzes individual events, estimates CCF model parameters, and summarizes the results of an application. (See Section 4 for details.)

REPORT—Generates reports containing information about applications, events, plants, systems, component types, failure modes, proximate causes, coupling factors, shock types, operational status, event types, and defense mechanisms. (See Section 5 for details.)

UTILITY—Performs miscellaneous utility functions including rebuilding the database, specifying the monitor type currently in use, calculating hypothetical ("what if") situations, and changing your current password. (See Section 6 for details.)

When you select an option in the main menu, the monitor displays a brief description of the option at the bottom of the screen.

1.3.2 Starting CCFWIN

To start CCFWIN, double click the CCFWIN program icon, or click Programs on the Start Bar and select CCF for Windows.

1.4 Function Keys

Function keys perform special commands and functions, depending on which screen you're using. CCF designated four function keys to provide specific commands throughout this software application. The function keys <F1>, <F8>, <F9>, and <F10> provide the following features:

- <F1> Help—Displays associated online help messages.
- <F8> Mark—Functions as a toggle switch for marking or unmarking an item in a list. An asterisk marks the item for inclusion in the search. To mark or unmark an item, simply highlight the item and press <F8>.
- <F9> All—Operates as a toggle switch for marking or unmarking ALL items in a selection list.
- <F10> Range—Serves as a toggle switch for sequentially marking or unmarking a range of items in a list. To mark a range, highlight the first item to include and press <F10>. The message "Range selected—Highlight end of range . . ." appears at the bottom of the screen. Scroll through the list and find the last item to include and press <F10>. Asterisks will appear in front of all items that fall within the designated range. To remove the asterisks from the selected applications, simply press <F10> and select the same range. Press <F10> again and CCF will unmark the selected applications.

1.5 CCF Windows Version

The purpose of this section is give the user an overview of the CCF Windows (CCFWIN) application interface. Other than this section the remainder of this manual deals with the CCFDOS application. CCFWIN provides the same functionality as the DOS version, but the user interface is very different. The CCFWIN application has extensive online help which can guide you through its use.

1.5.1 Exiting CCFWIN

To leave the CCFWIN application, select File from the menu bar. Select the Exit submenu option. The CCF database will be closed and the application will be terminated.

1.5.2 The Windows Interface

1.5.2.1 Screen Display. CCFWIN allows a more intuitive user interface by not limiting the screens to 80 characters of fixed fonts as in DOS. In many cases several DOS screens are replaced by one Windows dialog box.

1.5.2.2 Menus. CCFWIN uses dialogs with radio buttons or layered menus to replace the multiple menu screens required in DOS. This allows the user to select all of the options at once without having to move through multiple menus.

1.5.2.3 Functions Keys. In CCFWIN the DOS function keys have been replaced by buttons or pop-up menus. To invoke a pop-up menu, click the right mouse button. While holding down the right mouse button select the desired menu option by highlighting it and then releasing the mouse button.

1.5.2.4 Field Validation Lists. In CCF DOS, <F2> was pressed to get a list of valid field entries, but in CCFWIN combo boxes are used. The user can click down an arrow button to the side of the combo box to obtain a list of valid entries.

1.5.2.5 List Boxes. Windows list boxes are used in many places in CCFWIN. In some list boxes, multiple items can be selected for processing. The following discussion provides some hints on selecting list box items.

An item in a list box is "selected" if it is highlighted that is, displayed in a different color than the other items in the list. There are various ways to select items in a list. To select a single item, click on the desired item. It should now be highlighted. To select multiple contiguous items, click on the first desired item in the list and drag up or down the list to the last desired item. Alternately, click the first desired item, then while holding down the <SHIFT>key, click the last desired item. To select multiple non-contiguous items in the list, click several desired items while pressing the <CTRL> (control) key. All of the selected items should now be highlighted.

1.6 NPRDS Conditions of Use

BY USING THE COMMON CAUSE FAILURE DATABASE, WHICH CONTAINS NPRDS DATA, YOU AGREE TO THE FOLLOWING CONDITIONS: The data contained in the NPRDS are the exclusive property of the Institute of Nuclear Power Operations (INPO) and the U.S. nuclear utility members of INPO. NPRDS may be used only to promote safety and reliability in the operation of commercial nuclear power plants.

INPO strictly prohibits any use of NPRDS, or data obtained through NPRDS, in marketing, advertising, solicitations, proposals, and similar activities.

Data obtained through NPRDS are confidential. Disclosure is prohibited without the express written advance consent of INPO. In addition disclosure of data that identify an individual nuclear power plant is prohibited without the express, written, advance consent of the Member of INPO that has primary authority for the operation of that plant. Any disclosure to the U.S. Nuclear Regulatory Commission is permitted, without any consent, provided that the disclosure is accompanied by a statement that NPRDS data are confidential, commercial information and the exclusive property of INPO. Any individual or organization that obtains access to NPRDS by means of contract with an INPO Member shall return to the Member all NPRDS data, user identification codes, passwords, documentation, and similar items at the conclusion of the contract.

2. SEARCH

SEARCH scans the CCF database for specific common cause events. You can also save the list of events as an application for future use (e.g., Generic and Specific analysis applications).

To search for an event, either type **S** in the option field of the main menu or use the up and down arrow keys to highlight SEARCH on the main menu. Press <Enter> to access the Initial Search Database screen (Figure 2).

Search Database		Total Selected Events	2578
L-029-83-0119-BO ELECTRICAL DISTURBANCE TRIPS BATTERY INPUT BREAKERS. L-029-83-1080-CR OFFSITE ELECTRICAL DISTURBANCE OPEN BATTERY BREAKERS. L-029-85-1156-CO 4160V BREAKERS FAIL TO OPEN ON CONTAINMENT ISOLATION SIGNAL. L-029-86-1081-CX 480V OVERLOAD RELAY COILS UNDERSIZED. L-029-87-1487-VS MAIN STEAM SAFETY VALVES SET TOO HIGH. L-029-87-1855-VS PRIMARY CODE SAFETY VALVES SETPT IN EXCESS OF TS REQUIREMENT L-029-90-0590-FR DIESEL ENGINE CAPACITY (400 KW) TOO LOW DUE TO DESIGN ERROR L-029-91-0591-FS EMERGENCY GENERATORS EDG1 AND EDG3 CONTROL RELAY ARCING.			
Name	L-029-83-0119-BO Src LER	Plant	YANKEE ROWE Power---%
Title	ELECTRICAL DISTURBANCE TRIPS BATTERY INPUT BREAKERS.		P1 1.00 P2 1.00
System	DCP Proxim Cause IC	CCCG Size	2 Op-Det BO Mode O P3 0.00
Component	BCH Shock Type NL	Timing Factor	1.00 Event Type EXP P4 ----
Fail Mode	NO Coupl Factor EI	Shared Cause Fc1.00	Event Level SYS P5 ----
Plnt Type	P Mult Units? N	Date	1983/03/23 Defense Mech FSB P6 ----
<Esc>	<Enter>		<F3> <F4> <F5> <F6> <F7> <F8>
Exit	Search	Remove Event	View Descrip Narrative Report Reset Save List

Figure 2. Initial Search Database screen.

The screen consists of two windows. The top window contains all events currently stored in the CCF database. This window displays the first eight events stored in the database. You may scroll through the entire list of events using either the <PgUp> and <PgDn> keys or the up and down arrow keys. As you scroll through the list of events, the bottom window displays detailed information about the highlighted event. As the database increases in size, you may be forced to scroll through several pages of events before locating a desired event. You can use the speed search feature to facilitate your search. To use speed search, simply start typing the first few characters of the event code you are trying to locate. As you type each letter, speed search simultaneously highlights the closest event matching your entry.

NOTE: All CCF selection screens employ the speed search function (e.g., applications, plants, and component types).

SEARCH provides the following functions:

<Esc> Exit—Terminates SEARCH, and then displays the save/cancel window if you performed any Search functions; otherwise, <Esc> returns to the main menu.

- <Enter>** Search—Initiates the search function. This function allows you to easily search for events. To start the Search function, press **<Enter>** (see Section 2.1).
- ** Remove Event—Deletes an event from the top window. When you highlight an event and press ****, a message will appear asking if you wish to remove this event from the list. Respond **Y** or **N** and press **<Enter>**.
- <F1>** Online Help (not displayed at the bottom of the screen)—Provides direct access to CCF subjects without interrupting work in progress or using this manual to answer questions about CCF. Press **<F1>** to access the glossary of subjects. Tab through the list and highlight the desired subject. Press **<Enter>** to view the text. If related information exists, you can tab to the highlighted subjects within the help text or tab to the subjects listed under "See also" and press **<Enter>**. Press **<F1>** to access the Hypertext Help window. Press **<F10>** to back out of the screens or press **<Esc>** to exit the online help and return to the program.
- <F3>** View—Views the event data. Highlight the desired event and press **<F3>**. A screen will appear showing event information, including component degradation values. You can also view any comments attached to the event by pressing **<F4>** in the View Event screen. After you finish viewing the information, press **<Enter>** or **<Esc>** to return to the previous screen.
- <F4>** Description—Directly views the description associated with the selected event without accessing the View Event screen first. Highlight the desired event and press **<F4>**. A window containing the associated description for that event will appear. Press **<Esc>** to exit the description window.
- <F5>** Narrative—Directly views the narrative associated with the selected event without accessing the View Event screen first. Highlight the desired event and press **<F4>**. A window containing the associated narrative for that event will appear. Press **<Esc>** to exit the narrative window.
- <F6>** Report—Generates the Qualified Events Report (see Section 2.5).
- <F7>** Reset—Resets the event list to reflect the original list. This is the same list of events displayed in the top window when you first entered CCF (i.e., all events in the database). Reset restores anything deleted during the CCF session.
- <F8>** Save List—Saves the event list in an application. Once a search has been completed, you can save the event for future use.

NOTE: Each time you select the SEARCH option from the main menu, the top window will display all events in the database. Once you execute a search, CCF displays only those events that meet your criteria in this window. Further searches will be evaluated against the entire database, and the top window will be updated accordingly. Events appearing in this window may be saved before you exit by selecting the **<F5>** option. This list can then be used for subsequent studies.

Once you have completed SEARCH and located the desired events, you can save the list of events by pressing <F5> (see Section 2.3), or you can exit without saving the list of events by pressing <Esc>. When you press <Esc>, Figure 3 is displayed. Here, CCF will give you another chance to save the list before exiting. At the prompt, you may save and exit or exit without saving before returning to the main menu, or select cancel and return to the previous screen.

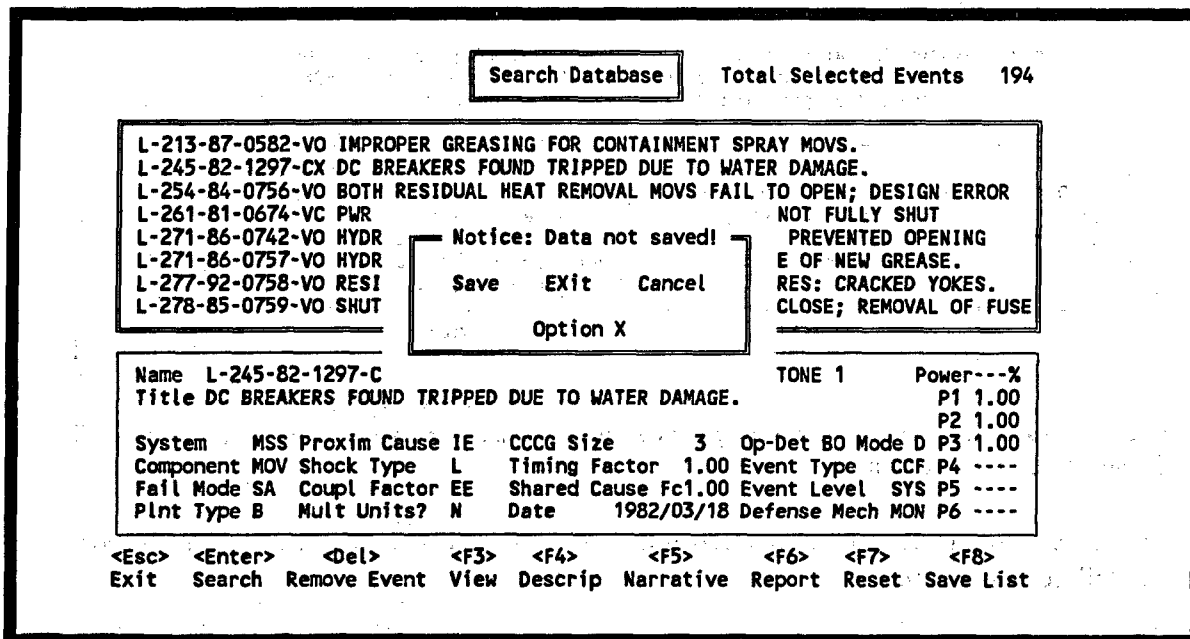


Figure 3. Exit prompt.

2.1 Search Fields

The Search Criteria screen (Figure 4) appears when you start the Search function (press <Enter>). This function requires search criteria to perform a search. You may enter values into any combination of fields. For most fields, you may also press <F2> to select a value from a list of values. A brief description of these fields follows. See Volume 3¹ for more details about these fields.

Name—Enter the event code number assigned to the event by the data coder.

Plant—Enter the name of the nuclear power plant (<F2> is available).

Type—Enter the plant type (B for BWR or P for PWR).

Start Date and/or End Date—Enter the start date and end date of a date range. All events that occurred after the start date and/or before the end date will be selected. The format is yyyy/mm/dd.

System—Enter a three-character designator. If you select the list option <F2> and use individually marked systems in the search, an "@" will appear in the search field. Refer to Section 1.4 for information regarding <F8>, <F9>, and <F10> functions to mark the system.

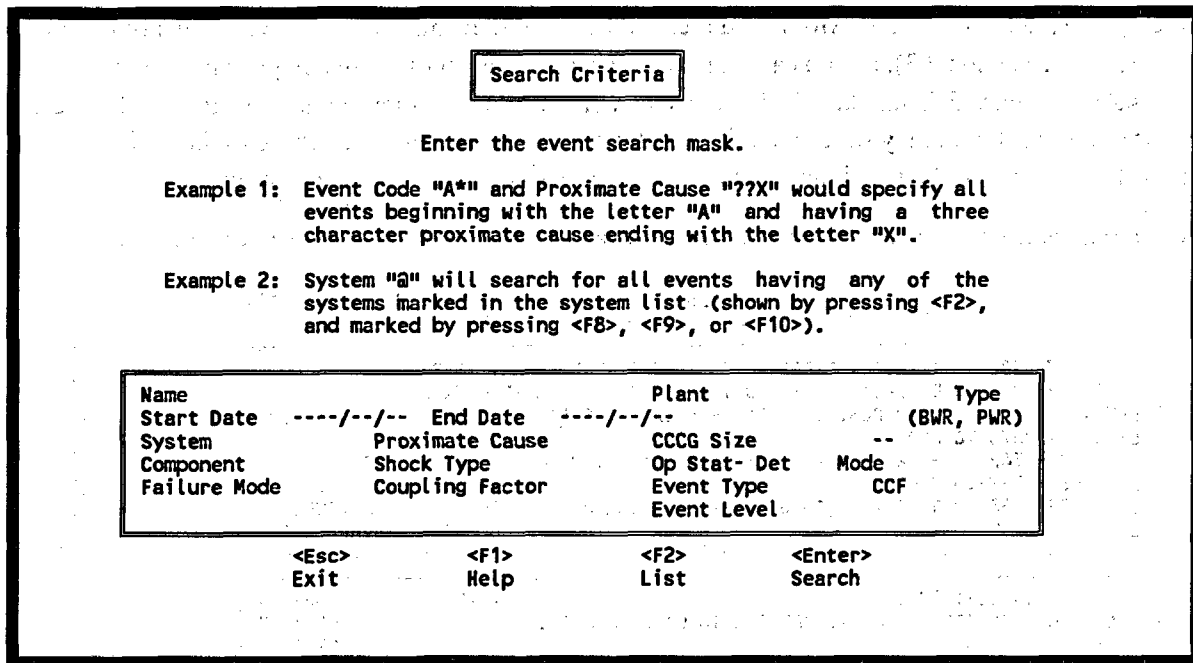


Figure 4. Search Criteria screen.

Proximate Cause—Proximate cause characterizes the condition that is readily identified as the condition that leads to failure (a symptom).

CCGG Size—Enter the system size or number of redundant components.

Component—Enter a three-character designator (<F2> is available).

Shock Type—Enter L or NL (<F2> is available). Shock type classifies the event as either a lethal or nonlethal shock to the system.

Operation Status-Detected—Indicates when the event was detected.

Operation Status-Mode—Indicates during what condition the event is significant.

Failure Mode—Enter a two-character designator (<F2> is available).

Coupling Factor—Enter a two- or four-character designator (<F2> is available). The coupling factor explains why and how a failure is systematically induced in several components.

Event Type—Enter a three-character designator (<F2> is available). Event type places events into type categories.

Event Level—Enter SYS, COM, or leave blank. Event Level indicates whether the event qualifies as a functional-level failure or a component-level failure.

The Search function uses all marked items to perform the search; therefore, you will probably want to change these defaults. Specific function keys have been defined that allow you to mark or unmark items in

the selection list (See Section 1.4). Position the cursor in a field and press <F2>. For example, position the cursor in the failure mode field and press <F2>. A screen similar to Figure 5 will appear. Scroll through the list using the up and down arrow keys or the <PgUp> and <PgDn> keys. When the desired failure mode is highlighted, press <Enter>. Or, you may use the <F8>, <F9>, or <F10> keys to mark the desired events. In either case, you will return to Figure 4 where the selected failure mode is written into the failure mode search field. As a default, the system will select all event codes, plants, types, systems, proximate causes, coupling factors, and shock types (i.e., marked with an asterisk).

Search Criteria

MF REDUCED FLOW, NO HEAT TRANSFER EFFECT
 *NO NO VOLTAGE/AMPERAGE OUTPUT
 *OO FAIL TO CLOSE (NORMALLY OPEN)
 *PG FAILURE TO TRANSFER HEAT/PLUGGED
 SA SPURIOUS ACTUATION
 SD SETPOINT DRIFT
 *VR FAIL TO REMAIN CLOSED (DETECTABLE LEAKAGE)
 XA HUMAN ERROR OF ALIGNMENT

Note: "*" indicates a wild card match or marked item

Name	Plant	Type	(BWR, PWR)
Start Date	1992/01/01	End Date	1992/12/31
System	Proximate Cause	CCCG Size	--
Component	Shock Type	Op Stat- Det	Mode
Failure Mode	Coupling Factor	Event Type	CCF
		Event Level	

<Esc>
Exit

<Enter>
Select

<F8>
Mark

<F9>
All

<F10>
Range

Figure 5. Failure mode selection list.

2.2 Using Wildcards

You can specify wildcards for all optional search fields. The wildcards equate to those used in DOS. That is, an asterisk (*) represents an entire word or a group of characters, while the question mark (?) represents a single character. For example, entering an A* in the System field, will locate all events for a system starting with the letter A (e.g., ACS and ACT). On the other hand, entering A? will locate only those events with a two-character system identifier.

2.3 Saving Search Results

Once you locate the desired events, you may save the results. Press <F8> to save the list to an existing application or create a new application in which to save the list (see Section 2.4). If you wish to exit the screen without saving the list, press <Esc>. In addition, if you decide to start over, press <F7> to return to the original list of events (this will be the list of events since the last save).

2.4 Saving Results in Application

Pressing <F8> displays the Select Applications screen (Figure 6). If you are saving to an existing application, simply highlight the application and press <Enter>. Now, you must decide what to do with any duplicate events (Figure 7). If a selected event already exists in the application, you need to specify whether to replace the existing event with the selected event. Enter a Y or N and press <Enter>. The events will be copied to the specified application. If you wish to create a new application for storing the selected events, highlight NEW APP and press <Enter>. The cursor will be in the lower portion of the screen. Enter the new application name (mandatory), description (optional), and CCCG level (mandatory—value from 2 to 6) for the newly created application, and press <Enter>. You will be returned to the top portion of the Select Applications screen (see Figure 6). Here, the newly created application will be highlighted in the list. With the new application name highlighted, press <Enter>. CCF will copy the selected events into the new application. When CCF finishes the copy process, it will return you back to the search menu.

2.5 Search Reports

To generate a long or short Qualified Events report, press <F6> at the Search Database screen to access the Search Report screen (Figure 8). Use the up and down arrow keys to highlight either the long or short report format or enter L or S into the Option field. Press <Enter> to access the Report Options screen (Figure 9). By default, the report is written to a file called SEARCH.RPT in the current directory. This can be changed by entering CON to display the report on the screen, PRN to print the report to the printer, or a valid DOS filename to save the report. Both reports contain detailed information about qualified events (Figures 10 and 11). Press <Enter> to initiate the report. Your screen should display the message, "Qualified Events report being generated" to verify the operation. Once CCF generates the report, the program will exit the Report Options screen and return to the Search Database screen with a verification message displayed at the bottom of the screen.

Select Application

<NEW APP>	
DGN-3	DIESEL GENERATOR FAILURES MAPPED TO TARGET SIZE 3
EPS-4	
RHR-PMP-FO-4	RHR PMP'S FAILURES MAPPED TO SIZE 4

Name	<NEW APP>		
Description			
CCCG Level	--	Component Type	Failure Mode

<Esc> Exit <Enter> Select <F3> Edit

Figure 6. Select Application screen to store events.

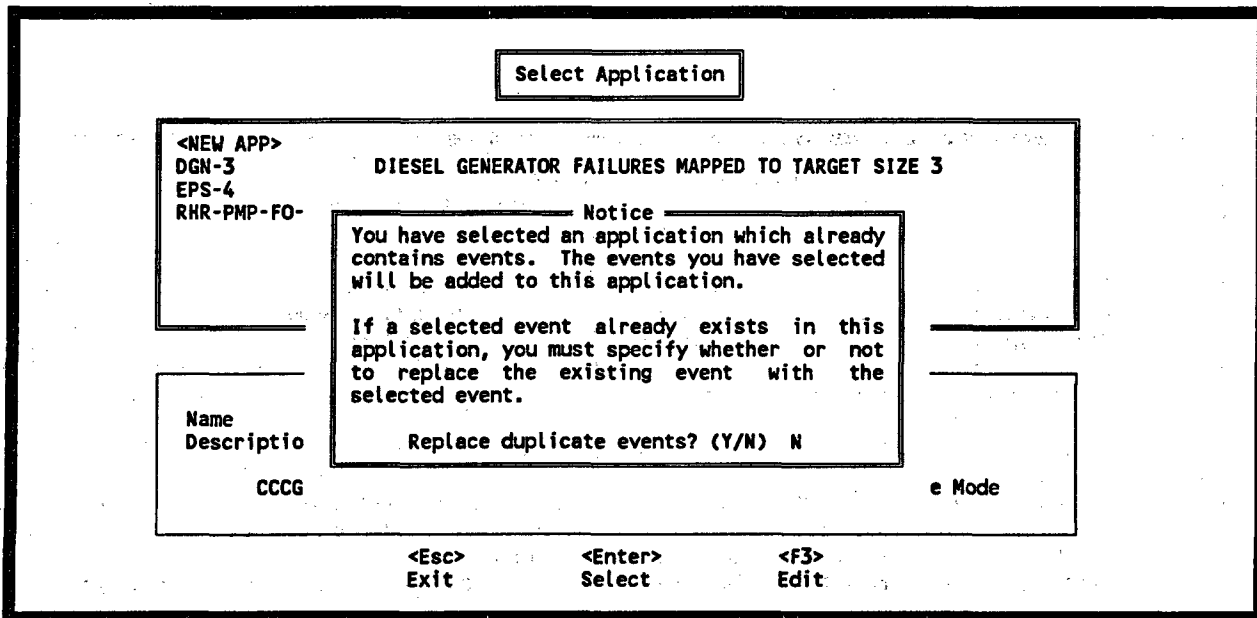


Figure 7. Replace duplicate events prompt.

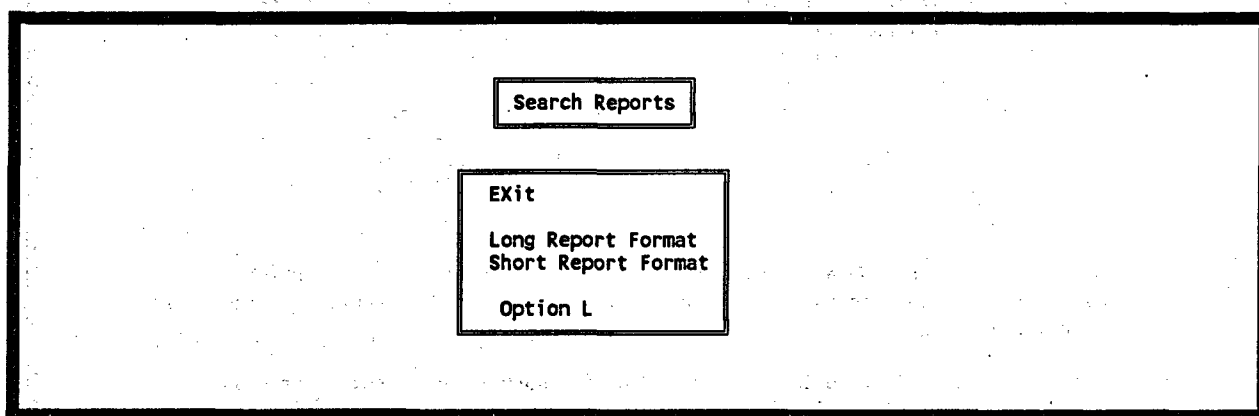


Figure 8. Search Reports screen.

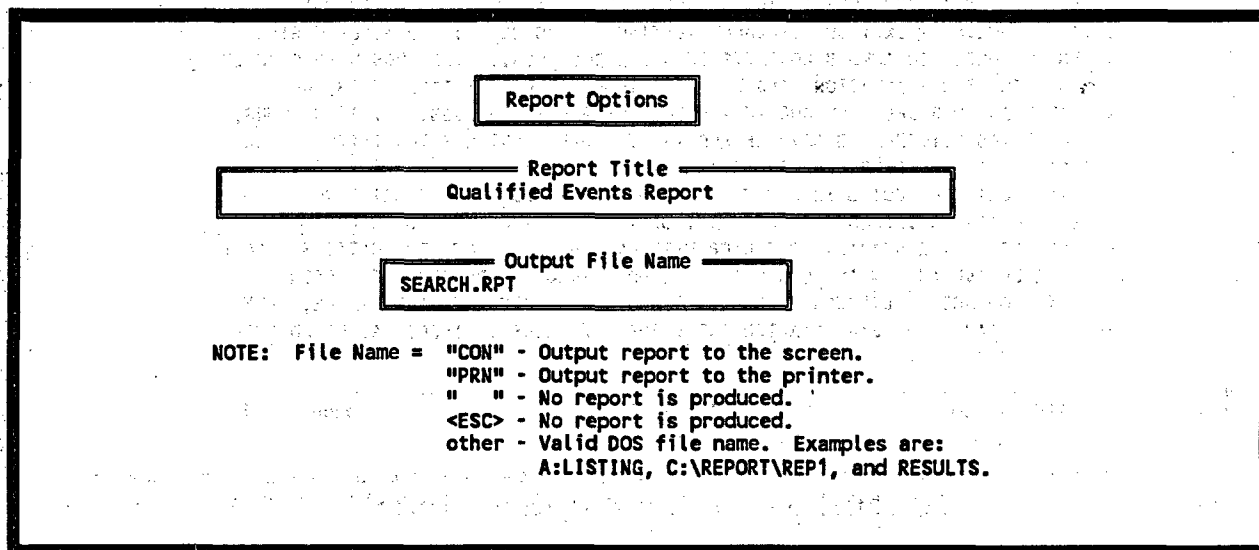


Figure 9. Search—Report Options screen.

Qualified Events Report

Total Records Found : 182

(Search Mask)

Event Name : Component Type : Shock Type :
 Plant Name : Failure Mode : FS Op-Det: Mode:
 Plant Type : Proximate Cause : Event Type : CCF
 System : Coupling Factor : Event Level :

Name L-029-91-0591-FS Plant YANKEE ROWE Power 0%

System EPS Failure Mode FS Shared Cause Fct 1.00 Event Level SYS
 Component DGN Fail Mode App 1.00 Timing Factor 1.00 Defense Mech MON
 Shock Type L Prox Cause DC Op- Detect BO Mode D
 CCGG Size 3 Coupl Factor HQIC Event Type CCF

Title EMERGENCY GENERATORS EDG1 AND EDG3 CONTROL RELAY ARCING.

Component Degradation Values						
Use? P	Date	Time	Use? P	Date	Time	
1 X 0.50	1991/11/05	11:05:00	9	----	----/--/--	---:---:--
2 X 0.50	1991/11/05	10:00:00	10	----	----/--/--	---:---:--
3 X 0.10	----/--/--	00:00:00	11	----	----/--/--	---:---:--
4	----/--/--	---:---:--	12	----	----/--/--	---:---:--
5	----/--/--	---:---:--	13	----	----/--/--	---:---:--
6	----/--/--	---:---:--	14	----	----/--/--	---:---:--
7	----/--/--	---:---:--	15	----	----/--/--	---:---:--
8	----/--/--	---:---:--	16	----	----/--/--	---:---:--

LER 029-91-005.
 240/480 Vac starting contactor coil was in systems designed for 250Vdc which caused control relay arcing across contacts making an automatic restart of the EDGs not possible.

Plant in Mode 5, Refueling Shutdown. Found during surveillance testing of EDGs 1 and 3. EDG 2 out of service for repairs to its generator output air circuit breaker.

11/05/91

POWER LEVEL - 000%. THE PLANT WAS IN MODE 5, AT 0% REACTOR POWER, WITH A MAIN COOLANT SYSTEM TEMPERATURE OF 103 DEGREES FAHRENHEIT. EDG NO. 2 WAS OUT OF SERVICE. DURING WEEKLY SURVEILLANCE TESTING OF EDG NOS. 1 AND 3, EXCESSIVE ARCING WAS OBSERVED ACROSS CONTACTS IN A CONTROL RELAY. THE EDGS WERE REMOVED FROM SERVICE FOR EVALUATION, AND DECLARED INOPERABLE. AT 1115 HOURS, AN UNUSUAL EVENT WAS DECLARED DUE TO THE LOSS OF ALL THREE EDGS. AT 1300 HOURS, EDG NO. 2 WAS RETURNED TO SERVICE AND THE UNUSUAL EVENT WAS TERMINATED. THE ROOT CAUSE OF THE CONTROL RELAY ARCING WAS THE INSTALLATION OF 240/480 VAC STARTING CONTACTOR COILS IN A SYSTEM DESIGNED FOR 125 VDC. SHORT TERM CORRECTIVE ACTION INCLUDES REPLACEMENT OF THE AC COILS WITH DC COILS AND REPLACEMENT OF THE STARTER CONTACTOR WITH ONE RATED FOR DC APPLICATIONS. LONG TERM CORRECTIVE ACTION IS TO UPGRADE THE EDG CIRCUITRY DURING THE PRESENT REFUELING OUTAGE. ALTHOUGH EDGS NOS. 1 AND 3 WERE DECLARED INOPERABLE, THEY REMAINED CAPABLE OF BEING STARTED AND LOADED IF NEEDED. THERE WAS NO ADVERSE

1994/10/06

12:27:37

page 1

Figure 10. Example of Qualified Events Report—long report format.

Qualified Events Report

Total Records Found : 182

Name Plant	Title/ Component	Degradation Values/												
Fail	F Mode	Prox	Time	Coupl	Share	Shk	Comp	CCCG	Oper	Evt	Evt	Def		
Pwr Sys	Mode	Applic	Caus	Fact	Fact	Cause	Typ	Code	Size	Stat	Type	Lev	Mec	
L-029-91-0591-FS EMERGENCY GENERATORS EDG1 AND EDG3 CONTROL RELAY ARCING.														
YANKEE ROWE		0.50	0.50	0.10										
0% EPS	FS	1.00	DC	1.00	HQIC	1.00	L	DGN	3	BO	D	CCF	SYS	MON
L-029-91-0603-FS DEFECTIVE WIRE CRIMPING IN EMERGENCY DIESEL GEN CIRCUITS														
YANKEE ROWE		1.00	0.10	0.10										
100% EPS	FS	1.00	DC	1.00	OMTP	1.00	NL	DGN	3	BO	O	CCF	SYS	MAI
L-206-83-2128-FS CHARGING PUMPS REMOVED FROM SERVICE ERRONEOUSLY.														
SAN ONOFRE 1		1.00	1.00											
0% HPI	FS	1.00	HA	1.00	OOOS	1.00	L	PMP	2	BO	D	CCF	SYS	MON
L-247-84-0001-FS TWO AUX FEEDWATER PUMPS FAILED TO START-RELAY FAILURE														
INDIAN POINT 2		1.00	1.00											
---% AFW	FS	1.00	IE	1.00	EE	1.00	L	MOT	2	BO	D	CCF	SYS	PBR
L-247-84-2130-FS HI PRESS SFTY INJ PUMPS FAIL TO START, BORON SOLIDIFICATION														
INDIAN POINT 2		1.00	1.00	1.00										
100% HPI	FS	1.00	IE	1.00	EI	1.00	L	PMP	3	BO	O	CCF	SYS	MON
L-247-86-0688-FS 2 OF 3 EMERG DIESEL GENERATOR OUTPUT BREAKERS FAIL TO CLOSE.														
INDIAN POINT 2		0.00	1.00	1.00										
100% EPS	FS	1.00	IC	0.01	HDCP	0.50	NL	DGN	3	BO	O	CCF	COM	MON
L-247-91-0689-FS 2 EDGS FAIL TO AUTOMATICALLY LOAD: UNIT TRIP LOCKOUT RELAYS														
INDIAN POINT 2		1.00	1.00	0.10										
0% EPS	FS	1.00	HA	1.00	OMTS	1.00	L	DGN	3	BO	D	CCF	SYS	MON
L-249-94-2373-FS DEGRADED AIR START SYSTEM ON EMERGENCY DIESEL GENERATORS														
DRESDEN 3		0.10	0.01											
99% EPS	FS	1.00	DC	1.00	HDCP	1.00	NL	DGN	2	BO	O	CCF	SYS	DIV
L-250-84-0006-FS AUX FEEDWATER PUMP GOVERNOR FAILURE - LACK OF TEST PROCEDURE														
TURKEY POINT 3		1.00	1.00	0.10										
---% AFW	FS	1.00	PA	1.00	OMTP	1.00	L	TUR	3	BO	D	CCF	SYS	MAI
L-255-81-0596-FS EDG SHUTDOWN SEQUENCERS FAILED-DIRTY CONTACTS/STUCK CLUTCH														
PALISADES		1.00	1.00											
0% EPS	FS	1.00	PA	1.00	OMTC	1.00	NL	DGN	2	BO	D	CCF	SYS	MAI
L-255-86-0322-FS SERVICE WATER PUMP PERFORMANCE LESS THAN FSAR REQUIREMENTS														
PALISADES		0.10	0.10	0.10	0.00									
0% ESW	FS	1.00	DC	1.00	HQIC	1.00	L	PMP	3	BO	O	CCF	SYS	DIV

1997/05/28

13:41:15

page 1

Figure 11. Example of Qualified Events Report—short report format.

1. The first part of the document discusses the importance of maintaining accurate records of all transactions. It emphasizes that proper record-keeping is essential for the integrity of the financial system and for the ability to detect and prevent fraud. The text notes that records should be kept for a minimum of seven years and should be accessible to authorized personnel at all times.

2. The second part of the document outlines the specific requirements for record-keeping. It states that all transactions must be recorded in a clear and concise manner, using a standardized format. This includes recording the date, amount, and description of each transaction. The text also requires that records be kept in a secure and protected environment, with access restricted to authorized personnel only.

3. The third part of the document discusses the role of internal controls in ensuring the accuracy and reliability of financial records. It notes that internal controls should be designed to prevent errors and fraud, and to ensure that all transactions are properly recorded and reported. The text emphasizes that internal controls should be regularly reviewed and updated to reflect changes in the business environment.

4. The fourth part of the document discusses the importance of transparency and accountability in financial reporting. It notes that financial statements should be prepared and presented in a clear and understandable manner, and that they should be subject to independent audit. The text emphasizes that transparency and accountability are essential for the confidence of investors and other stakeholders in the financial system.

5. The fifth part of the document discusses the role of the regulatory authorities in ensuring the integrity of the financial system. It notes that the regulatory authorities have a responsibility to monitor and enforce the rules and regulations that govern the financial system. The text emphasizes that the regulatory authorities should work closely with the industry to identify and address any potential risks or issues.

6. The sixth part of the document discusses the importance of ongoing education and training for financial professionals. It notes that the financial system is constantly evolving, and that financial professionals must stay up-to-date on the latest developments and best practices. The text emphasizes that ongoing education and training are essential for the success of the financial system.

7. The seventh part of the document discusses the importance of ethical behavior in the financial industry. It notes that financial professionals have a responsibility to act ethically and to uphold the highest standards of integrity. The text emphasizes that ethical behavior is essential for the trust and confidence of investors and other stakeholders in the financial system.

8. The eighth part of the document discusses the importance of risk management in the financial industry. It notes that financial institutions face a variety of risks, including credit risk, market risk, and operational risk. The text emphasizes that effective risk management is essential for the stability and success of financial institutions.

9. The ninth part of the document discusses the importance of innovation and technology in the financial industry. It notes that technology is driving significant changes in the way that financial services are delivered, and that financial institutions must embrace innovation to remain competitive. The text emphasizes that innovation and technology are essential for the growth and development of the financial system.

3. GENERIC

GENERIC edits applications and events, analyzes the events of an application, and summarizes the values of applications statistically. The Edit function modifies, inserts, and deletes data contained in an application. The Event function deletes, views comments, or analyzes existing events of an application. From the Generic Event Analysis screen, Analyze allows you to calculate "what if" type situations. The Application Summary function allows you to summarize CCF statistics using various modeling techniques, performing mapped or unmapped calculations, using a staggered testing scheme, and create reports.

To run the GENERIC option, type **G** in the Option field of the main menu or use the up and down arrow keys to highlight the GENERIC option. Press **<Enter>** to access the Applications screen (Figure 12).

Applications

ACP_4KV_BKR_U_CC	4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96
ACP_4KV_BKR_U_CX	4160 VAC CIRCUIT BRKRS, SPURIOUS OPEN, 94/95 UPDATE, 11-4-96
AFW_AOV_UPD_VC	AUX FEEDWATER AOVS, FAIL TO CLOSE, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VO	AUX FEED AOVS, FAIL TO OPEN, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VR	AUX FEED AOVS, FAIL TO REMAIN CLOSED, 94/95 UPDATE, 11-25-96
AFW_CKV_UPD_VC	PWR AUX FEED CHK VLVS, FAIL TO CLOSE, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VO	PWR AUX FEED CHK VLVS, FAIL TO OPEN, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VR	AUX FEED CHK VLV, FAIL TO REMAIN CLOSED, 94/95 UPD, 11-23-96

Name	ACP_4KV_BKR_U_CC			
Description	4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96			
CCCG Size	6	Component Type	Failure Mode	
<Esc> Exit	<F3> Edit	<F4> Events	<F5> Copy	<Enter> Appl. Summary

Figure 12. Generic—Application list.

GENERIC provides the following functions:

- <Esc>** Exit—Terminates the Applications screen and returns to the main menu.
- <F3>** Edit—Edits the application (see Section 3.1).
- <F4>** Events—Removes events from a list, views event comments, analyzes an event, and performs summary statistics for an application (see Section 3.2).
- <F5>** Copy—Copies an application to a new application (see Section 3.3).

<Enter> Applications Summary—Directly performs summary statistics for an application (see Section 3.4).

3.1 Editing Applications

The Edit function modifies, adds, or deletes an application or a group of applications. To edit an application, press <F3> to access the Edit Applications screen (Figure 13).

```

Edit Applications

ACP_4KV_BKR_U_CC 4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96
ACP_4KV_BKR_U_CX 4160 VAC CIRCUIT BRKRS, SPURIOUS OPEN, 94/95 UPDATE, 11-4-96
AFW_AOV_UPD_VC   AUX FEEDWATER AOVs, FAIL TO CLOSE, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VO   AUX FEED AOVs, FAIL TO OPEN, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VR   AUX FEED AOVs, FAIL TO REMAIN CLOSED, 94/95 UPDATE, 11-25-96
AFW_CKV_UPD_VC   PWR AUX FEED CHK VLVS, FAIL TO CLOSE, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VO   PWR AUX FEED CHK VLVS, FAIL TO OPEN, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VR   AUX FEED CHK VLV, FAIL TO REMAIN CLOSED, 94/95 UPD, 11-23-96

Name          ACP_4KV_BKR_U_CC
Description    4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96

          CCGG Size 6          Component Type          Failure Mode

<Esc>      <Enter>   <Ins>     <Del>     <F8>     <F9>     <F10>
Exit       Modify    Add       Delete    Mark     All      Range

```

Figure 13. Generic—Edit Applications screen.

Edit provides the following functions:

- <Esc> Exit—Terminates the Edit Application screen and returns to the Applications screen.
- <Enter> Modify—Changes the name, description, CCGG level, component type, or failure mode of the selected application (see Section 3.1.1).
- <Ins> Add—Adds a new application to the database (see Section 3.1.2).
- Delete—Removes an application from the database. To delete an application, highlight the application and press . A verification window will ask if you want to delete the highlighted record. Enter either Y or N and press <Enter>. If you enter Y, the application will be deleted immediately. If you have marked any applications (using <F8>, <F9>, or <F10>), CCF will only ask once before it deletes all of the marked applications.

3.1.1 Modifying an Application

To modify an application, highlight the desired application and press <Enter> to access the Modify Application screen (Figure 14). Make any necessary changes to the fields and press <Enter> to save the changes.

Modify Application

```

ACP_4KV_BKR_U_CC 4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96
ACP_4KV_BKR_U_CX 4160 VAC CIRCUIT BRKRS, SPURIOUS OPEN, 94/95 UPDATE, 11-4-96
AFW_AOV_UPD_VC:  AUX FEEDWATER AOVS, FAIL TO CLOSE, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VO:  AUX FEED AOVS, FAIL TO OPEN, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VF:  AUX FEED AOVS, FAIL TO REMAIN CLOSED, 94/95 UPDATE, 11-25-96
AFW_CKV_UPD_VC:  PWR AUX FEED CHK VLVS, FAIL TO CLOSE, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VO:  PWR AUX FEED CHK VLVS, FAIL TO OPEN, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VF:  AUX FEED CHK VLV, FAIL TO REMAIN CLOSED, 94/95 UPD, 11-23-96

```

```

Name          ACP_4KV_BKR_U_CC
Description   4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96

      CCGG Size 6          Component Type          Failure Mode

```

<Esc>	<F1>	<F2>	<Enter>
Exit	Help	List	Modify

Figure 14. Generic—Modify Application screen.

NOTE: Use <Tab> to move from field to field on the screen.

Modify Application provides the following functions:

- <Esc> Exit—Terminates the Modify Application screen and returns to the Edit Application screen.

- <F1> Help—Provides direct access to CCF subjects without interrupting work in progress or using this manual to answer questions about CCF. Press <F1> to access the glossary of subjects. Tab through the list and highlight the desired subject. Press <Enter> to view the text. If related information exists, you can tab to the highlighted subjects within the help text or tab to the subjects listed under "See also" and press <Enter>. Press <F1> to access the Hypertext Help window. Press <F10> to back out of the screens or press <Esc> to exit the online help and return to the program.

- <F2> List—Provides a list of either component types or failure modes for the appropriate fields. You can select a component type or failure mode from the list by highlighting a list item and pressing <Enter>.

<Enter> Modify—Saves changes to the Name, Description, CCCG Level, Component Type, and Failure Mode fields. Simultaneously, **<Enter>** returns to the Edit Applications screen.

3.1.2 Adding an Application

To add an application, press **<Ins>** to access the Add Application screen (Figure 15). Type in the name (mandatory), description (optional), CCCG level (mandatory), component type (optional), failure mode (optional), and press **<Enter>**.

Add Application

ACP_4KV_BKR_U_CC	4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96
ACP_4KV_BKR_U_CX	4160 VAC CIRCUIT BRKRS, SPURIOUS OPEN, 94/95 UPDATE, 11-4-96
AFW_AOV_UPD_VC	AUX FEEDWATER AOVS, FAIL TO CLOSE, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VO	AUX FEED AOVS, FAIL TO OPEN, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VR	AUX FEED AOVS, FAIL TO REMAIN CLOSED, 94/95 UPDATE, 11-25-96
AFW_CKV_UPD_VC	PWR AUX FEED CHK VLVS, FAIL TO CLOSE, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VO	PWR AUX FEED CHK VLVS, FAIL TO OPEN, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VR	AUX FEED CHK VLV, FAIL TO REMAIN CLOSED, 94/95 UPD, 11-23-96

Name	Description	CCCG Size --	Component Type	Failure Mode
<Esc>	<F1>	<F2>	<Enter>	
Exit	Help	List	Add	

Figure 15. Generic—Add Application screen.

NOTE: Use **<Tab>** to move from field to field on the screen.

Add Application provides the following functions:

- <Esc>** Exit—Terminates the Add Application screen and returns to the Edit Application screen.
- <F1>** Online Help—Provides direct access to CCF subjects without interrupting work in progress or using this manual to answer questions about CCF. Press **<F1>** to access the glossary of subjects. Tab through the list and highlight the desired subject. Press **<Enter>** to view the text. If related information exists, you can tab to the highlighted subjects in the help text or tab to the subjects listed under "See also" and press **<Enter>**. Press **<F1>** to access the Hypertext Help window. Press **<F10>** to back out of the screens or press **<Esc>** to exit the online help and return to the program.

<F2> List—Provides a list of either component types or failure modes for the appropriate fields. You can add a component type or failure mode from the list by highlighting a list item and pressing <Enter>.

<Enter> Add—Adds the new application and returns to the Edit Applications screen.

3.2 Event Analysis

The Events function deletes an event, views comments and narratives of an event, or analyzes an event within an application. To select the Event function, highlight the desired application, and press <F4> to access the Event Analysis screen (Figure 16).

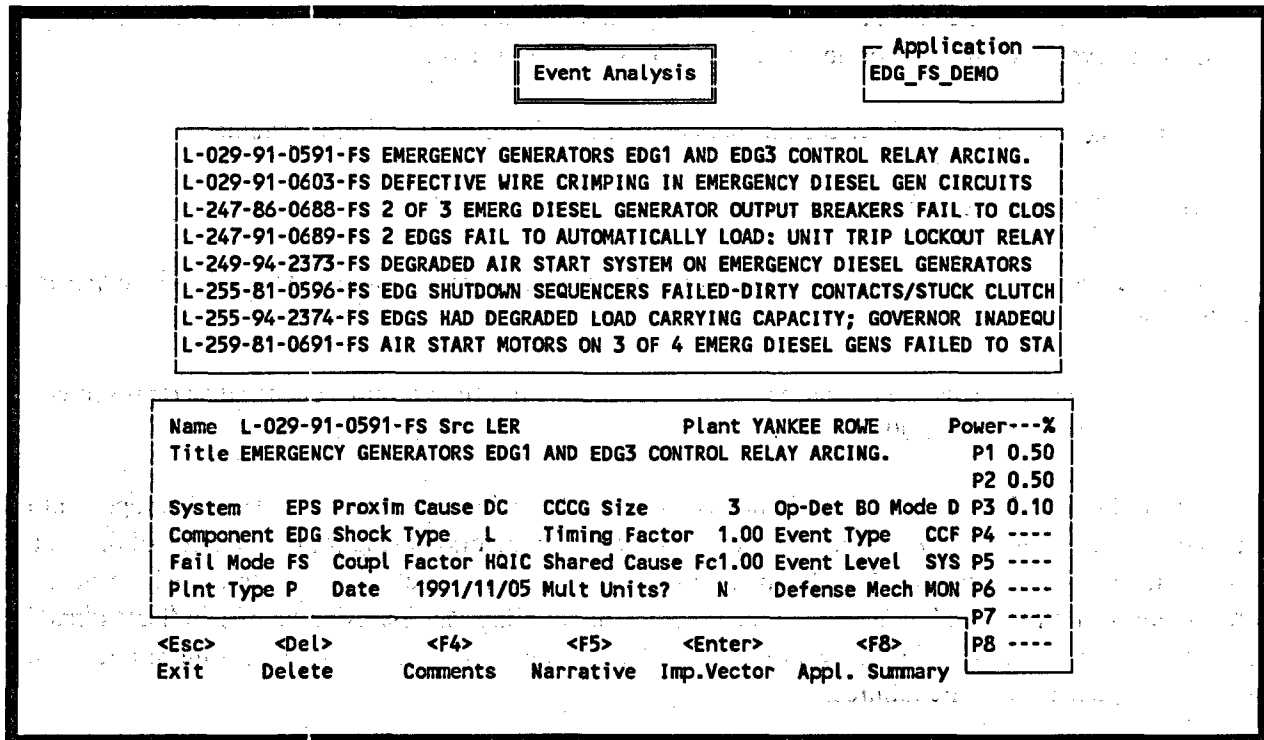


Figure 16. Generic—Event Analysis screen.

The top window lists all events contained in the application selected. The bottom window contains the information associated with the highlighted event. See Reference 1 of this report for more details about the following fields:

Name—Provides the event code number assigned to the event by the data coder.

Plant—Identifies the name of the nuclear power plant where the CCF event occurred.

Power—States the percentage of full power at the time of the CCF event.

Title—Gives a short description of the event.

System—Names the system that includes the failed component.

Component—Identifies the name of the component that experienced the CCF event.

Fail Mode—Defines the failure in terms of which function the components did not perform.

Plant Type—Define the type of plant where the CCF event occurred P-Pressurized Water Reactor and B-Boiling Water Reactor.

Proximate Cause—Characterizes the condition that is readily identified as leading to failure (a symptom) of a component or function.

Shock Type—Relates the relationship of one component failure to another. That is, the shock type classifies the event as lethal (L) or nonlethal shock (NL) to the system.

Coupling Factor—Describes the mechanism that ties the multiple failures together.

Date—Date of the event.

CCCG Level—Indicates the system size or number of redundant components that can be exposed to a CCF event.

Timing Factor—This is a measure of how close in time multiple failures occurred as represented by 'q'. This value ranges from 0.00 to 1.00.

Shared Cause Factor—Ties two failures together. This value ranges from 0.00 to 1.00, representing the analyst's assessment of the degree of presence of a factor or factors causing the propagation of the failure to more than one component. This factor provides the flexibility to classify events for which detailed information is not furnished to determine the presence of coupling factors. A value of 1 indicates that the analyst believes the failures in the event were coupled. Values less than one represent more uncertainty about the dependency of the failures.

Multiple Units—States if the event affected more than one unit at a site.

Operational Status-Detected—Shows when the event was detected.

Operational Status-Mode—Shows when the event occurred.

Event Type—Establishes which events are used in Probabilistic Risk Assessment (PRA) CCF parameter estimations.

Event Level—Establishes whether the failure affected just the component or the system.

Defense Mechanism—Describes the defenses that you can apply to the coupling factor to prevent the CCF event from occurring.

Component Degradation (P1-P8)—There are eight component degradation values. This value ranges from 0.00 to 1.00 and indicates the extent that the degraded component failed (see Reference 1).

Event Analysis provides the following functions:

- <Esc>** Exit—Terminates the Event Analysis screen and returns to the Applications screen.
- ** Delete—Removes an event from the selected application. To delete an event, highlight the event and press . A prompt will ask if this event is to be removed from the application. Enter Y or N and press <Enter>. If Y is entered, CCF removes the event from the list immediately.
- <F4>** Comments—Views comments associated with the event. You cannot edit these comments.
- <F5>** Narratives—Views narratives associated with the event. You cannot edit these narratives.
- <Enter>** Impact Vector—Performs an event impact vector analysis (see Section 3.2.1).
- <F8>** Application Summary —Summarizes the CCF statistics summary (see Section 3.4).

3.2.1 GENERIC Event Analysis

To access the Event Analysis screen (Figure 17), highlight the desired event and press <Enter>. The description window displays the first event (or the event highlighted) and its associated information. The information includes the default values for the component degradation level, timing factor, shared cause factor, and average impact vector. (You can change the default values of these fields.) CCF uses the component degradation level values, timing factor, and shared cause factor to calculate the average impact vector (shown in the bottom portion of the screen). Also, you can directly input the average impact vector, bypassing the CCF calculation altogether. A brief explanation of these fields follows.

Component Degradation—You can supply up to eight component degradation values. This value ranges from 0.00 to 1.00 and indicates the extent that the degraded component failed (see Reference 1).

Average Impact Vector—The calculation results based on algorithms built in CCF define the average impact vector. You may input your own numbers, if desired, instead of using the CCF results. (See Volume 2.)²

NOTE: Use <Tab> to move from field to field on the screen.

Event L-219-86-1158-CC		Generic Event Analysis		1 of 21					
Title 4160V BREAKERS WITH POTENTIAL RESTART FAILURE.									
Proximate Cause	DE	Component Degradation Level							
Coupling Factor	HDCP	P1	P2	P3	P4	P5	P6	P7	P8
Event Type	CCF	0.10	0.10	0.10	0.01	0.01	0.01	----	----
CCF Shock Type	L	Timing Factor				1.00			
Failure Mode	00	Shared Cause Factor				1.00			
CCCG Size	6								

Average Impact Vector							
F1	F2	F3	F4	F5	F6	F7	F8
0.2572	0.0335	0.0018	0.0000	0.0000	0.0000	----	----

<Esc>	<F1>	<Enter>	<F3>	<F4>	<F5>	<F6>	<F7>	<F8>
Exit	Help	Calculate	View Event	Comment	Narr.	Previous	Next	Save

Figure 17. Generic—Event Analysis screen.

Generic Event Analysis provides the following functions:

- <Esc> Exit—Terminates the GENERIC Event Analysis screen and returns to the Event Analysis screen.
- <F1> Online Help—Provides direct access to CCF subjects without interrupting work in progress or using this manual to answer questions about CCF. Press <F1> to access the glossary of subjects. Tab through the list and highlight the desired subject. Press <Enter> to view the text. If related information exists, you can tab to the highlighted subjects in the help or tab to the subjects listed under "See also" and press <Enter>. Press <F1> to access the Hypertext Help window. Press <F10> to back out of the screens or press <Esc> to exit the online help and return to the program.
- <F2> List—Provides a list of degradation values that you can insert in the Component Degradation Level fields. To select a value for a field, press <F2>, highlight a value in the list, and press <Enter>. Exit the list by pressing <Esc>.

NOTE: <F2> is available for the Component Degradation Level fields only.

- <Enter> Calculate—Calculates the average impact vector based on the information provided. However, you may want to use specific values for the average impact vector. CCF allows you to edit this field. In addition, CCF will only perform the calculations if requested.

- <F3>** View Event—Views information about the event, including the component degradation levels. View Event also allows you to view comments associated with the event. After you finish viewing the information, press **<Enter>** or **<Esc>** to return to the previous screen.
- <F4>** Comment—Directly views comments associated with the event without accessing the View Event screen. You cannot edit these comments.
- <F5>** Narrative—Directly views narrative associated with the event without accessing the View Event screen. You cannot edit these narratives.
- <F6>** Previous—Displays the previous event. This allows you to scroll back through the events in an application one record at a time.
- <F7>** Next—Displays the next event. This allows you to scroll forward through the events in an application one record at a time.
- <F8>** Save—Saves the current screen selections and values as the default values for the next time you summarize the statistics of the application. The message "Record saved" will appear at the bottom of the screen to verify this operation. The next event will be displayed.

3.3 Copy Application

Copy Application allows you to make copies of existing applications. All the events for the selected application can be copied to a new application. To run Copy Application, highlight the application you wish to copy and press **<F5>**. The Copy Application screen (Figure 18) allows you to make the copy of that application.

CCF Copy Application screen provides the following functions:

- <Esc>** Exit—Terminates the CCF Copy Application screen and returns to the Applications screen.
- <Enter>** Copy—Copies the selected application to the application specified.

3.4 Application Summary

Application Summary calculates summary statistics for an application based, in part, on the impact vectors of the events belonging to that application. In addition, Calculate lets you perform these calculations based solely upon their own input numbers, rather than using an application event list. To run Application Summary, highlight the application you want and press **<Enter>**. The CCF Summary Statistics screen (Figure 19) allows you to include mapping of the events and/or staggering the testing scheme for the events in your calculations. You may also look at point estimates of events using the Alpha-Factor model, Multiple Greek Letter model, or both models.

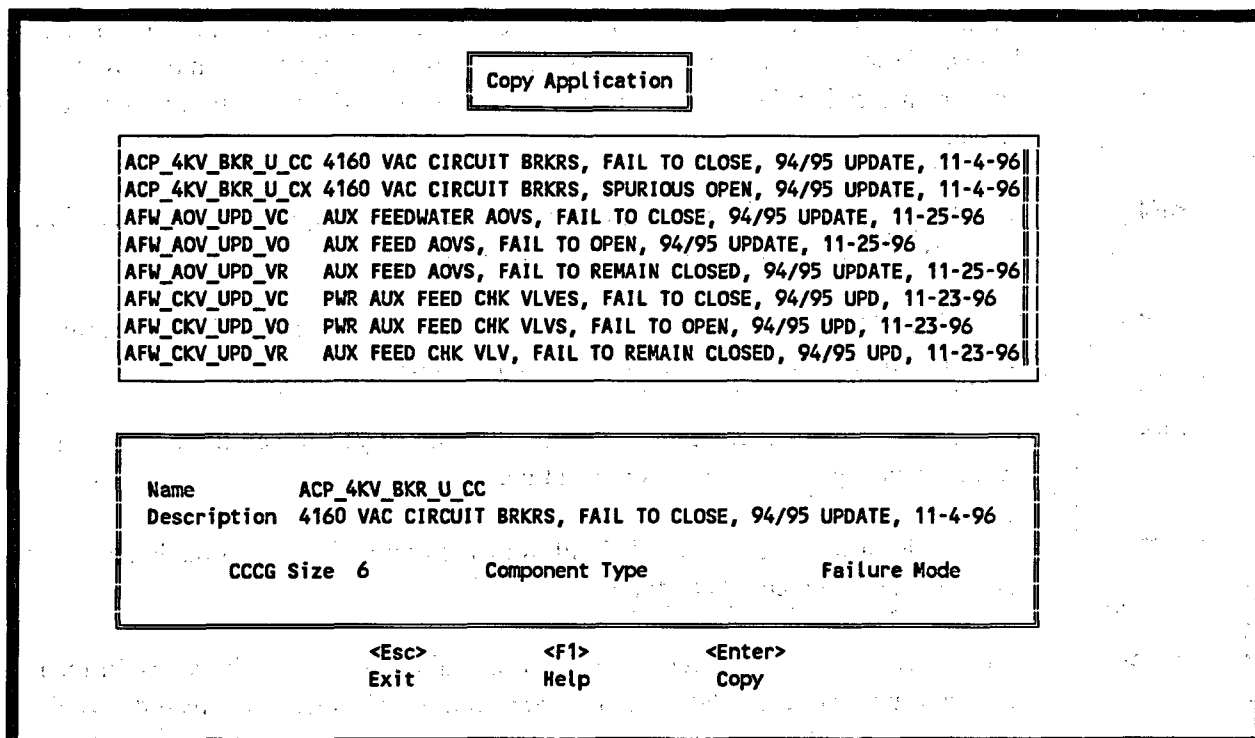


Figure 18. Generic—Copy Application screen.

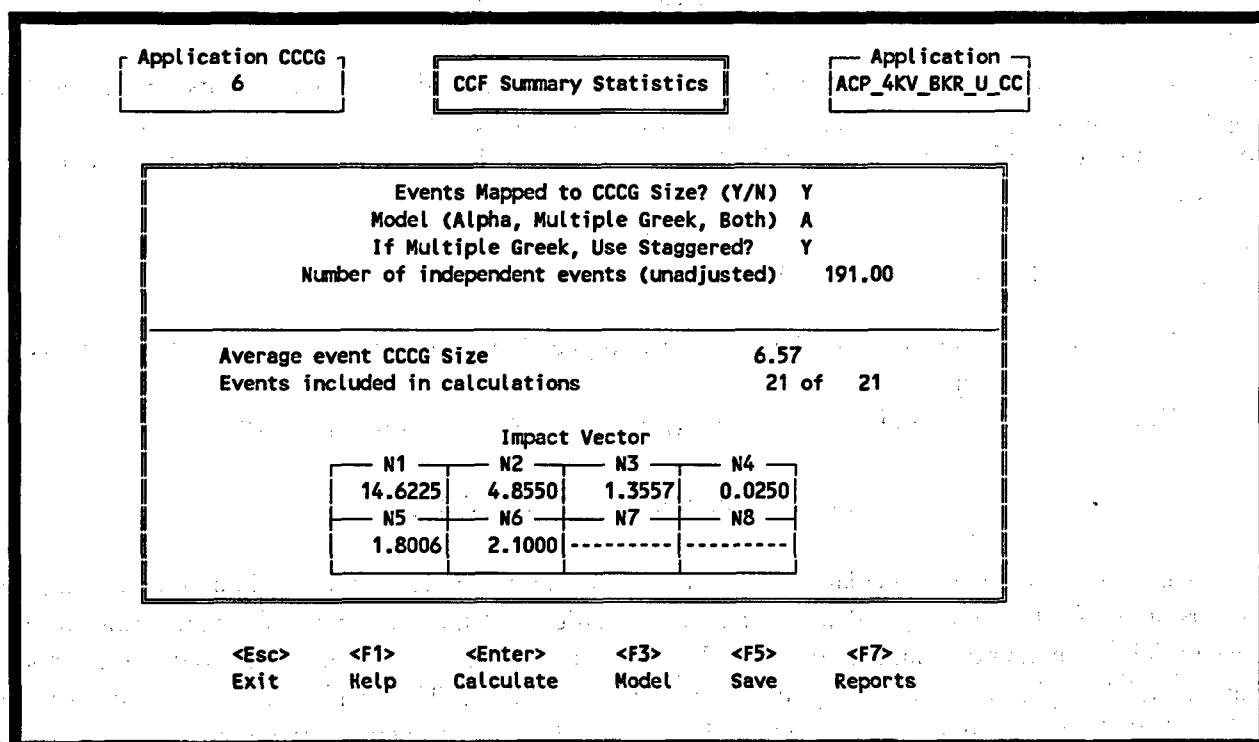


Figure 19. Generic—CCF Summary Statistics screen.

CCF Summary Statistics provides the following functions:

- <Esc> Exit—Terminates the CCF Summary Statistics screen, and then displays the Save/Cancel window if you performed any application summaries; otherwise, <Esc> returns to the Applications screen.
- <F2> Independent Event Totals—Breaks down the number of independent events. This function is available when you place your cursor in the Number or Independent Events field. Press <F2> to access the Independent Event Totals screen (Figure 20).

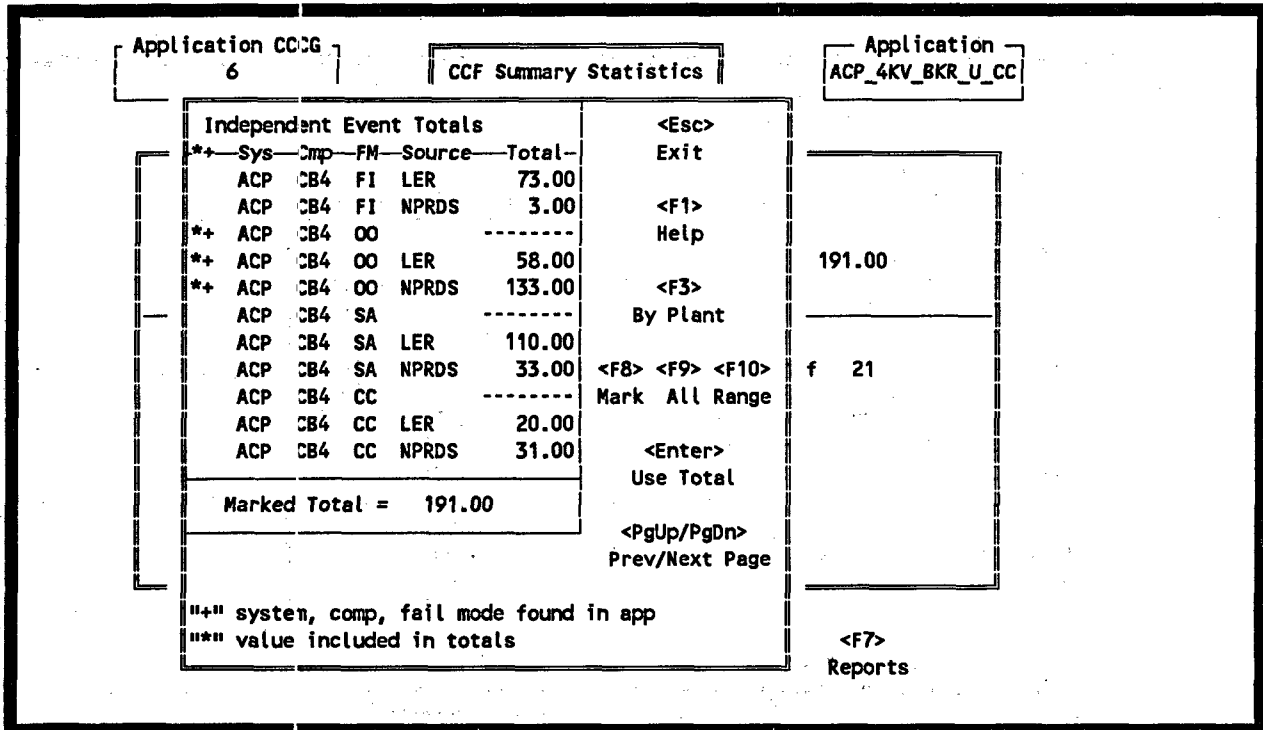


Figure 20. Generic—Breakdown of independent event total.

NOTE: The <F2> key is enabled for the Number of Independent Events field only.

- <Enter> Calculate—Recalculates the impact vectors and the point estimations of the models if you change your mapped and/or staggered selections for the application.
- <F3> Model—Displays the point estimations for both models and the Bayesian Uncertainty Distribution for the Alpha-Factor Model (see Sections 3.4.1 and 3.4.2).
- <F5> Save—Saves the current screen selections and values as the default values for the next time you summarize the statistics of the application. The message "Record saved" will appear at the bottom of the screen to verify this operation.
- <F7> Report—Generates a special quantification report or an application report (see Section 3.5).

You can also alter the values included in the marked total value by adding or deleting independent events with the <F8>, <F9>, and <F10> keys (see Section 1.4).

- <Esc> Exit—Terminates the Independent Event Totals screen without changing the number of independent events field used in the calculation.
- <Enter> Use Total—Terminates the Independent Event Totals screen and changes the number of independent event field used in the calculation to the marked total shown on this screen.
- <F3> By Plant—Breaks down the number of independent events for the highlighted entry by the plants which contributed to the total (Figure 21).

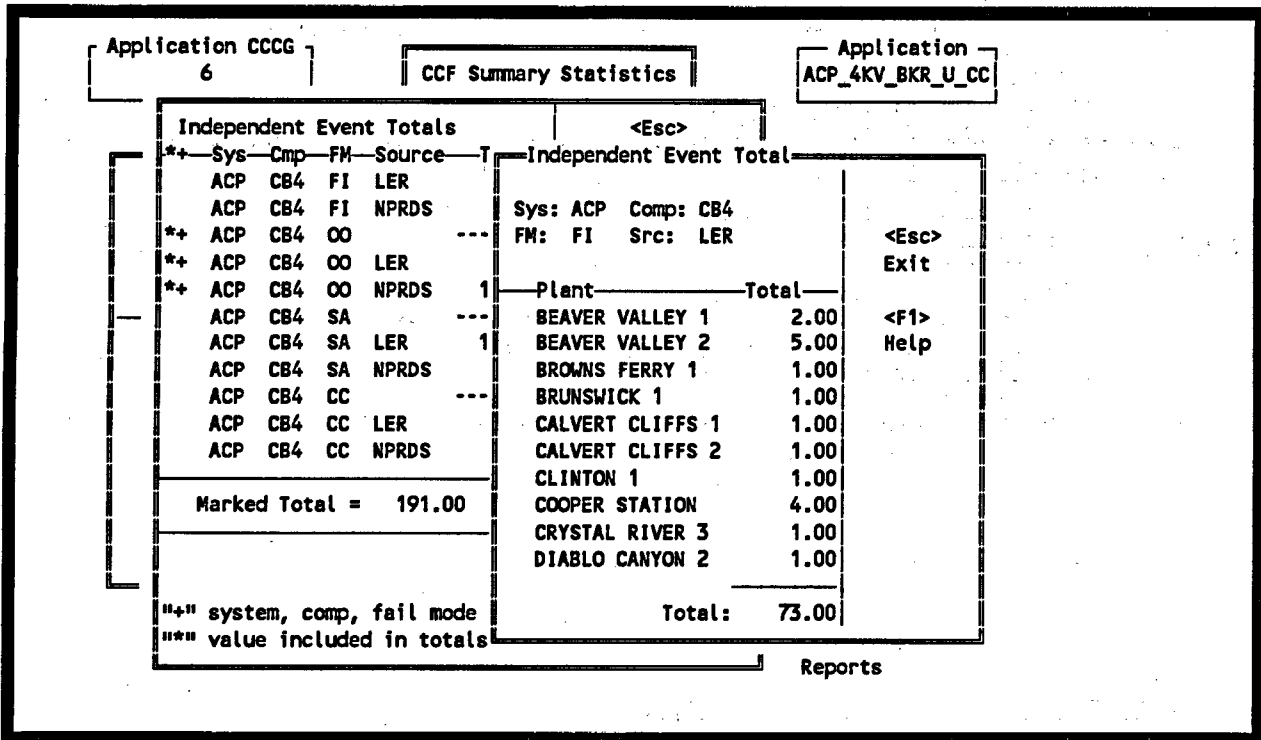


Figure 21. Generic—Breakdown of independent event totals by plant.

3.4.1 Alpha-Factor Model

The Alpha-Factor Model displays Bayesian Distributions, point estimates, and uncertainty summary information for the model. To initiate this model, type an A in the Model field (Figure 19). Press <F3> to access the Select Display Type (Figure 22). Use the up and down arrow keys to highlight the appropriate uncertainty calculation method or type the highlighted letter into the Option field. Press <Enter> to access either the Point Estimate screen (see Section 3.4.1.1), the Nonhomogeneous Bayesian Plant to Plant Distribution menu (see Section 3.4.1.2), the Homogeneous Bayesian screen (see Section 3.4.1.3), or the Uncertainty Summary screen (see Section 3.4.1.4).

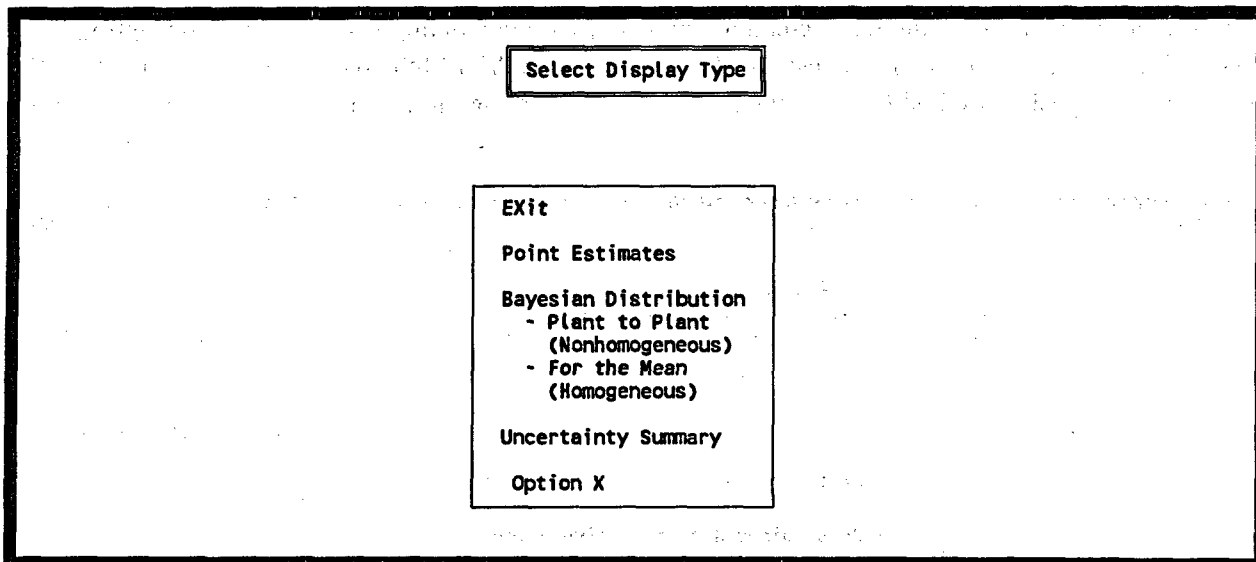


Figure 22. Generic—Alpha-Factor Model menu.

3.4.1.1 Point Estimate. The Alpha-Factor Model Point Estimate screen (Figure 23) provides the following functions:

<Esc> Exit—Terminates this screen and returns to the Alpha-Factor model menu.

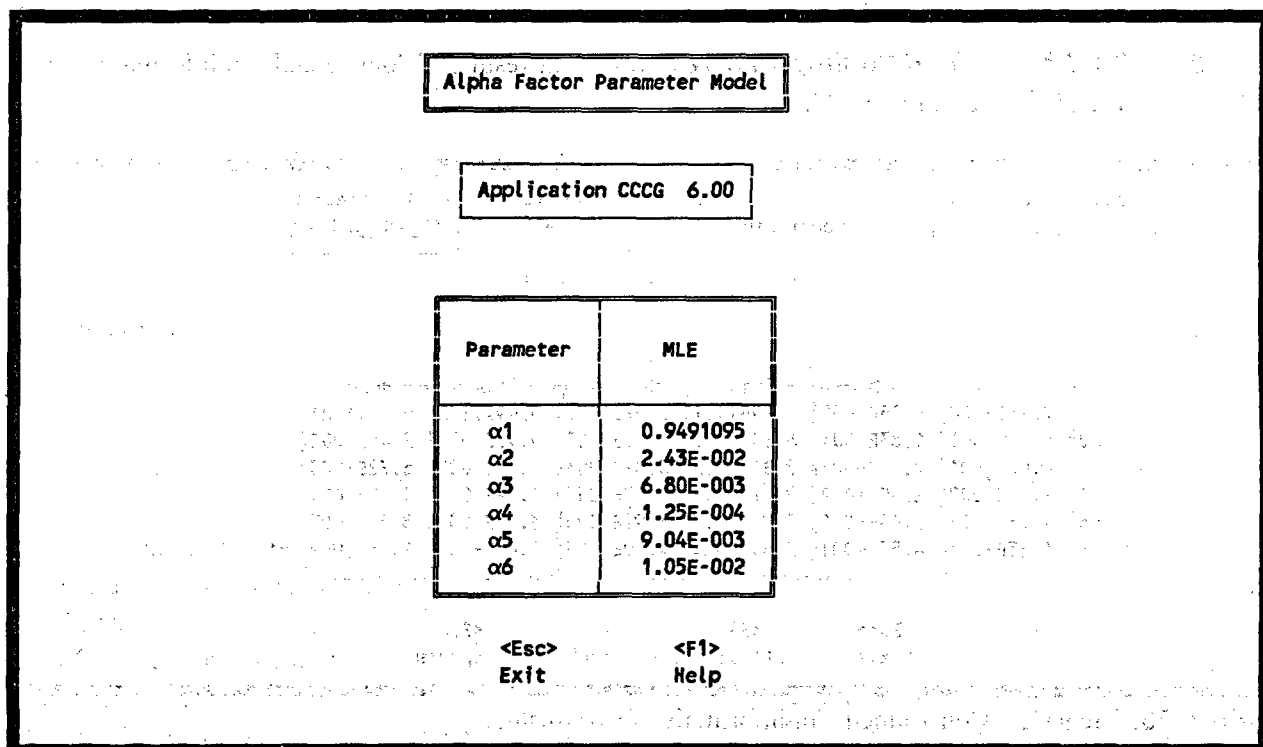


Figure 23. Generic—Alpha-Factor Model Point Estimate screen.

3.4.1.2 Nonhomogeneous Bayesian Distributions or Plant to Plant Distributions. The Nonhomogeneous Bayesian Model Selection Menu is shown in Figure 24. Use the up and down arrow keys

to highlight the appropriate model calculation method or type the highlighted letter into the Option field. Press <Enter> to access either the Constrained Noninformative Prior Method (see Section 3.4.1.2.1) or the Hierarchical Bayesian Method (see Section 3.4.1.2.2). Press <Esc> to return to the Alpha-Factor Model menu.

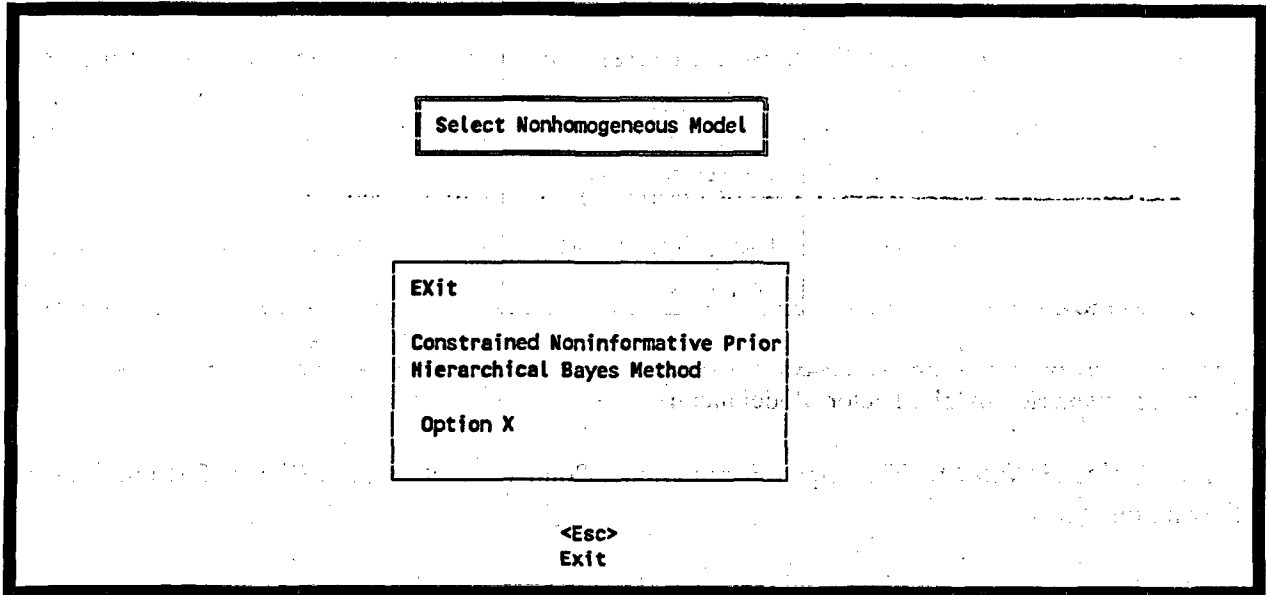


Figure 24. Generic—Nonhomogeneous Model menu.

3.4.1.2.1 Constrained Noninformative Prior—The results of Constrained Noninformative Prior calculations are displayed in Figure 25.

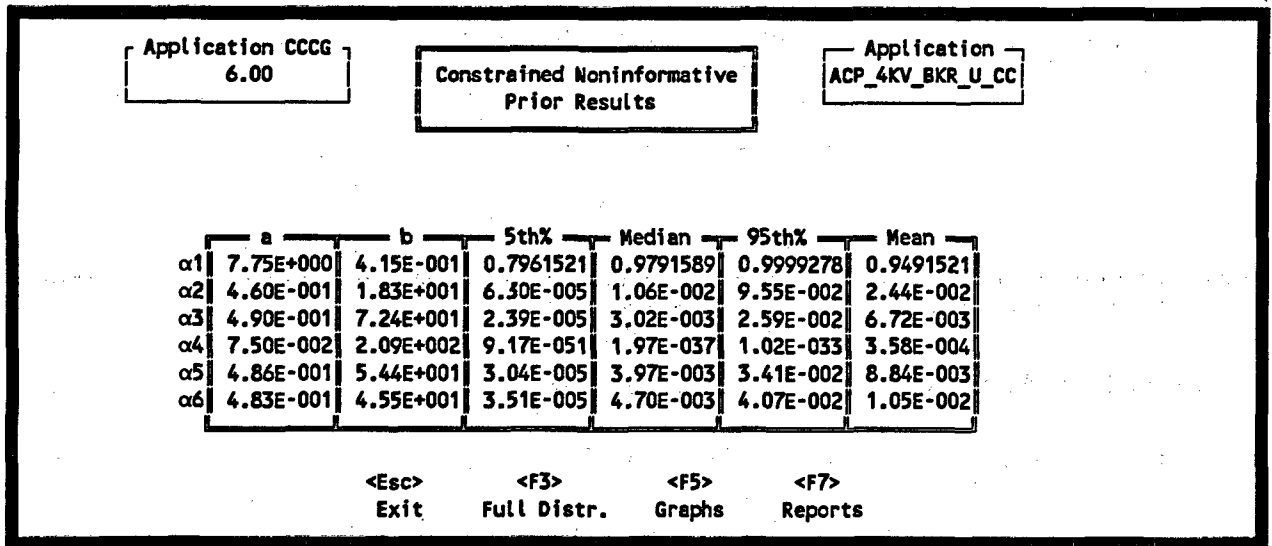


Figure 25. Generic—Constrained Noninformative Prior Results.

The Constrained Noninformative Prior Results provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Nonhomogeneous Model menu.
- <F3> Full Distribution—Displays the full distribution for each applicable alpha. (Figure 26).
- <F5> Graphs—Plots the probability density or cumulative distribution. To initiate this function, press <F5>, enter the plot type either cumulative or density and press <Enter>. Next enter the alpha parameter to plot (from 1 to CCCG number), and then press <Enter> to plot the distributions.
- <F7> Reports—Prints an Estimation Report of the Constrained Noninformative Prior Results.

α	α1	α2	α3	α4	α5	α6
0.005	6.13E-001	4.23E-007	2.18E-007	5.96E-034	2.65E-007	2.96E-007
0.010	6.64E-001	1.91E-006	8.97E-007	6.15E-030	1.10E-006	1.24E-006
0.025	7.38E-001	1.40E-005	5.82E-006	1.24E-024	7.27E-006	8.29E-006
0.050	7.96E-001	6.32E-005	2.39E-005	1.28E-020	3.03E-005	3.48E-005
0.100	8.55E-001	2.86E-004	9.90E-005	1.32E-016	1.26E-004	1.46E-004
0.200	9.13E-001	1.30E-003	4.13E-004	1.36E-012	5.34E-004	6.25E-004
0.250	9.31E-001	2.14E-003	6.59E-004	2.68E-011	8.56E-004	1.00E-003
0.300	9.45E-001	3.22E-003	9.71E-004	3.05E-010	1.26E-003	1.48E-003
0.400	9.65E-001	6.25E-003	1.81E-003	1.41E-008	2.37E-003	2.80E-003
0.500	9.79E-001	1.06E-002	3.03E-003	2.76E-007	3.97E-003	4.69E-003
0.600	9.88E-001	1.70E-002	4.74E-003	3.15E-006	6.23E-003	7.38E-003
0.700	9.94E-001	2.63E-002	7.22E-003	2.47E-005	9.51E-003	1.12E-002
0.750	9.96E-001	3.27E-002	8.91E-003	6.24E-005	1.17E-002	1.39E-002
0.800	9.97E-001	4.08E-002	1.10E-002	1.50E-004	1.46E-002	1.73E-002
0.900	9.99E-001	6.77E-002	1.82E-002	8.16E-004	2.41E-002	2.86E-002
0.950	9.99E-001	9.60E-002	2.59E-002	2.08E-003	3.42E-002	4.06E-002
0.975	1.00E+000	1.24E-001	3.38E-002	3.80E-003	4.46E-002	5.30E-002
0.990	1.00E+000	1.62E-001	4.45E-002	6.54E-003	5.86E-002	6.96E-002
0.995	1.00E+000	1.90E-001	5.27E-002	8.85E-003	6.94E-002	8.22E-002

<Esc>

Figure 26. Generic—Full distribution of the constrained noninformative prior results.

The Full Distribution screen provides the following function:

- <Esc> Exit—Terminates this screen and returns to the Constrained Noninformative Prior Results screen.

3.4.1.2.2 Hierarchical Bayesian Method—The results of Hierarchical Bayesian menu is displayed in Figure 27.

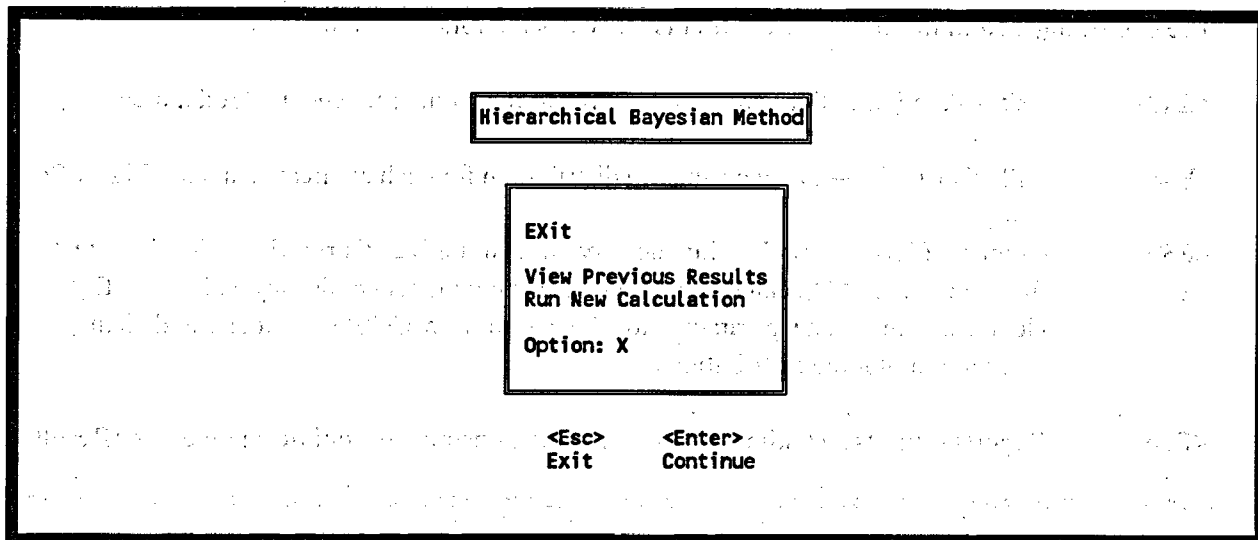


Figure 27. Generic—Hierarchical Bayesian Method menu.

Use the up and down arrow keys to highlight the appropriate selection or type the highlighted letter into the Option field. Press <Enter> to either View Previous Results (see Section 3.4.1.2.3.1) or Run New Calculation (see Section 3.4.1.2.3.2). Press <Esc> to return to the Nonhomogeneous Model menu screen.

3.4.1.2.3.1 Hierarchical Bayesian Method—View Previous Results—The results of the last Hierarchical Bayesian calculation saved will be displayed in Figure 28.

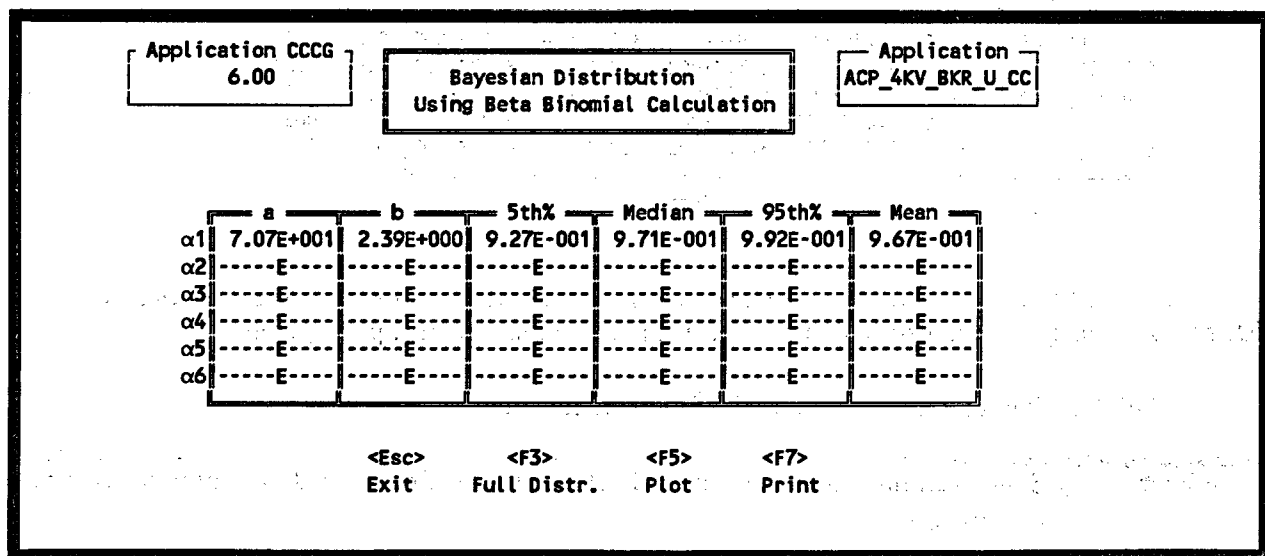


Figure 28. Generic—Hierarchical Bayesian Method results.

The Hierarchical Bayesian Method results screen provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Hierarchical Bayesian menu screen.
- <F3> Full Distribution—Displays the full posterior distribution for each applicable alpha (Figure 26).
- <F5> Plot Distribution—Plots the probability density or cumulative distribution. To initiate this function, press <F5>, enter the plot type either cumulative or density and press <Enter>. Next enter the alpha parameter to plot (from 1 to CCCG number), and then press <Enter> to plot the distributions.
- <F7> Print Model—Prints an Estimation Report of the Hierarchical Bayesian Method Distribution. See Sections 3.4.1 and 3.4.3 for more details.

3.4.1.2.3.2 Hierarchical Bayesian Method—Run New Calculations—An introduction screen (Figure 29) provides information about the Hierarchical Bayesian calculation.

Intermediate files may be saved during the computation. To save these files select yes in Save Files and enter a file name.

Save Files: N (Y/N)
File Name : DATAFILE

	Run Calc.	Use Ln Scale	Cmp Bnds	User Defined Boundaries					
				Alpha			Beta		
				Minimum	Maximum	Pts	Minimum	Maximum	Pts
1	X			3.29E-001	1.77E+003	100	1.23E-002	1.58E+001	100
2	X		X	-----E-----	-----E-----	---	-----E-----	-----E-----	---
3	X		X	-----E-----	-----E-----	---	-----E-----	-----E-----	---
4	X		X	-----E-----	-----E-----	---	-----E-----	-----E-----	---
5	X		X	-----E-----	-----E-----	---	-----E-----	-----E-----	---
6	X		X	-----E-----	-----E-----	---	-----E-----	-----E-----	---

<Esc> <Enter>
 Exit Continue

Figure 29. Generic—Hierarchical Bayesian Method—Run new calculation initial screen.

To create intermediate files, enter Y, and enter a name for the file(s). The Hierarchical Bayesian method may be run for an individual alpha, several alpha values, or for all of the alpha values. To run the calculation for an alpha place an X in the Run Calculation Column. If you wish to have the computer generate the boundaries, place an X in the Computer Ends column. If you wish to use the Log Normal Scale, place an X in the Use Ln Scale Column.

- <Esc> Exit—Terminates this screen and returns to the Hierarchical Bayesian menu screen.

<Enter> Continue—Continues with the Hierarchical Bayesian Calculation.

Calculation progress updates will be displayed at the bottom of the screen throughout the calculation. To terminate the calculation at anytime, press <Esc>. A message will appear asking you to confirm the termination of the calculation, press Y to terminate, N to cancel the terminate and continue the calculation. Once the calculation has completed the Hierarchical Bayesian Method Results screen (Figure 28) will be displayed.

3.4.1.3 Homogeneous Bayesian Distributions. The results of Homogeneous Bayesian calculations are displayed in Figure 30.

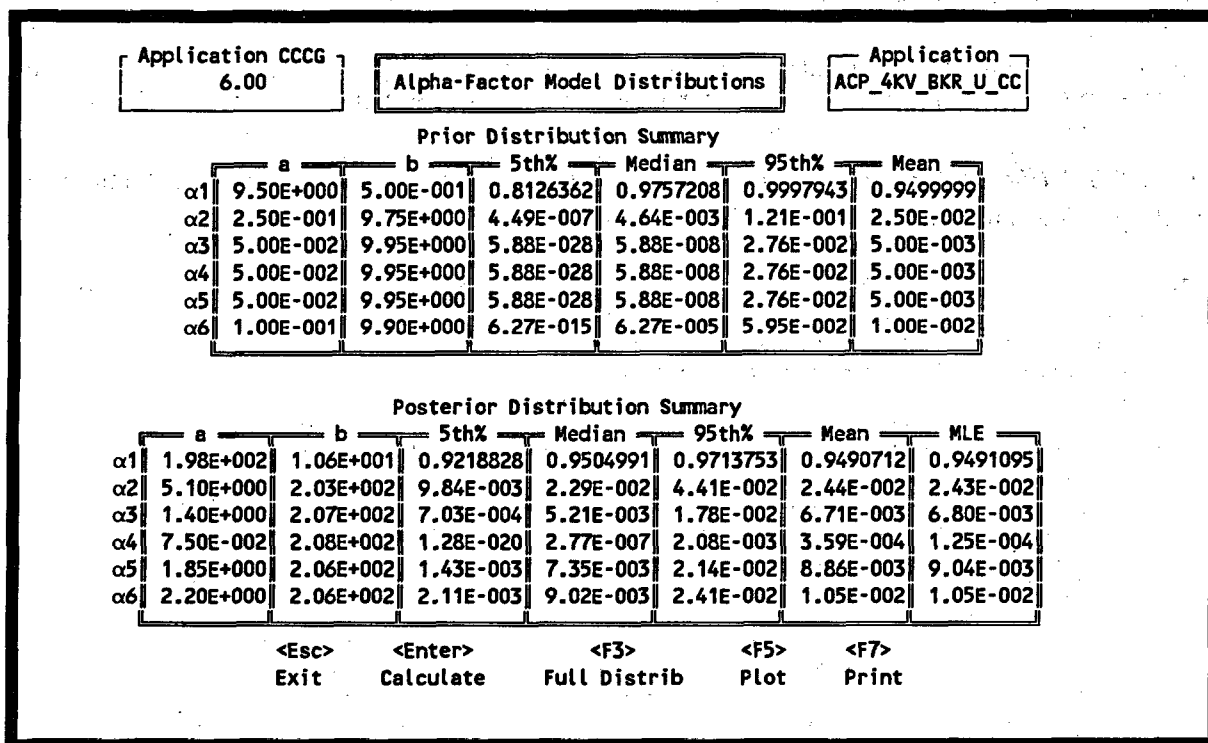


Figure 30. Generic—Homogeneous Bayesian Distributions.

The Homogeneous Bayesian Distribution screen provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Alpha Factor Model menu.
- <Enter> Calculate—Allows you to enter distribution parameters from A1 to CCCG size and then calculates the prior and posterior distribution summaries.

NOTE: The Program calculates the distributions using the set of input values in column "a". Default values in column "a" are provided, based on the CCCG size. You can input your own "a" values and recalculate the distributions. Save the application to retain the new values; otherwise, exit from the option, and the program will default back to the original values suggested in column "a". Note that any time you change the CCCG size for the application, the program will default to the suggested values in column "a" for the new CCCG size.

- <F3> Full Distribution—Displays the full posterior distribution for each applicable alpha (Figure 25).
- <F5> Plot Distribution—Plots the probability density for the prior and posterior distributions. To initiate this function, press <F5>, enter the alpha parameter to plot (from 1 to 6), and then press <Enter> to plot the distributions.
- <F7> Print Model—Prints an Estimation Report of the Bayesian Distribution. See Sections 3.5.1 and 3.5.3 for more details.

3.4.1.4 Bayesian Uncertainty Summary. The results of Bayesian Uncertainty calculations are displayed in Figure 31.

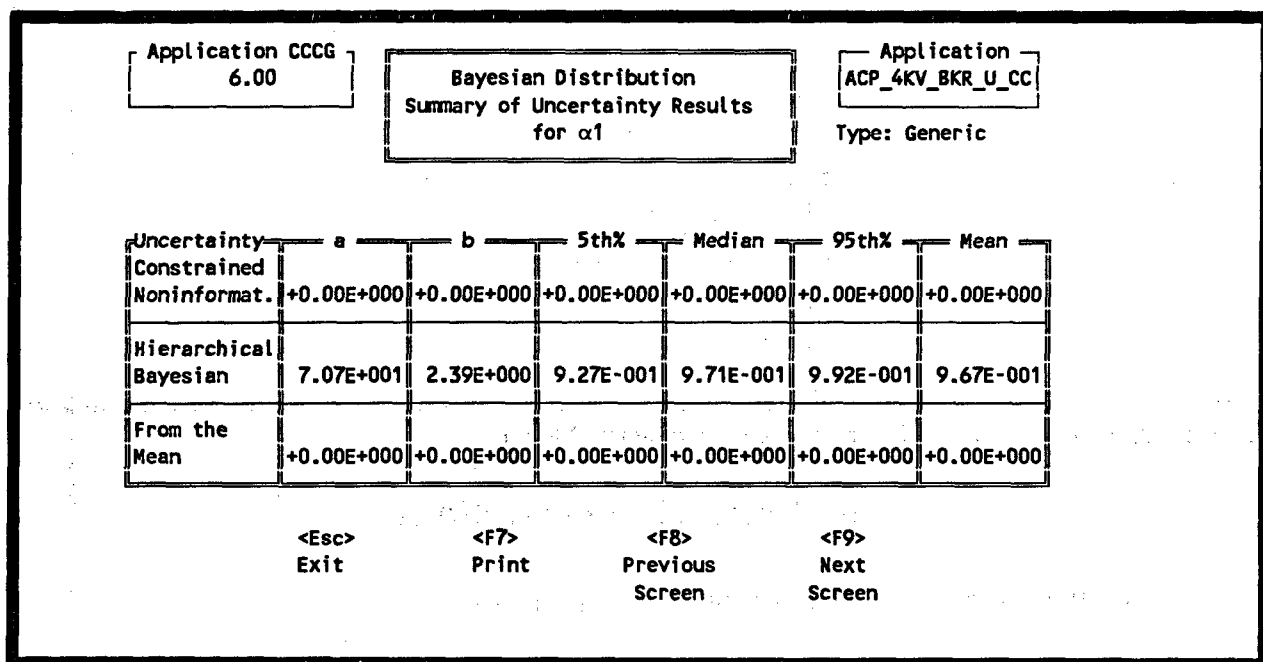


Figure 31. Generic—Bayesian uncertainty summary.

The Bayesian Uncertainty Summary screen (Figure 31) provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Alpha Factor Model menu.
- <F7> Print Model—Prints an Uncertainty Summary Report of the Bayesian Distributions. See Sections 3.5.1 and 3.5.3 for more details.
- <F8> Previous Screen—Displays the previous alpha comparison screen.
- <F9> Next Screen—Displays the next alpha comparison screen.

3.4.2 Multiple Greek Letter Model

To initiate the Multiple Greek Letter models (Figure 32), type an M in the Model field (Figure 19) and press the F3 key to generate the model.

Parameter	MLE
1-Beta	1.58E-001
Beta	7.26E-001
Gamma	8.42E-001
Delta	9.95E-001
Epsilon	5.83E-001
Mu	-----E----

<Esc> Exit <F1> Help

Figure 32. Generic—Multiple Greek Factor Parametric Model.

3.5 Generic Report Options

The Report option allows you to create the following reports:

- Application (unmapped events)
- Event Summary Statistics (unmapped events)
- Application (mapped events)
- Application Summary (mapped events)
- Detailed Events (mapped events)
- Event Summary Statistics (mapped events)
- Application Event Report (mapped events)

Figure 33 or Figure 34 appears if you type N or Y in the Events Mapped to CCGG Size field respectively. See Sections 3.5.1 through 3.5.7 for specific details about the reports.

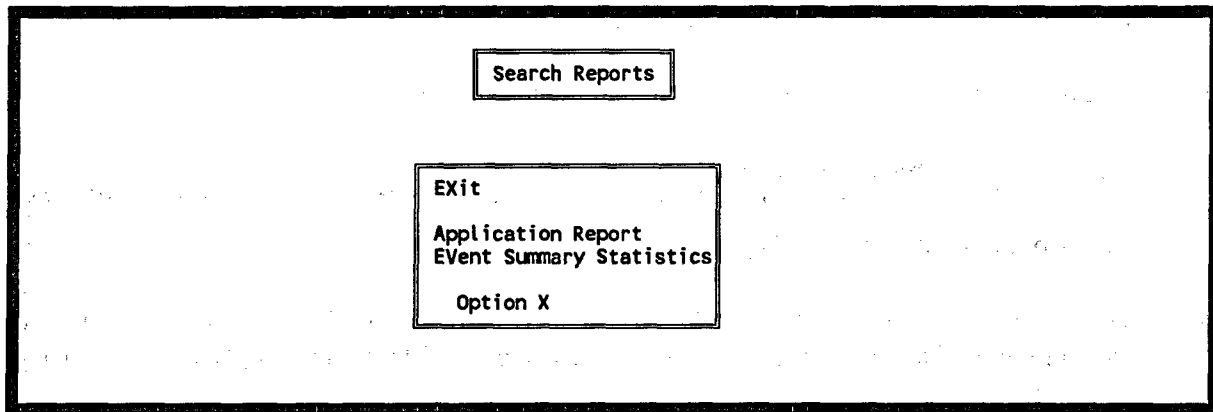


Figure 33. Generic—Unmapped—event, Search Reports screen.

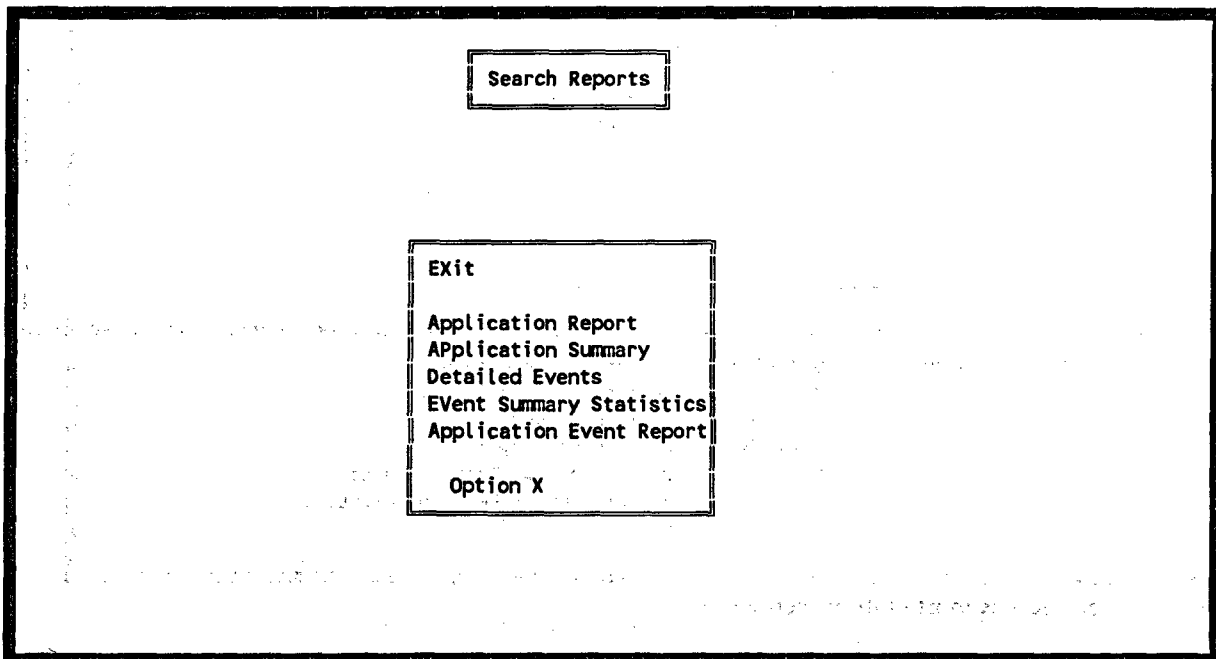


Figure 34. Generic—Mapped—event, Search Reports screen.

3.5.1 Application Report (Generic Unmapped)

1. Type N to perform calculations without mapping the event.
2. Press <F7> to access the Search Reports screen (Figure 33).
3. Type A or highlight Application Report.
4. Press <Enter> to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.

Report Options

Report Title
Event Summary Statistics

Output File Name
CON

NOTE: File Name = "CON" - Output report to the screen.
"PRN" - Output report to the printer.
" " - No report is produced.
<ESC> - No report is produced.
other - Valid DOS file name. Examples are:
A:LISTING, C:\REPORT\REP1, and RESULTS.

Figure 35. Generic—Report Options screen.

5. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:
 - PRN Prints the report on the attached printer.
 - " " If the file name is left blank, no report will be generated.
 - <Esc> No report will be generated.
 - other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.
6. Press <Enter> once you supply an output destination. A report similar to Figure 36 will be generated.

3.5.2 Event Summary Statistics Report

1. Type N to perform calculations without mapping the event.
2. Press <F7> to access the Search Reports screen (Figure 33).
3. Type V or highlight Event Summary Statistics.
4. Press <Enter> to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.

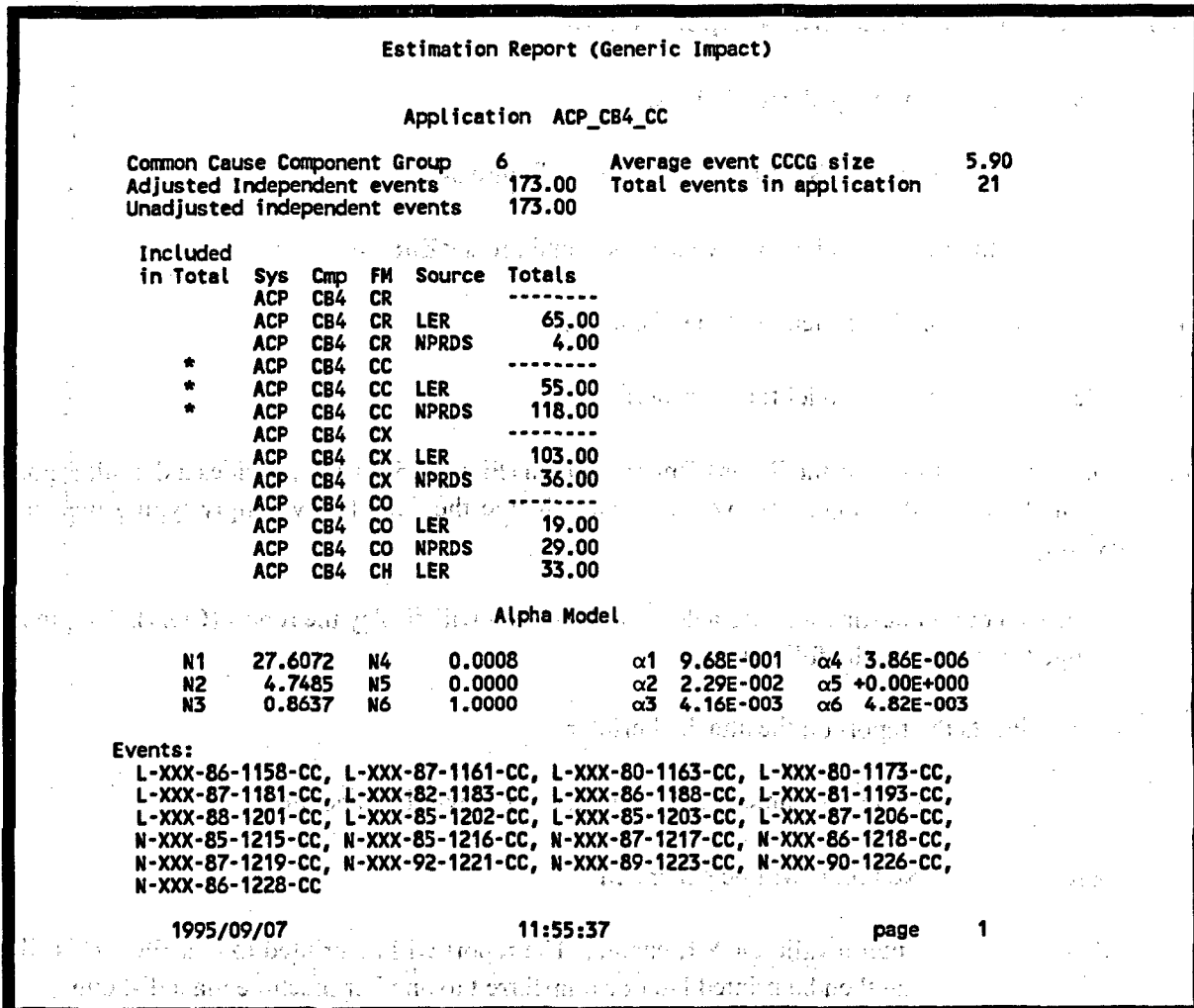


Figure 36. Generic—Example of a Generic Impact Estimation Report.

5. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

6. Press **<Enter>** once you supply an output destination. A report similar to Figure 37 will be generated.

3.5.3 Application Report (Generic Mapped Impact)

1. Type **Y** to perform mapped calculations.
2. Press **<F7>** to access the Search Reports screen (Figure 34).
3. Type **R** or highlight Application Event Report and press **<Enter>**.
4. The Select Report Type menu will be displayed.
5. Select the uncertainty model for the report.
6. Press **<Enter>** to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.
7. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

8. Press **<Enter>** once you supply an output destination. A report similar to the report provided in selected uncertainty option will be generated (Figure 38).

Estimation Report (Generic Mapped Impact)

Application EDG_FS_DEMO

Common Cause Component Group	6	Average event CCG size	2.83
Adjusted Independent events	1643.10	Total events in application	55
Unadjusted independent events	775.00		

Included

in Total	Sys	Cmp	FM	Source	Totals
	EPS	EDG	FR		-----
	EPS	EDG	FR	LER	587.00
	EPS	EDG	FR	NPRDS	2.00
*	EPS	EDG	FS		-----
*	EPS	EDG	FS	LER	764.00
*	EPS	EDG	FS	NPRDS	11.00
	EPS	EDG	FX	LER	23.00

Alpha Model

N1	7.8655	N5	8.2757	α1	0.9665335	α5	4.84E-003
N2	12.4137	N6	13.2901	α2	7.26E-003	α6	7.78E-003
N3	14.1969	N7	-----	α3	8.31E-003	α7	-----E----
N4	8.9886	N8	-----	α4	5.26E-003	α8	-----E----

Events:

L-029-91-0591-FS, L-029-91-0603-FS, L-247-86-0688-FS, L-247-91-0689-FS,
 L-249-94-2373-FS, L-255-81-0596-FS, L-255-94-2374-FS, L-259-81-0691-FS,
 L-259-82-0692-FS, L-259-86-0597-FS, L-261-93-0598-FS, L-271-84-0600-FS,
 L-277-95-2376-FS, L-280-91-0694-FS, L-286-87-1237-FS, L-286-90-0693-FS,
 L-286-92-0702-FS, L-295-94-2588-FS, L-296-88-1172-FS, L-304-94-2378-FS,
 L-317-80-0619-FS, L-320-80-0627-FS, L-325-82-0699-FS, L-325-82-0700-FS,
 L-327-80-0622-FS, L-327-80-0623-FS, L-327-80-0624-FS, L-327-82-0701-FS,
 L-339-87-0638-FS, L-348-80-0703-FS, L-348-81-0705-FS, L-348-81-0706-FS,
 L-364-81-0707-FS, L-366-83-0708-FS, L-369-90-0645-FS, L-387-82-0710-FS,
 L-387-85-0647-FS, L-388-84-0651-FS, L-395-85-0652-FS, L-412-93-0654-FS,
 L-416-82-0711-FS, L-424-90-0735-FS, L-425-90-0734-FS, L-425-91-0659-FS,
 L-440-87-0660-FS, L-456-90-0736-FS, L-457-90-0747-FS, L-461-92-0725-FS,
 L-461-93-0726-FS, L-499-91-0728-FS, L-528-85-0685-FS, L-528-87-0533-FS,
 L-529-87-0540-FS, L-530-87-0731-FS, N-313-84-1240-FS

1997/06/14

02:11:19

page 1

Figure 38. Generic—Example of a Generic Application report.

3.5.4 Application Summary Report (Generic Mapped Impact)

1. Type Y to perform mapped calculations.
2. Press <F7> to access the Search Reports screen (Figure 34).
3. Type P or highlight Application Summary Report.
4. Press <Enter> to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.

- Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

- Press <Enter> once you supply an output destination. A report similar to Figure 39 will be generated.

Applications Listing		
Application	CCCG Size	Description
EDG_FS_DEMO	6	DEMO APPLICATION: EVENTS WITH COMPONENT EDG AND SYSTEM FS L-029-91-0591-FS, L-029-91-0603-FS, L-247-86-0688-FS, L-247-91-0689-FS, L-249-94-2373-FS, L-255-81-0596-FS, L-255-94-2374-FS, L-259-81-0691-FS, L-259-82-0692-FS, L-259-86-0597-FS, L-261-93-0598-FS, L-271-84-0600-FS, L-277-95-2376-FS, L-280-91-0694-FS, L-286-87-1237-FS, L-286-90-0693-FS, L-286-92-0702-FS, L-295-94-2588-FS, L-296-88-1172-FS, L-304-94-2378-FS, L-317-80-0619-FS, L-320-80-0627-FS, L-325-82-0699-FS, L-325-82-0700-FS, L-327-80-0622-FS, L-327-80-0623-FS, L-327-80-0624-FS, L-327-82-0701-FS, L-339-87-0638-FS, L-348-80-0703-FS, L-348-81-0705-FS, L-348-81-0706-FS, L-364-81-0707-FS, L-366-83-0708-FS, L-369-90-0645-FS, L-387-82-0710-FS, L-387-85-0647-FS, L-388-84-0651-FS, L-395-85-0652-FS, L-412-93-0654-FS, L-416-82-0711-FS, L-424-90-0735-FS, L-425-90-0734-FS, L-425-91-0659-FS, L-440-87-0660-FS, L-456-90-0736-FS, L-457-90-0747-FS, L-461-92-0725-FS, L-461-93-0726-FS, L-499-91-0728-FS, L-528-85-0685-FS, L-528-87-0533-FS, L-529-87-0540-FS, L-530-87-0731-FS, N-313-84-1240-FS
1997/06/14	02:12:18	page 1

Figure 39. Generic—Example of a Generic Application Summary report.

3.5.5 Detailed Events (Generic Mapped)

- Type Y to perform mapped calculations.
- Press <F7> to access the Search Reports screen (Figure 34).
- Type P or highlight Application Summary Report.

4. Press **<Enter>** to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.
5. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

6. Press **<Enter>** once you supply an output destination. A report similar to Figure 40 will be generated.

3.5.6 Event Summary Statistics (Generic Mapped)

1. Type **Y** to perform mapped calculations.
2. Press **<F7>** to access the Search Reports screen (Figure 34).
3. Type **V** or highlight Event Summary Statistics.
4. Press **<Enter>** to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.
5. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

6. Press **<Enter>** once you supply an output destination. A report similar to Figure 41 will be generated.

Application Detail Report

Application EDG_FS_DEMO

Common Cause Component Group 6 Average event CCCG size 2.83
 Adjusted Independent events 1643.10 Total events in application 55
 Unadjusted independent events 775.00

Included in Total	Sys	Cmp	FM	Source	Totals
	EPS	EDG	FR		-----
	EPS	EDG	FR	LER	587.00
	EPS	EDG	FR	NPRDS	2.00
*	EPS	EDG	FS		-----
*	EPS	EDG	FS	LER	764.00
*	EPS	EDG	FS	NPRDS	11.00
	EPS	EDG	FX	LER	23.00

Alpha Model

N1	7.7671	N5	8.1359	α1	0.9672358	α5	4.76E-003
N2	12.1000	N6	13.2831	α2	7.08E-003	α6	7.78E-003
N3	13.7509	N7	-----	α3	8.05E-003	α7	-----E----
N4	8.6516	N8	-----	α4	5.06E-003	α8	-----E----

Events:

L-029-91-0591-FS, L-029-91-0603-FS, L-247-86-0688-FS, L-247-91-0689-FS,
 L-249-94-2373-FS, L-255-81-0596-FS, L-255-94-2374-FS, L-259-81-0691-FS,
 L-259-82-0692-FS, L-259-86-0597-FS, L-261-93-0598-FS, L-271-84-0600-FS,
 L-277-95-2376-FS, L-280-91-0694-FS, L-286-87-1237-FS, L-286-90-0693-FS,
 L-286-92-0702-FS, L-295-94-2588-FS, L-296-88-1172-FS, L-304-94-2378-FS,
 L-317-80-0619-FS, L-320-80-0627-FS, L-325-82-0699-FS, L-325-82-0700-FS,
 L-327-80-0622-FS, L-327-80-0623-FS, L-327-80-0624-FS, L-327-82-0701-FS,
 L-339-87-0638-FS, L-348-80-0703-FS, L-348-81-0705-FS, L-348-81-0706-FS,
 L-364-81-0707-FS, L-366-83-0708-FS, L-369-90-0645-FS, L-387-82-0710-FS,
 L-387-85-0647-FS, L-388-84-0651-FS, L-395-85-0652-FS, L-412-93-0654-FS,
 L-416-82-0711-FS, L-424-90-0735-FS, L-425-90-0734-FS, L-425-91-0659-FS,
 L-440-87-0660-FS, L-456-90-0736-FS, L-457-90-0747-FS, L-461-92-0725-FS,
 L-461-93-0726-FS, L-499-91-0728-FS, L-528-85-0685-FS, L-528-87-0533-FS,
 L-529-87-0540-FS, L-530-87-0731-FS, N-313-84-1240-FS

1997/06/14

02:12:35

page 1

Figure 40. Generic—Example of Mapped Detailed Event report.

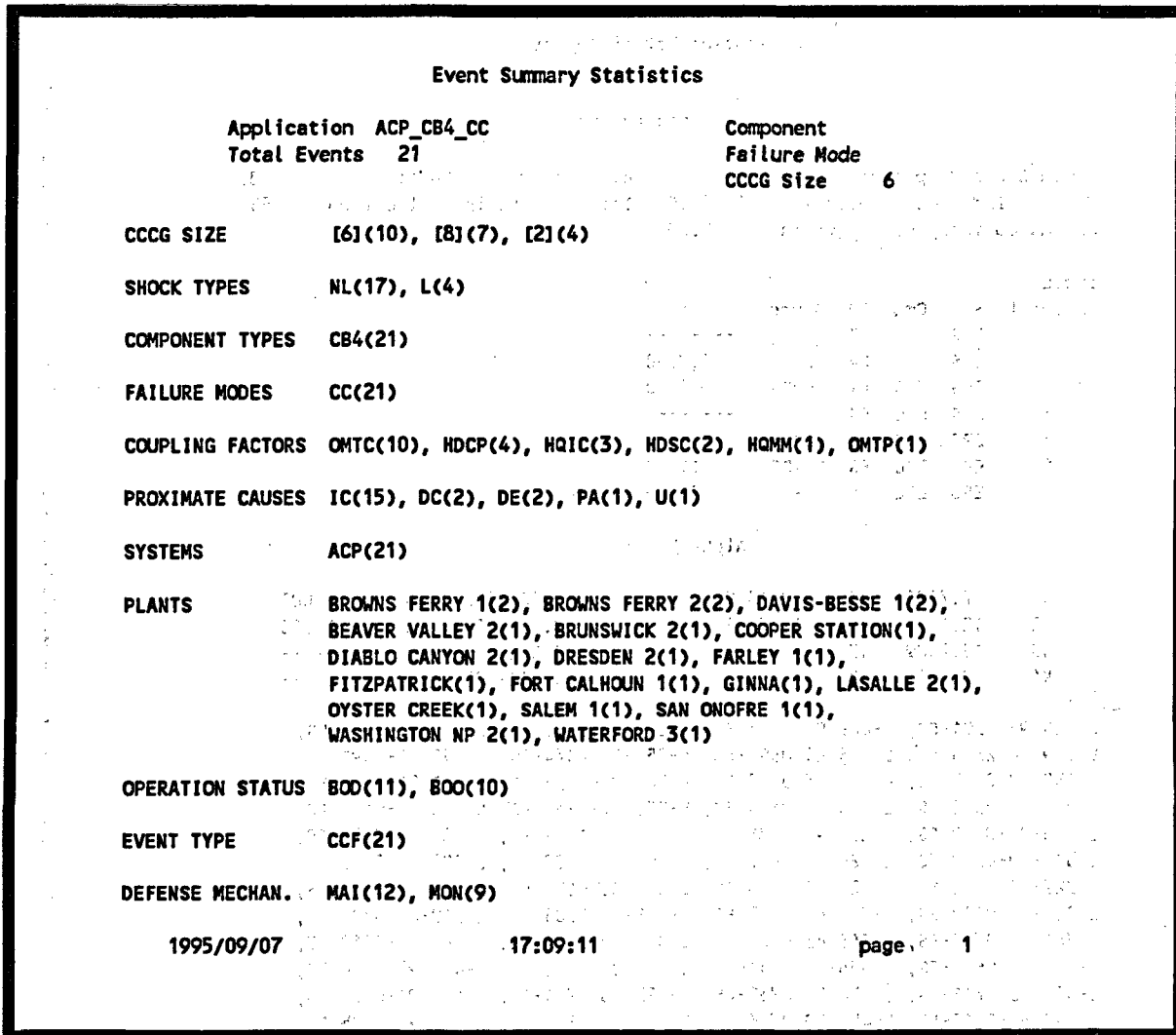


Figure 41. Generic—Example of Mapped Event Summary Statistics report.

3.5.7 Application Event Report (Generic Mapped)

1. Type **Y** to perform mapped calculations.
2. Press **<F7>** to access the Search Reports screen (Figure 34).
3. Type **A** or highlight Application Report.
4. Press **<Enter>** to access the Report Options screen (Figure 35). CCF provides a default report title and output file name; however, you may change the defaults by simply typing over the existing text.
5. Specify an output destination. As a default, the screen will display the report (CON). You may change this to one of the following:

PRN Prints the report on the attached printer.

" " If the file name is left blank, no report will be generated.

<Esc> No report will be generated.

other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

6. Press **<Enter>** once you supply an output destination. A report similar to Figure 11 will be generated. The report will contain the application events instead of the search events in Figure 11, but the information for each event is the same.

1. Introduction

The purpose of this study is to investigate the effects of various factors on the growth and development of the human body. The study is based on a series of experiments conducted over a period of several years. The results of these experiments are presented in the following sections.

The first section of the study deals with the effects of nutrition on growth. It is shown that a diet rich in protein and vitamins is essential for normal growth. The second section discusses the effects of exercise on growth. It is found that regular exercise promotes growth and development. The third section examines the effects of stress on growth. It is concluded that stress can have a negative impact on growth.

The fourth section of the study deals with the effects of hormones on growth. It is shown that growth hormone plays a crucial role in the development of the human body. The fifth section discusses the effects of environmental factors on growth. It is found that factors such as temperature and humidity can influence growth.

In conclusion, the study has shown that growth and development are influenced by a variety of factors. A balanced diet, regular exercise, and a stress-free environment are all essential for normal growth. Further research is needed to better understand the complex interactions between these factors.

4. SPECIFIC

SPECIFIC edits applications and events, analyzes the events of an application, and summarizes the values of applications statistically. The Edit function allows you to modify, insert, and delete data contained in an application. The Event function allows you to delete, view comments, or analyze existing events of an application and to calculate "what-if" type situations. SPECIFIC provides mapped calculations and results from adjusted as well as unadjusted independent events. The Application Summary function summarizes CCF statistics using various modeling techniques for point estimations, selecting a staggered testing scheme, and creating reports. To run the SPECIFIC option, type P in the Option field of the main menu or use the up and down arrow keys to highlight SPECIFIC. Press <Enter> to access the Applications screen (Figure 42). SPECIFIC provides the following functions:

Applications

ACP_4KV_BKR_U_CC	4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96
ACP_4KV_BKR_U_CK	4160 VAC CIRCUIT BRKRS, SPURIOUS OPEN, 94/95 UPDATE, 11-4-96
AFW_AOV_UPD_VC	AUX FEEDWATER AOVS, FAIL TO CLOSE, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VO	AUX FEED AOVS, FAIL TO OPEN, 94/95 UPDATE, 11-25-96
AFW_AOV_UPD_VR	AUX FEED AOVS, FAIL TO REMAIN CLOSED, 94/95 UPDATE, 11-25-96
AFW_CKV_UPD_VC	PWR AUX FEED CHK VLVS, FAIL TO CLOSE, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VO	PWR AUX FEED CHK VLVS, FAIL TO OPEN, 94/95 UPD, 11-23-96
AFW_CKV_UPD_VR	AUX FEED CHK VLV, FAIL TO REMAIN CLOSED, 94/95 UPD, 11-23-96

Name ACP_4KV_BKR_U_CC
 Description 4160 VAC CIRCUIT BRKRS, FAIL TO CLOSE, 94/95 UPDATE, 11-4-96

CCCG Size	6	Component Type	Failure Mode
-----------	---	----------------	--------------

<Esc>	<F3>	<F4>	<F5>	<Enter>
Exit	Edit	Events	Copy	Appl. Summary

Figure 42. Specific—Application list for the Specific option.

- <Esc> Exit—Terminates Applications screen and returns to the main menu.
- <F3> Edit—Edits the application (see Section 3.1).
- <F4> Events—Removes events from a list, views event comments, analyzes an event, and performs summary statistics for an application (see Section 4.1).
- <F5> Copy—Copies an application to a new application. (see Section 3.3)

<Enter> Application Summary—Directly performs summary statistics for an application (see Section 4.2).

4.1 Event Analysis

The Events function deletes an event, views comments of an event, or analyzes an event within an application. To select the Events function, highlight the desired application and press <F4> to access the Event Analysis screen (Figure 43).

Event Analysis		Application ACP_4KV_BKR_U_CC	
L-219-86-1158-CC 4160V BREAKERS WITH POTENTIAL RESTART FAILURE. L-244-87-1161-CC 4160V BREAKERS FAIL TO CLOSE. L-259-80-1163-CC ALTERNATE BKRS FAIL TO CLOSE AND NORMAL BKRS FAIL TO RECLOSE. L-277-88-1234-CC 4160V BREAKER CLOSURE CIRCUITRY DISABLED. L-286-84-1094-CC 4160V BREAKERS FAIL TO OPERATE DURING LOSS OF OFFSITE POWER. L-309-94-2427-CC SEVERAL 4KV BREAKERS WOULD NOT CLOSE L-309-95-2428-CC CRACKED INTERNAL CAM FOLLOWERS IN AC BREAKERS L-324-82-1183-CC STARTUP XFMR BREAKER & #3 DIESEL BREAKER FAILED TO CLOSE			
Name	L-219-86-1158-CC	Src LER	Plant OYSTER CREEK
Title	4160V BREAKERS WITH POTENTIAL RESTART FAILURE.		Power---%
			P1 0.10
			P2 0.10
System	ACP	Proxim Cause DE	CCCG Size 6
Component	CB4	Shock Type L	Op-Det BO Mode D
Fail Mode	OO	Coupl Factor HDCP	Shared Cause Fc1.00
Plnt Type	B	Date 1986/12/06	Event Type CCF
		Mult Units? N	Event Level SYS
		Defense Mech MON	P3 0.10
			P4 0.01
			P5 0.01
			P6 0.01
			P7 ----
			P8 ----
<Esc>		<F4>	<F5>
Exit	Delete	Comments	Narrative
			Imp.Vector
			Appl. Summary
			+-----+

Figure 43. Specific—Event Analysis screen.

The top window lists all events contained in the application selected. The bottom window contains the information associated with the highlighted event. See Reference 1 of this report for more details about the following fields.

Name—Provides the event code number assigned to the event by the data coder.

Plant—Identifies the name of the nuclear power plant where the CCF event occurred.

Power—States the percentage of full power at the time of the CCF event.

Title—Gives a short description of the event.

System—Names the system that includes the failed component.

Component—Identifies the name of the component that experienced the CCF event.

Fail Mode—Defines the failure in terms of which function the components did not perform.

Plant Type—Define the type of plant where the CCF event occurred P-Pressurized Water Reactor and B-Boiling Water Reactor.

Proximate Cause—Characterizes the condition that is readily identified as leading to failure (a symptom) of a component or function.

Shock Type—Relates the relationship of one component failure to another. That is, the shock type classifies the event as lethal (L) or nonlethal shock (NL) to the system.

Coupling Factor—Describes the mechanism that ties the multiple failures together.

Date—Date of the event.

CCCG Level—Indicates the system size or number of redundant components that can be exposed to a CCF event.

Timing Factor—This is a measure of how close in time multiple failures occurred as represented by "q." This value ranges from 0.00 to 1.00.

Shared Cause Factor—Ties two failures together. This value ranges from 0.00 to 1.00, representing the analyst's assessment of the degree of presence of a factor or factors causing the propagation of the failure to more than one component. This factor provides the flexibility to classify events for which detailed information is not furnished to determine the presence of coupling factors. A value of 1 indicates that the analyst believes the failures in the event were coupled. Values less than one represent more uncertainty about the dependency of the failures.

Multiple Units—States if the event affected more than one unit at a site.

Operational Status-Detected—Shows when the event was detected.

Operational Status-Mode—Shows when the event occurred.

Event Type—Establishes which events are used in Probabilistic Risk Assessment (PRA) CCF parameter estimations.

Event Level—Establishes whether the failure affected just the component or the system.

Defense Mechanism—Describes the defenses that you can apply to the coupling factor to prevent the CCF event from occurring.

Component Degradation (P1-P8)—There are eight component degradation values. This value ranges from 0.00 to 1.00 and indicates the extent that the degraded component failed (see Reference 1).

Event Analysis provides the following functions:

- <Esc>** Exit—Terminates the Event Analysis screen and returns to the Applications screen.
- ** Delete—Removes an event from the selected application. To delete an event, highlight the event and press ****. A prompt will ask if this event is to be removed from the application. Enter Y or N and press **<Enter>**. If Y is entered, CCF removes the event from the list immediately.
- <F4>** Comments—Views comments associated with the event. You cannot edit these comments.
- <F5>** Narratives—Views narratives associated with the event. You cannot edit these narratives.
- <Enter>** Impact Vector—Performs an event analysis (see Section 3.2.1).
- <F8>** Application Summary—Summarizes the CCF statistics summary (see Section 3.4).

4.1.1 SPECIFIC Event Impact Vector Analysis

To access the Application Specific Event Analysis screen (Figure 44), highlight the desired application and press **<Enter>**. The description window displays the first event (or the event highlighted) and its associated information. You can change the default values for the following fields: Cause, Shock Type, Component Degradation Level, Coupling, Map Up Factor, Event Type, Fail Mode, Timing Factor, Shared Cause Factor, Average Impact Vector, and Application Specific Impact. CCF uses these values to calculate the average impact vectors and the application specific impact vectors (shown in the bottom portion of the screen). Also, you can directly input the average impact vector, bypassing the CCF calculation altogether. A brief description of the Map Up Factor, Component Degradation Level, Average Impact Vector, and Application Specific Impact fields follows.

Map Up Factor—Reflects whether the target system size is larger, equal, or smaller than the original system (see Reference 2).

Component Degradation—You can supply up to four component degradation values. This Level (Value) value ranges from 0.00 to 1.00 and indicates to what extent a degraded component failed (see Reference 1).

Average Impact Vector—The calculation results (based on algorithms built in CCF) that define the average impact vector. You may input your own numbers, if desired, instead of using the CCF results (see Reference 2).

Application Specific—The calculation results (based on algorithms built in CCF) that adjust the Impact original impact vector by accounting for qualitative and quantitative differences between the original and target systems (see Reference 2).

Application ACP_4KV_BKR_U_CC	Application Specific Event Analysis	1 of 21
---------------------------------	-------------------------------------	---------

Event Code L-219-86-1158-CC
Title 4160V BREAKERS WITH POTENTIAL RESTART FAILURE.

Applicability Factors	Component Degradation Level
Cause 1.00	P1 0.10 P2 0.10 P3 0.10 P4 0.01 P5 0.01 P6 0.01 P7 ---- P8 ----
Coupling 1.00	Timing Factor 1.00
Map Up Factor 1.00	Shared Cause Factor 1.00
Failure Mode 1.00	Event CCG Size 6
	Appl. CCG Size 6
	Event Type CCF

***** Application Specific Impact Vector *****

N/A	F1	F2	F3	F4	F5	F6	F7	F8
----	----	----	----	----	----	----	----	----

<Esc> <Enter> <F1> <F2> <F3> <F4> <F5> <F6> <F7> <F8>
Exit Calculate Help List View Event Comments Narr. Previous Next Save

Figure 44. Specific—Application Specific Event Analysis screen.

NOTE: Use <Tab> to move from field to field on the screen.

Application Specific Event Analysis provides the following functions:

- <Esc> Exit—Terminates the SPECIFIC Event Analysis screen and returns to the Event Analysis screen.
- <Enter> Calculate—Calculates the impact vector based on the information provided. However, you may want to use specific values for the average impact vector. CCF allows you to edit this field.
- <F2> List—Provides an L or NL selection for the Shock Type field. To select an L or NL, press <F2>, highlight your selection, and press <Enter>. Exit the list by pressing <Esc>.
- <F3> View Event—Views event information, including the component degradation values. You can also view the comments associated with this event by pressing <F4> in the View Event screen.
- <F4> Comments—Edits comments associated with the event analysis.
- <F5> Narrative—Edits narrative associated with the event analysis.
- <F6> Previous—Displays the previous event. This allows you to scroll back through the events in an application one record at a time.

- <F7> Next—Displays the next event. This allows you to scroll forward through the events in an application one record at a time.
- <F8> Save—Saves the current screen selections and values as the default values for the next time you summarize the statistics of the application. The message "Record saved" will appear at the bottom of the screen to verify this operation. The next event will then be displayed.

4.2 Application Summary

Application Summary calculates summary statistics for an application based, in part, on the impact vectors of the events belonging to that application. In addition, Calculate lets you perform these calculations based solely upon their input numbers, rather than using an application event list. To run Applications Summary, highlight the application you want and press <F8>. The CCF Summary Statistics screen (Figure 45) allows you to stagger the testing scheme in the calculations. You may also look at point estimates of events using the Alpha-Factor Model Distribution, Multiple Greek Letter Distributions, or look at the Bayesian Distribution for the Alpha-Factor Model.

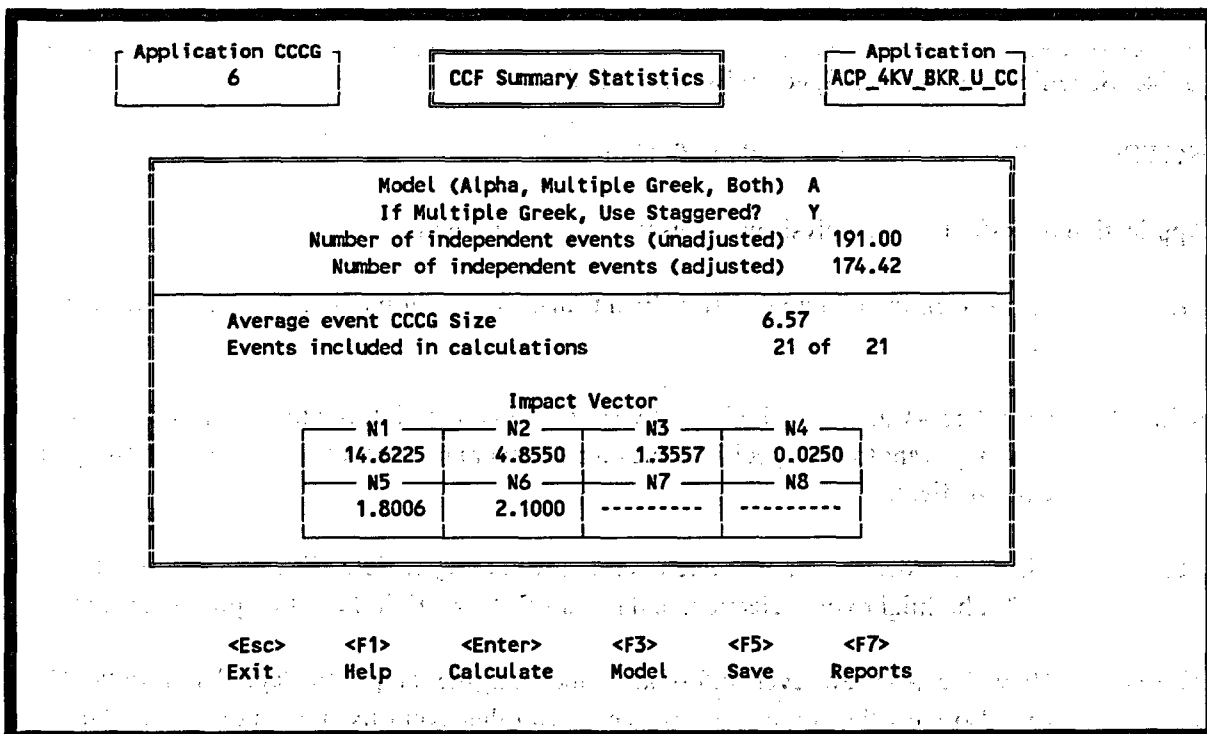


Figure 45. Specific—CCF Summary Statistics screen.

CCF Summary Statistics provides the following functions:

- <Esc> Exit—Terminates the CCF Summary Statistics screen, and then displays the Save/Cancel window if you performed any application summaries; otherwise, <Esc> returns to the Applications screen.

<F2> Independent Event Totals—Breaks down the number of independent events. This function is available when you place your cursor in the Number or Independent Events field. Press **<F2>** to access the Independent Event Totals screen (Figure 46).

NOTE: The **<F2>** key is enabled for the Number of Independent Events field only.

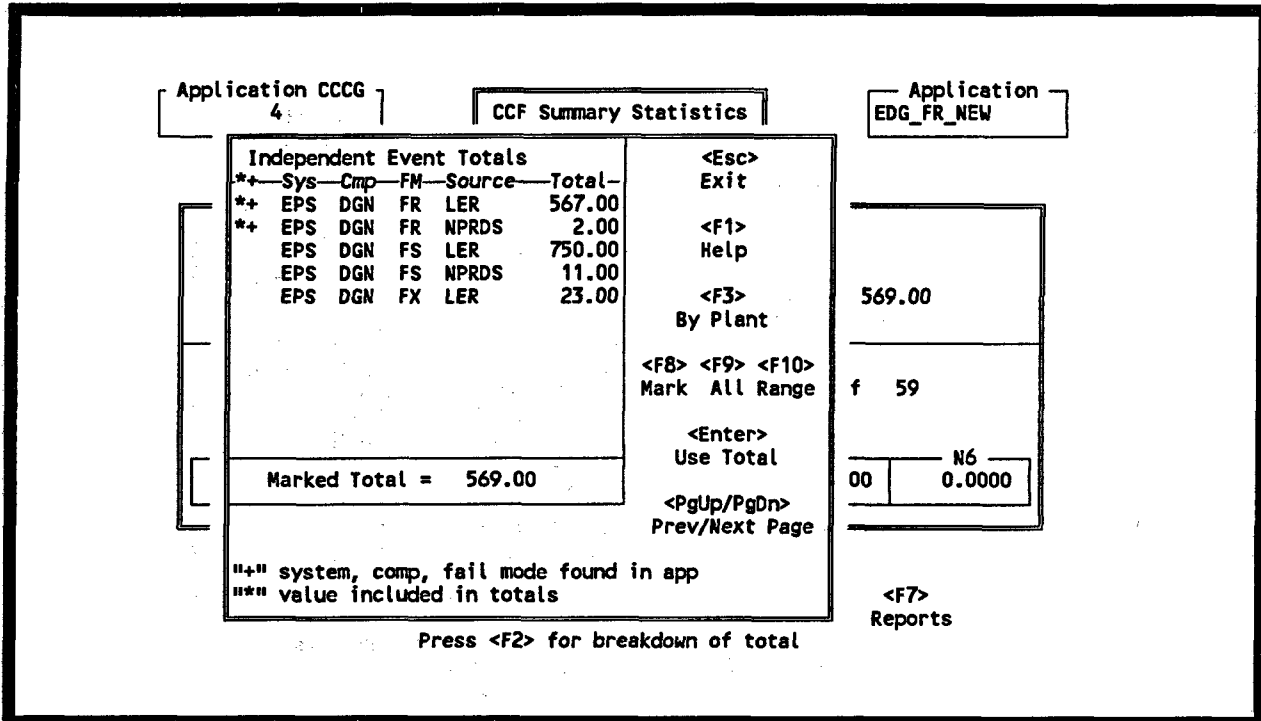


Figure 46. Specific—Breakdown of independent event total.

- <Enter>** Calculate—Recalculates the impact vectors and the point estimations of the models if you change your mapped and/or staggered selections for the application.
- <F3>** Model—Displays the point estimations for both models and the Bayesian Uncertainty Distribution for the Alpha-Factor Model (see Sections 4.2.1 and 4.2.2).
- <F5>** Save—Saves the current screen selections and values as the default values for the next time you summarize the statistics of the application. The message "Record saved" will appear at the bottom of the screen to verify this operation.
- <F7>** Report—Generates a special quantification report or an application report (see Section 4.3).

You can also alter the values included in the marked total value by adding or deleting independent events with the **<F8>**, **<F9>**, and **<F10>** keys (see Section 1.4).

- <Esc>** Exit—Terminates the Independent Event Totals screen without changing the number of independent events field used in the calculation.

- <Enter> Use Total—Terminates the Independent Event Totals screen and changes the number of independent event field used in the calculation to the marked total shown on this screen.
- <F3> By Plant—Breaks down the number of independent events for the highlighted entry by the plants which contributed to the total (Figure 47).

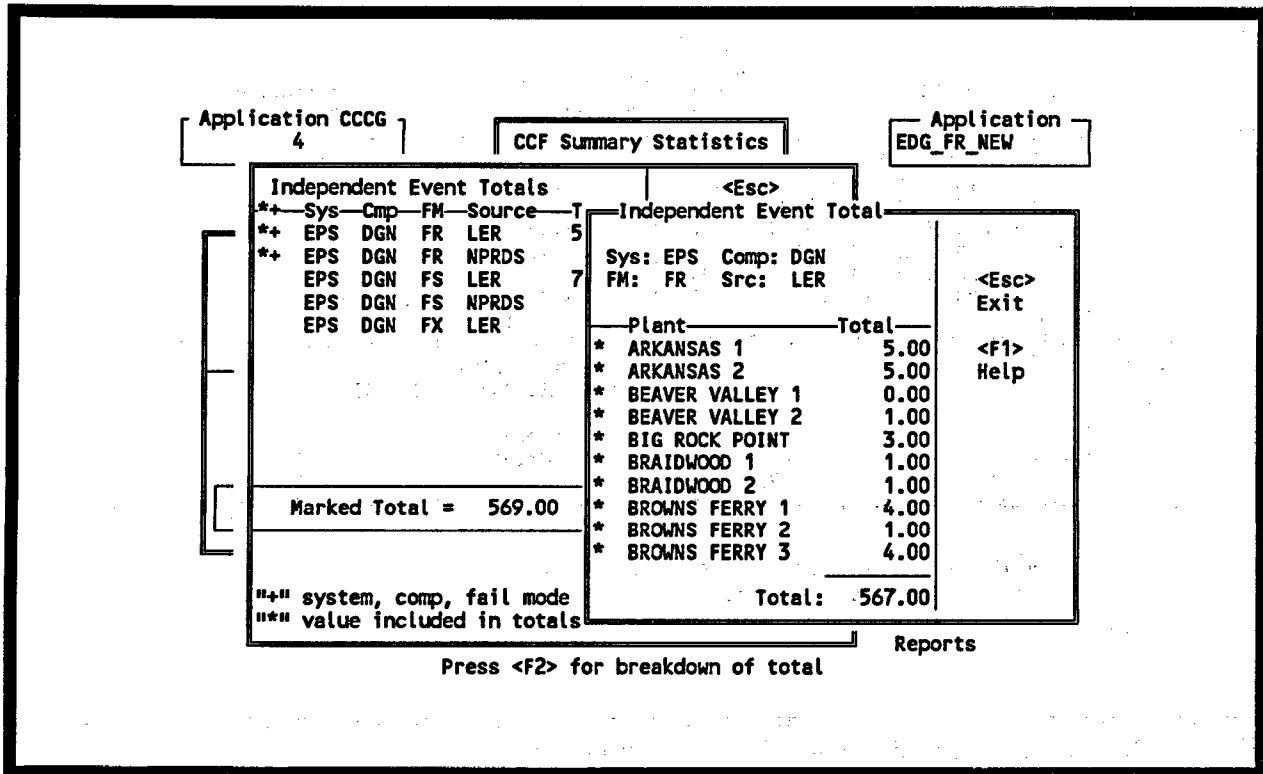


Figure 47. Specific—Breakdown of independent event totals by plant.

4.2.1 Alpha-Factor Model

The Alpha-Factor Model displays Bayesian Distributions, point estimates, and uncertainty summary information for the model. To initiate this model, type an A in the Model field. Press <F3> to access the Select Display Type (Figure 48). Use the up and down arrow keys to highlight the appropriate uncertainty calculation method or type the highlighted letter into the Option field. Press <Enter> to access either the Point Estimate screen (Figure 49), the Nonhomogeneous Bayesian Plant to Plant Distribution menu (see Section 4.2.1.2), the Homogeneous Bayesian screen (see Section 4.2.1.3), or the Uncertainty Summary screen (see Section 4.2.1.4).

4.2.1.1 Point Estimate. The Alpha-Factor Model Point Estimate screen provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Alpha-Factor model menu.

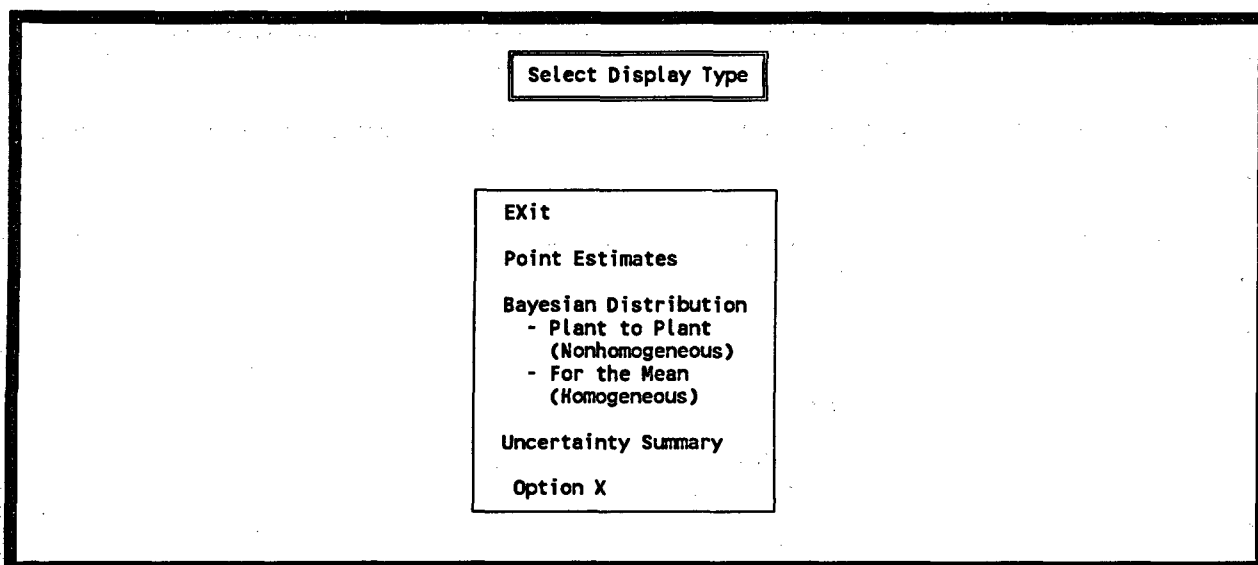


Figure 48. Specific—Alpha-Factor Model menu.

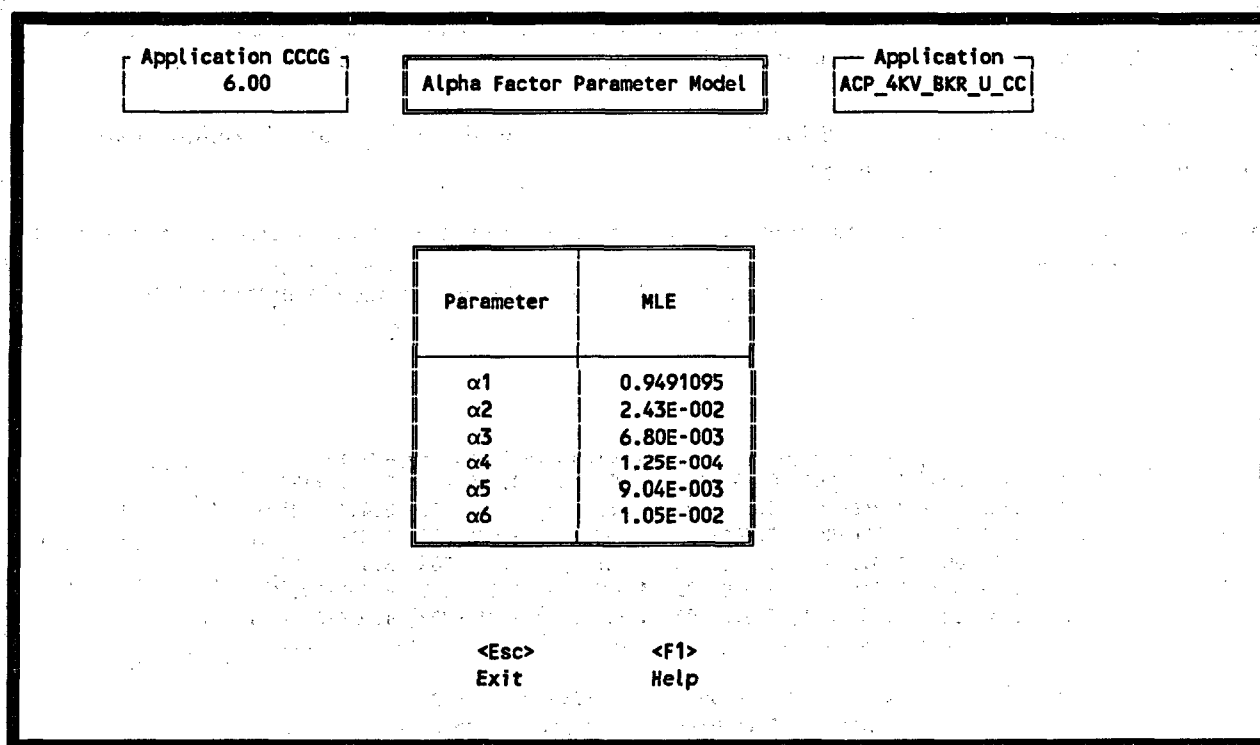


Figure 49. Specific—Alpha-Factor Model Point Estimate screen.

4.2.1.2 Nonhomogeneous Bayesian Distributions or Plant to Plant Distributions. The Nonhomogeneous Bayesian Model Selection Menu is shown in Figure 50. Use the up and down arrow keys to highlight the appropriate model calculation method or type the highlighted letter into the Option field. Press <Enter> to access either the Constrained Noninformative Prior Method (see Section 3.4.1.2.1) or the

Hierarchical Bayesian Method (see Section 3.4.1.2.2). Press <Esc> to return to the Alpha-Factor Model menu.

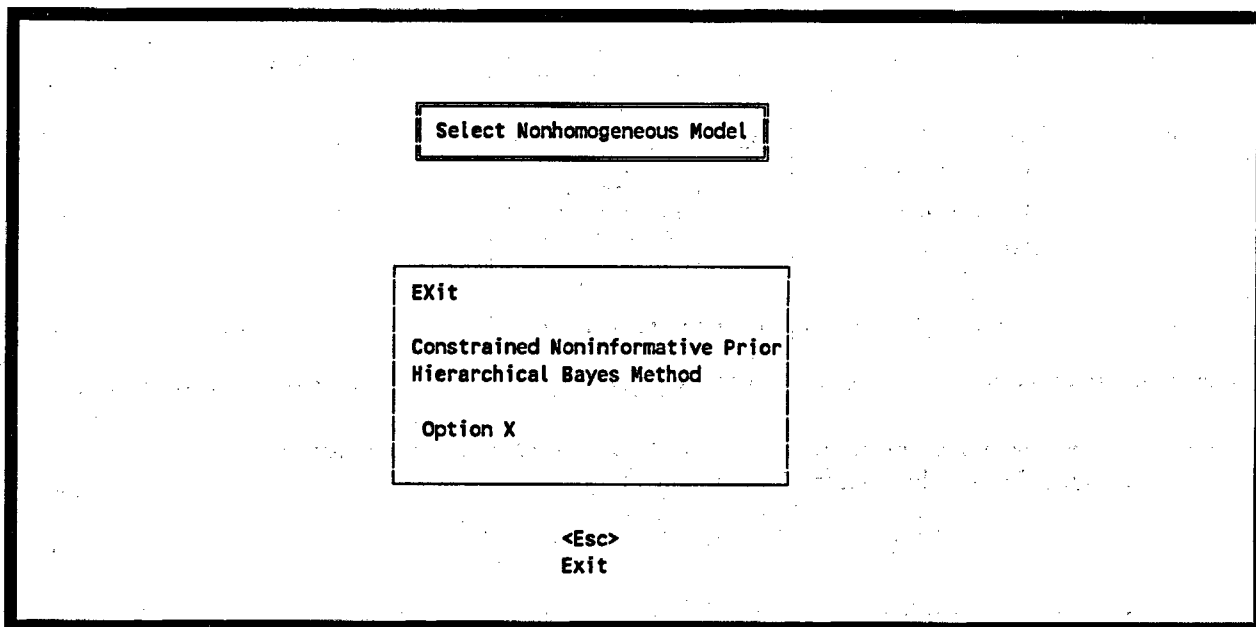


Figure 50. Specific—Nonhomogeneous Model menu.

4.2.1.2.1 Constrained Noninformative Prior—The results of Constrained Noninformative Prior calculations are displayed in Figure 51.

	a	b	5th%	Median	95th%	Mean
α1	7.74E+000	4.15E-001	0.7958122	0.9791301	0.9999279	0.9490712
α2	4.60E-001	1.84E+001	6.30E-005	1.06E-002	9.55E-002	2.44E-002
α3	4.90E-001	7.25E+001	2.39E-005	3.02E-003	2.58E-002	6.71E-003
α4	5.00E-001	1.39E+003	1.42E-006	1.63E-004	1.37E-003	3.59E-004
α5	4.86E-001	5.44E+001	3.04E-005	3.97E-003	3.42E-002	8.86E-003
α6	4.83E-001	4.55E+001	3.50E-005	4.70E-003	4.06E-002	1.05E-002

<Esc> Exit <F3> Full Distr. <F5> Graphs <F7> Reports

Figure 51. Specific—Constrained Noninformative Prior Results.

The Constrained Noninformative Prior Results provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Nonhomogeneous Model menu.
- <F3> Full Distribution—Displays the full distribution for each applicable alpha. (Figure 52).
- <F5> Graphs—Plots the probability density or cumulative distribution. To initiate this function, press <F5>, enter the plot type either cumulative or density and press <Enter>. Next enter the alpha parameter to plot (from 1 to CCCG number), and then press <Enter> to plot the distributions.
- <F7> Reports—Prints an Estimation Report of the Constrained Noninformative Prior Results.

q	A*1 1.91E+001	A*2 5.95E+000	A*3 4.70E+000
0.005	4.08E-001	5.60E-002	3.47E-002
0.010	4.31E-001	6.49E-002	4.14E-002
0.025	4.65E-001	7.95E-002	5.28E-002
0.050	4.94E-001	9.37E-002	6.42E-002
0.100	5.28E-001	1.12E-001	7.94E-002
0.200	5.68E-001	1.37E-001	1.00E-001
0.250	5.84E-001	1.47E-001	1.09E-001
0.300	5.98E-001	1.57E-001	1.18E-001
0.400	6.22E-001	1.75E-001	1.34E-001
0.500	6.45E-001	1.93E-001	1.50E-001
0.600	6.67E-001	2.12E-001	1.67E-001
0.700	6.90E-001	2.33E-001	1.86E-001
0.750	7.03E-001	2.45E-001	1.98E-001
0.800	7.16E-001	2.59E-001	2.11E-001
0.900	7.51E-001	2.96E-001	2.46E-001
0.950	7.78E-001	3.29E-001	2.78E-001
0.975	8.01E-001	3.58E-001	3.06E-001
0.990	8.25E-001	3.92E-001	3.40E-001
0.995	8.40E-001	4.16E-001	3.63E-001

<Esc>
Exit

Figure 52. Specific—Full distribution of the Alpha-Factor model.

4.2.1.2.2 Hierarchical Bayesian Method—The results of Hierarchical Bayesian menu is displayed in Figure 53.

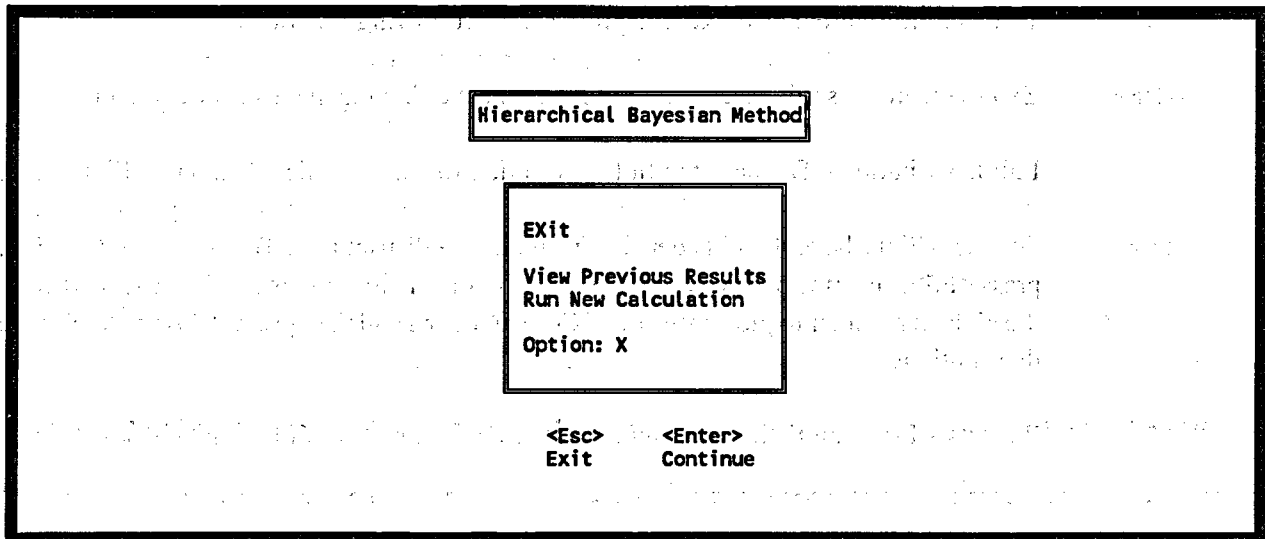


Figure 53. Specific—Hierarchical Bayesian Method menu.

Use the up and down arrow keys to highlight the appropriate selection or type the highlighted letter into the Option field. Press <Enter> to either View Previous Results (see Section 4.2.1.2.2.1) or Run New Calculation (see Section 4.2.1.2.2.2). Press <Esc> to return to the Nonhomogeneous Model menu.

4.2.1.2.2.1 Hierarchical Bayesian Method—View Previous Results—The results of the last Hierarchical Bayesian calculation saved will be displayed in Figure 54.

The Hierarchical Bayesian Method results screen provides the following functions.

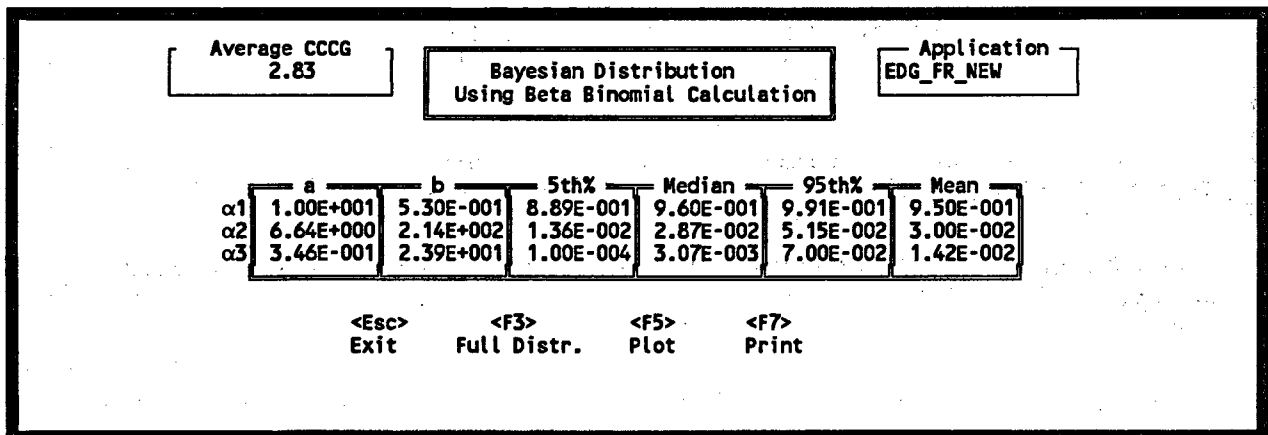


Figure 54. Specific—Hierarchical Bayesian Method results.

- <Esc> Exit—Terminates this screen and returns to the Hierarchical Bayesian menu screen.
- <F3> Full Distribution—Displays the full posterior distribution for each applicable alpha (Figure 52).

- <F5> Plot Distribution—Plots the probability density or cumulative distribution. To initiate this function, press <F5>, enter the plot type either cumulative or density and press <Enter>. Next enter the alpha parameter to plot (from 1 to CCCG number), and then press <Enter> to plot the distributions.
- <F7> Print Model—Prints an Estimation Report of the Hierarchical Bayesian Method Distribution. See Sections 3.5.1 and 3.5.5 for more details.

4.2.1.2.2 Hierarchical Bayesian Method—Run New Calculations—An introduction screen (Figure 55) provides information about the Hierarchical Bayesian calculation.

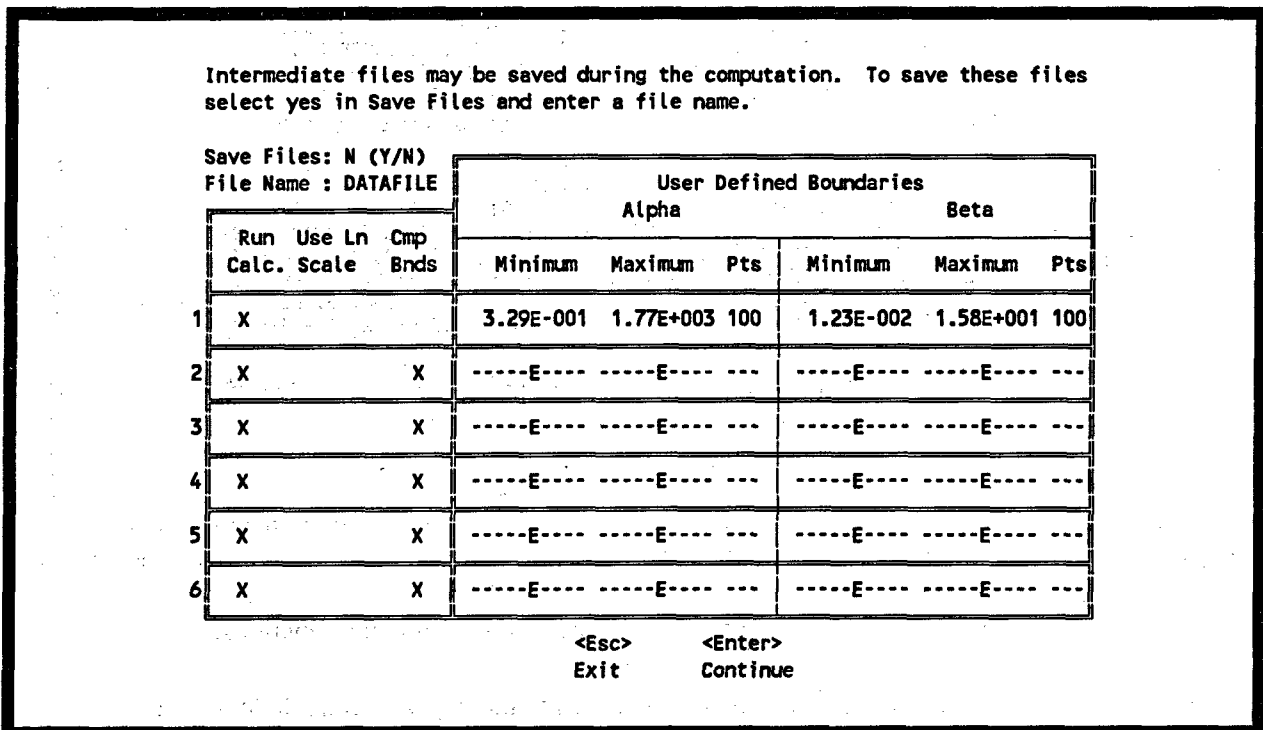


Figure 55. Specific—Hierarchical Bayesian Method—Run new calculation initial screen.

To create intermediate files, enter Y, and enter a name for the file(s). The Hierarchical Bayesian method may be run for an individual alpha, several alpha values, or for all of the alpha values. To run the calculation for an alpha place an X in the Run Calculation Column. If you wish to have the computer generate the boundaries, place an X in the Computer Ends column. If you wish to use the Log Normal Scale, place an X in the Use Ln Scale Column.

<Esc> Exit—Terminates this screen and returns to the Hierarchical Bayesian menu screen.

<Enter> Continue—Continues with the Hierarchical Bayesian Calculation.

Calculation progress updates will be displayed at the bottom of the screen throughout the calculation. To terminate the calculation at anytime, press <Esc>. A message will appear asking you to confirm the termination of the calculation, press Y to terminate, N to cancel the terminate and continue the calculation.

Once the calculation has completed the Hierarchical Bayesian Method Results screen (Figure 54) will be displayed.

4.2.1.3 Homogeneous Bayesian Distributions. The results of Homogeneous Bayesian calculations are displayed in Figure 56.

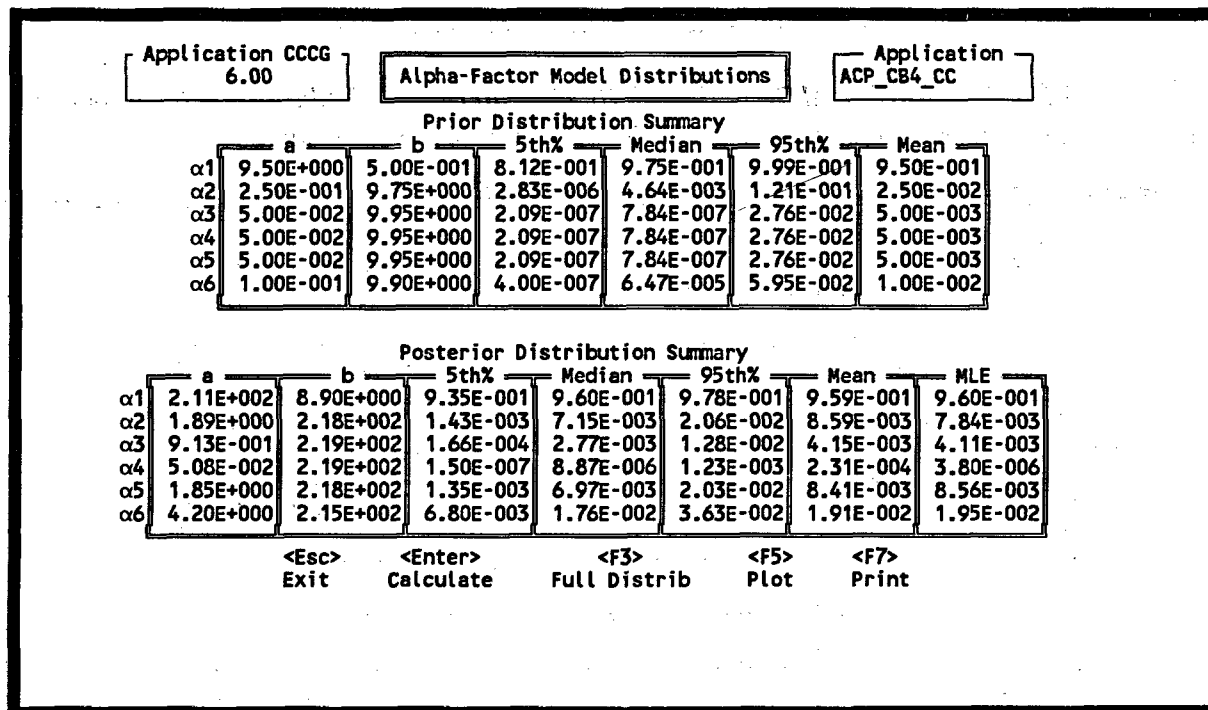


Figure 56. Specific—Homogeneous Bayesian Distribution.

The Homogeneous Bayesian Distribution screen provides the following functions:

- <Esc> Exit—Terminates this screen and returns to the Alpha Factor Model menu.
- <Enter> Calculate—Allows you to enter distribution parameters from A1 to CCCG size and then calculates the prior and posterior distribution summaries.

NOTE: The Program calculates the distributions using the set of input values in column "a". Default values in column "a" are provided, based on the CCCG size. You can input your own "a" values and recalculate the distributions. Save the application to retain the new values; otherwise, exit from the option, and the program will default back to the original values suggested in column "a". Note that any time you change the CCCG size for the application, the program will default to the suggested values in column "a" for the new CCCG size.

- <F3> Full Distribution—Displays the full posterior distribution for each applicable alpha (Figure 52).

- <F5> Plot Distribution—Plots the probability density for the prior and posterior distributions. To initiate this function, press <F5>, enter the alpha parameter to plot (from 1 to 6), and then press <Enter> to plot the distributions.
- <F7> Print Model—Prints an Estimation Report of the Bayesian Distribution. See Sections 3.5.1 and 3.5.5 for more details.

4.2.1.4 Bayesian Uncertainty Summary. The results of Bayesian Uncertainty calculations are displayed in Figure 57.

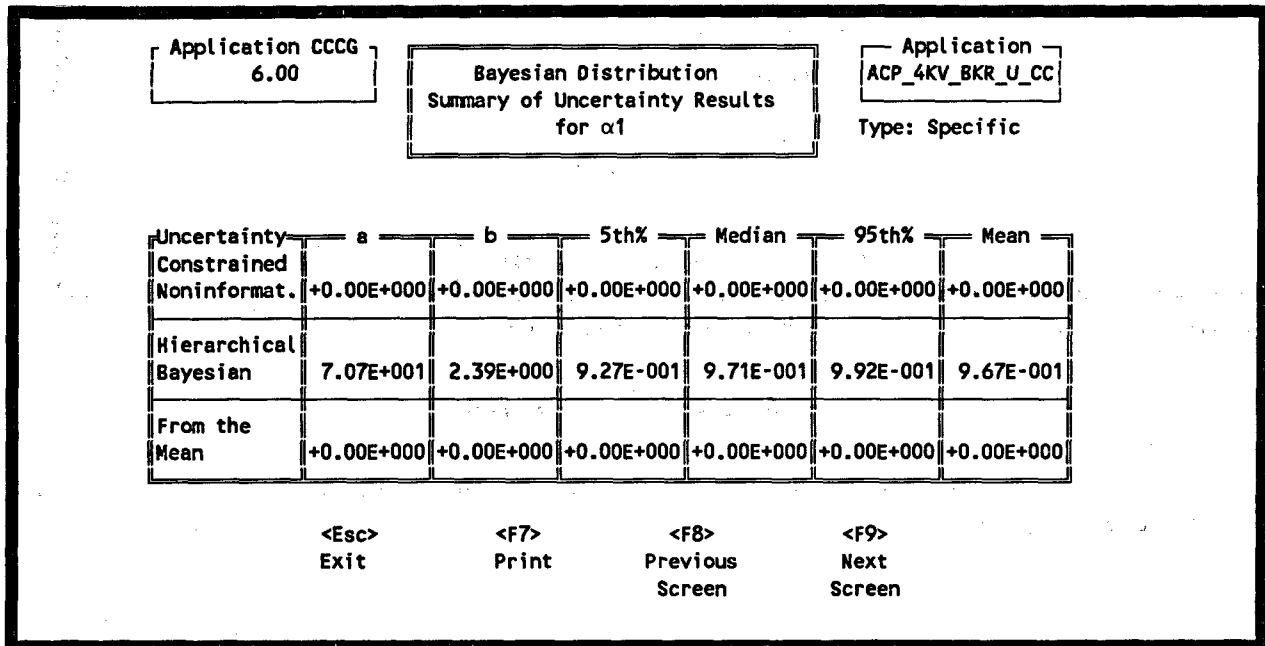


Figure 57. Specific—Bayesian Uncertainty Summary.

The Bayesian Uncertainty Summary screen (Figure 57) provides the following functions.

- <Esc> Exit—Terminates this screen and returns to the Alpha Factor Model menu.
- <F7> Print Model—Prints an Uncertainty Summary Report of the Bayesian Distributions. See Sections 3.5.1 and 3.5.5 for more details.
- <F8> Previous Screen—Displays the previous alpha comparison screen.
- <F9> Next Screen—Displays the next alpha comparison screen.

4.2.2 Multiple Greek Letter Model

To initiate the Multiple Greek Letter models (Figure 58), type an M in the Model field (Figure 45).

Multiple Greek Factor Parametric Model	
Application CCCG 4	
Parameter	MLE
Beta	5.85E-002
Gamma	5.54E-001

<Esc> Exit <Enter> Summary <F1> Help

Figure 58. Specific—Multiple Greek Factor Parametric Model.

4.3 Search Reports

Press <F7> to access the Search Reports options. See Sections 3.5.3 through 3.5.6 for more details about these report options.

5. REPORT

REPORT generates report outputs based on: applications, independent events (IE) totals, events, event text, etc. To generate a report, type R or use the up and down arrow keys to highlight REPORTS. Press <Enter> to access the Reports main menu (Figure 59).

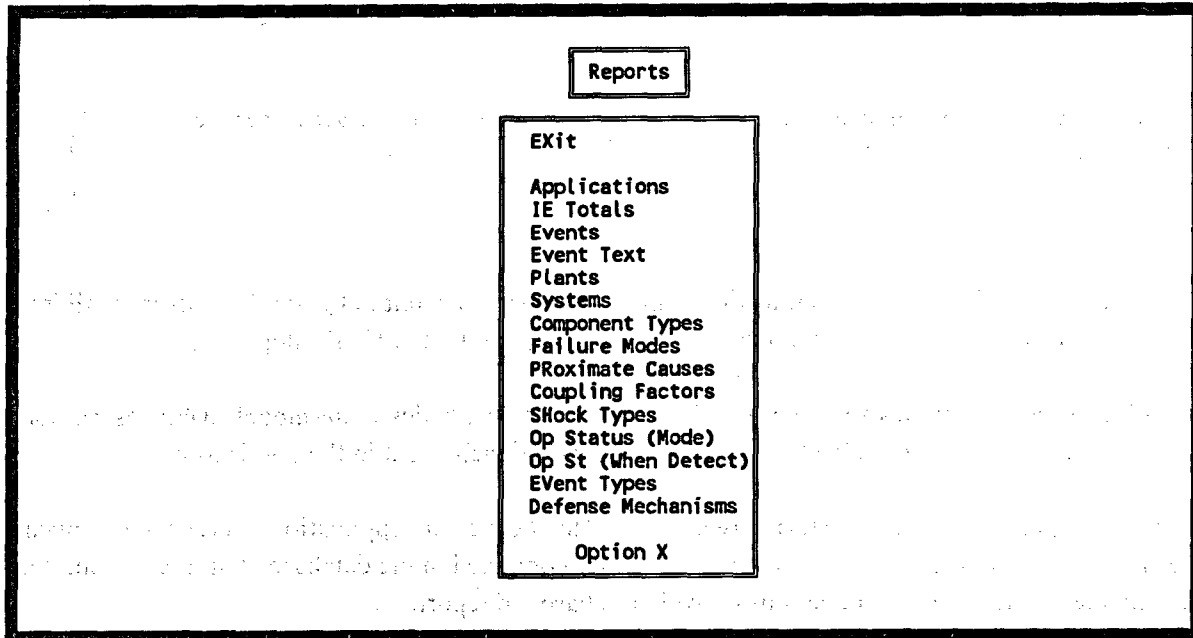


Figure 59. Reports main menu.

5.1 Applications

Applications generates a report based on selected applications. To select applications, Type A or use the up and down arrow keys to highlight Applications. Press <Enter> to access the Application Reports screen (Figure 60).

Choose either a generic or specific report and press <Enter> to access the Application Reports options screen (Figure 61). The following reports are available to either selection:

Application Summary—Generates an application listing showing the application name, CCCG level, description, and associated events for each application selected.

Calculation Results—Furnishes the application name, CCCG, average event redundancy, adjusted or unadjusted independent events, total number of events in application, included in total (events included in the calculation), system, component, failure mode, source, total events in application, alpha-model values, and associated events.

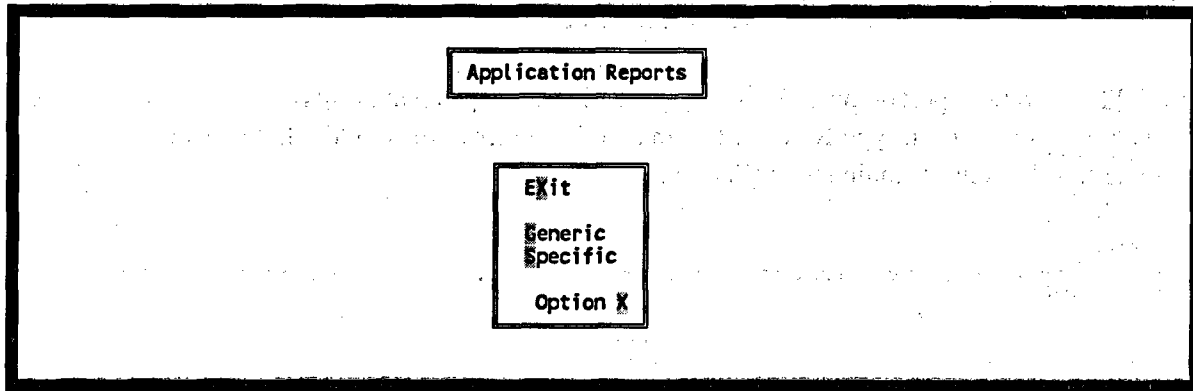


Figure 60. Application Reports menu.

Event Statistics—Provides the application name, component, a count of the total events that fall into the various CCCG, shock types, coupling factors, failure modes, and other CCF categories.

Detailed Events—Provides a hard copy of the CCF summary statistics, alpha model, event description, event analysis, and plant-specific impact vector assessments for each event in the application.

Whatever report type you select, a screen similar to the Select Applications screen will appear (Figure 62). This screen displays all applications currently contained in the database. On this screen, you must indicate the application or applications on which to base the report.

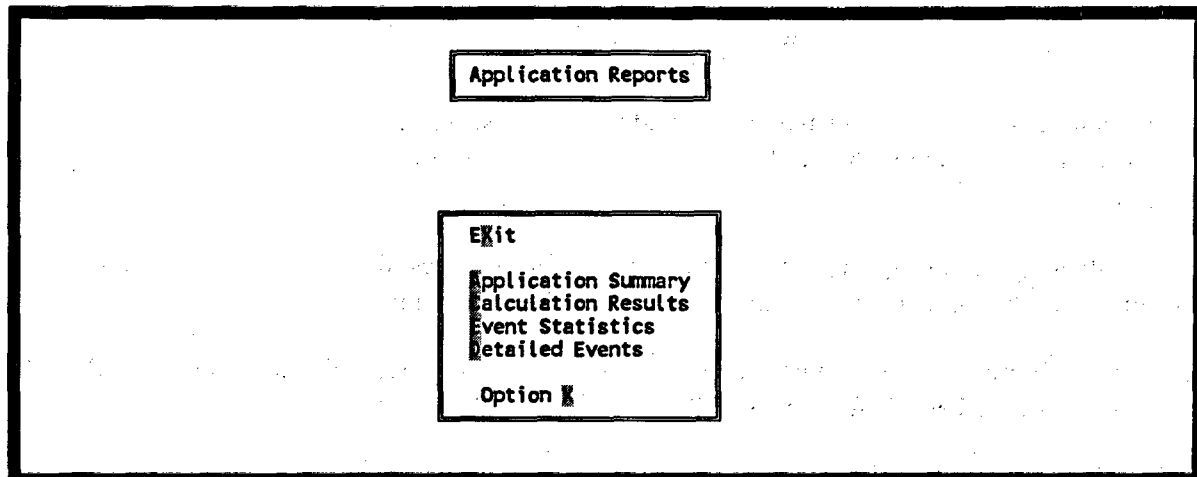


Figure 61. Application Reports options menu.

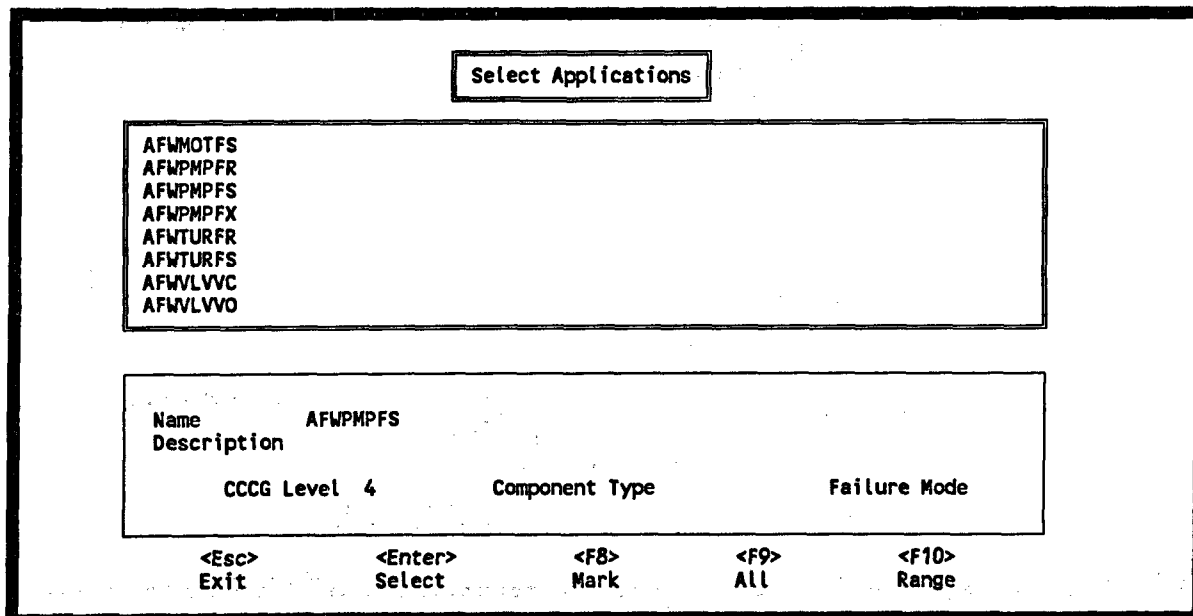


Figure 62. Select applications to report.

Select Applications provides the following functions:

- <Esc> Exit—Terminates the Select Applications screen and returns to the Application Reports menu.
- <Enter> Select—Chooses the currently highlighted application (or applications) for reporting. Press <Enter> to access the Report Option screen (Figure 63). CCF provides a default report title; however, you may change this by simply typing-over existing text. In addition, you must specify an output destination. As a default, the screen will display the report. However, you may change this to one of the following:
 - PRN Prints the report on the attached printer.
 - " " If the file name is left blank, no report will be generated.
 - <Esc> No report will be generated.
 - other Enter a valid DOS filename. The report will be printed to that file. This file can then be printed later or transferred to another machine via a diskette.

Once you supply an output destination, press <Enter>. The report will be generated.

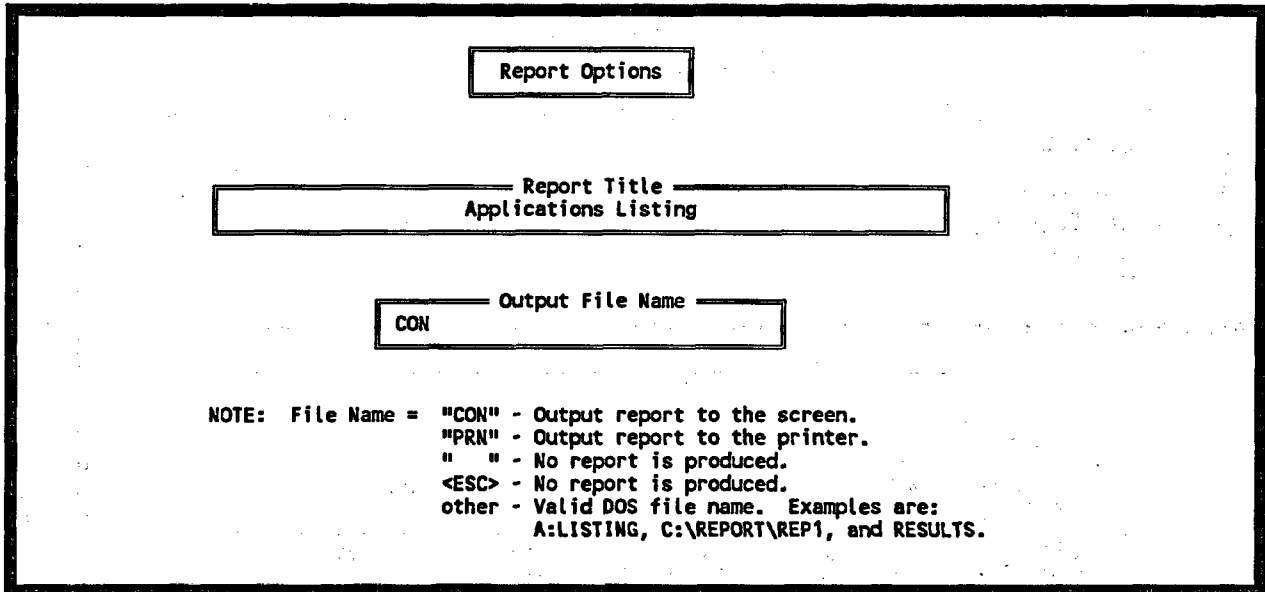


Figure 63. Report Options screen—Applications Listing.

5.2 Events

To produce this report, type E on the Reports main menu (Figure 59) or use the up and down arrow keys to highlight Events. Press <Enter> to access the Events Report screen (Figure 64). On this screen, you must indicate the sort order for the report. As shown, you can sort the report by plant name, system, component types, or failure modes. Sort the events by highlighting an order or select an order by entering the highlighted letter. Press <Enter> to access the Report Options screen (Figure 63). Refer to Section 5.1.

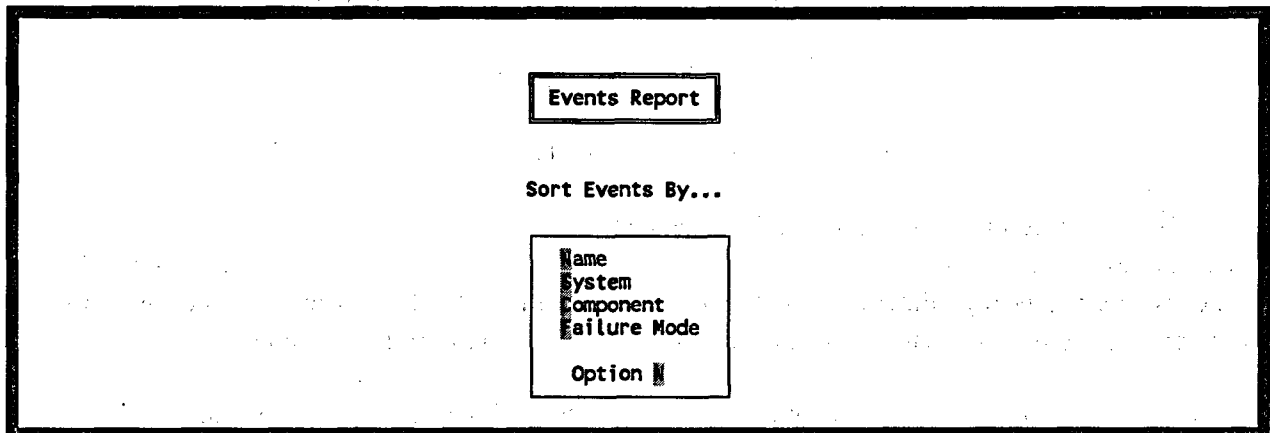


Figure 64. Select sort order for Events Report.

5.3 Event Text

To create this report, type a T on the Report main menu or use the up and down arrow keys to highlight Event Text. Press <Enter> to access the Event Reports screen (Figure 65). Select the events to report using <F8>, <F9>, and <F10> as described in Section 1.4. Once you have marked the events, press <Enter> to access the Report Options screen (Figure 63). Refer to Section 5.1.

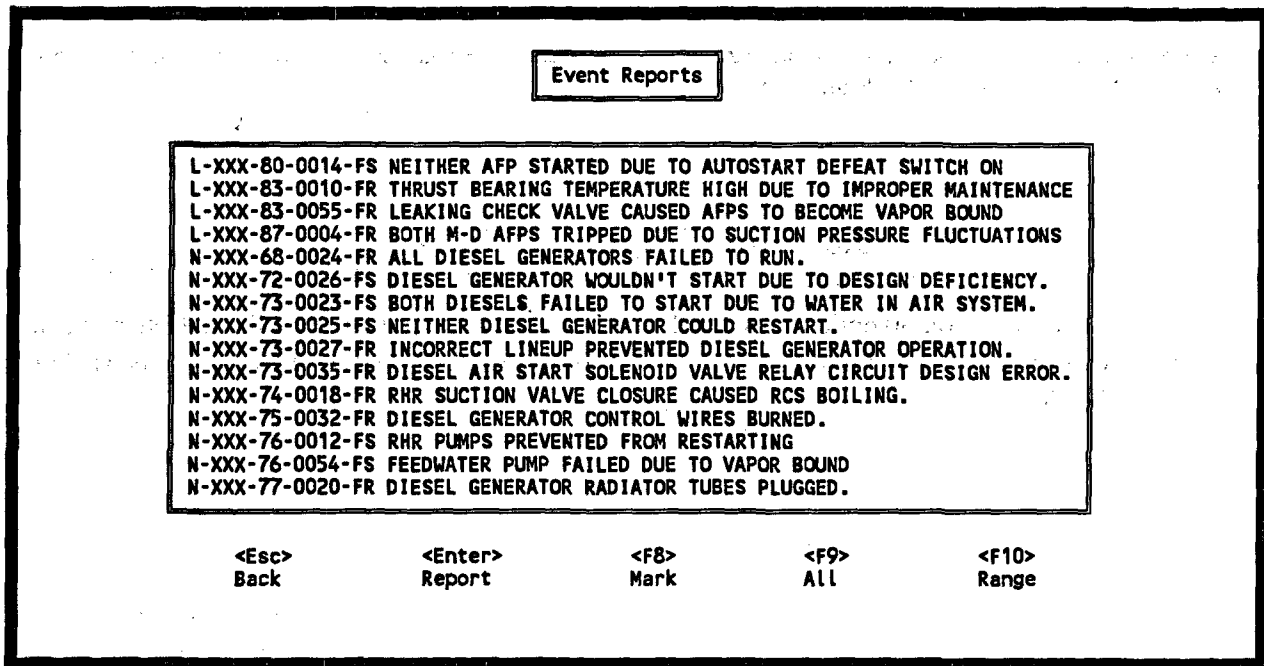


Figure 65. Select Event Report screen.

5.4 Plants

To start this report, type P on the Reports main menu or use the up and down arrow keys to highlight Plants. Press <Enter> to access the Plants Report screen (Figure 66). From this screen, you must indicate the sort order for the report. As shown, you can sort the plants by plant name or plant type. Select an order by entering the highlighted letter or highlighting Name or Type. Press <Enter> to access the Report options screen (Figure 63). Refer to Section 5.1.

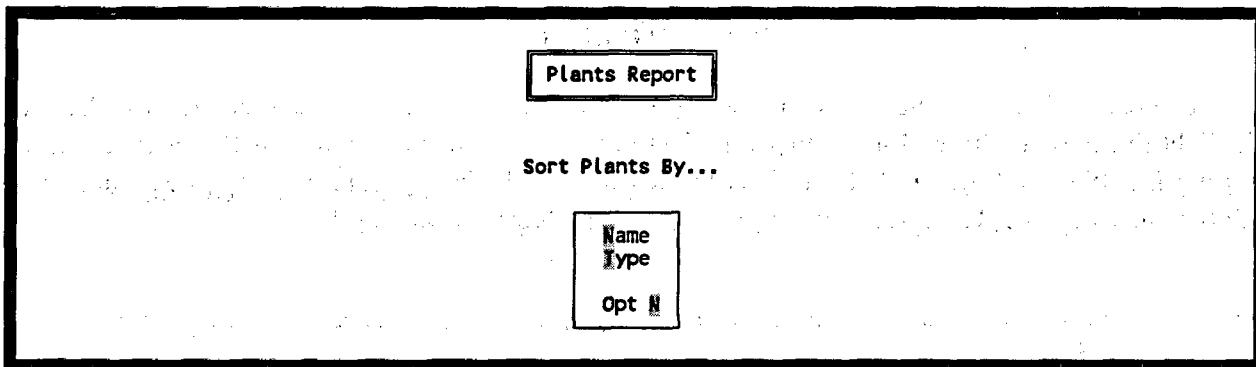


Figure 66. Select sort order for Plants Report.

5.5 Other Report Options

You can run the other report options listed in the Reports menu by typing the highlighted letter or using the up and down arrow keys to highlight option. Press <Enter> to access the Report Options screen (Figure 63). Refer to Section 5.1.

6. UTILITY

UTILITY rebuilds the database, changes the monitor type, calculates "what if" situations, converts parameters from one model to another, or changes your password. To select UTILITY, type U on the main menu or use the up and down arrow keys to highlight UTILITY. Press <Enter> to access the main menu of the Utilities screen (Figure 67). The following sections discuss each Utility option.

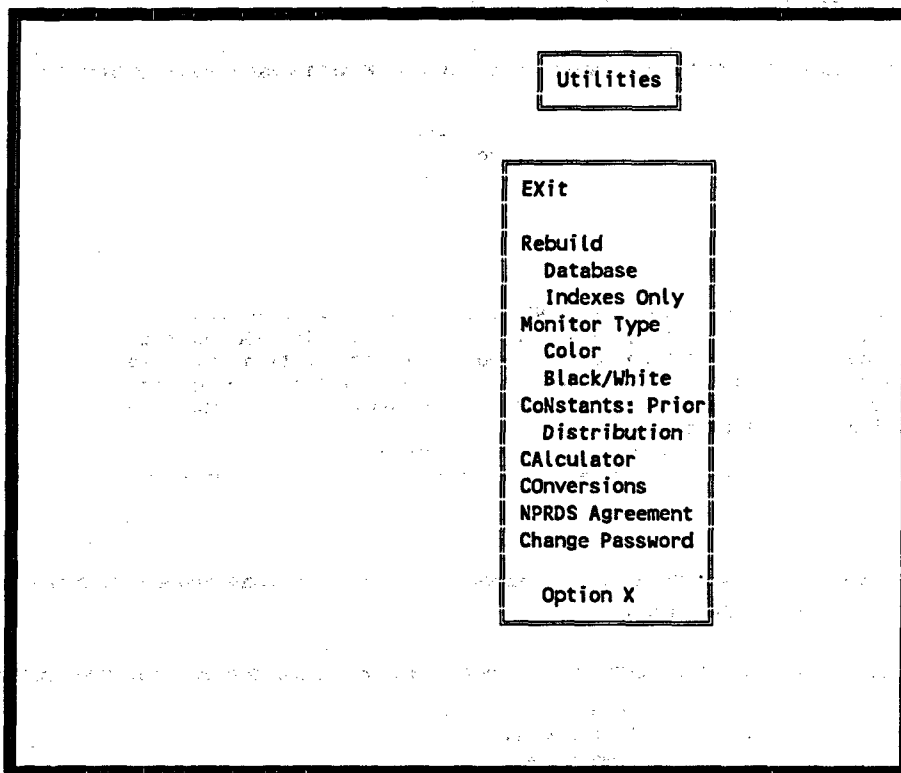


Figure 67. Utility main menu.

6.1 Rebuild

Rebuild restructures the database and re-indexes the data. If the data seems corrupted, perform a rebuild. However, you may rebuild the database anytime because the rebuild process compacts the data and generally helps the software run faster.

There are two types of rebuild: Database and Indexes Only. The Database option rebuilds all database files. The Indexes Only option reconstructs all index files (e.g., *.IDX). Use the Indexes Only option when access to data via the index files has been corrupted.

6.1.1 Database Option

If the database has been damaged, use the Database option to recover all data files; otherwise, use this option to restructure and optimize the database.

To recover the database, type **D** or use the up and down arrow keys to highlight Database. Press <Enter> to access the Database Recovery screen (Figure 68). Enter a **Y** and press <Enter> to continue, or enter an **N** and press <Enter> to terminate the rebuild process.

6.1.2 Indexes Only Option

To rebuild the indexes only, type **I** or use the up and down arrow keys to highlight Indexes Only. Press <Enter> to access the Index Recovery screen (Figure 69). Enter a **Y** and press <Enter> to continue, or enter an **N** and press <Enter> to terminate the rebuild process.

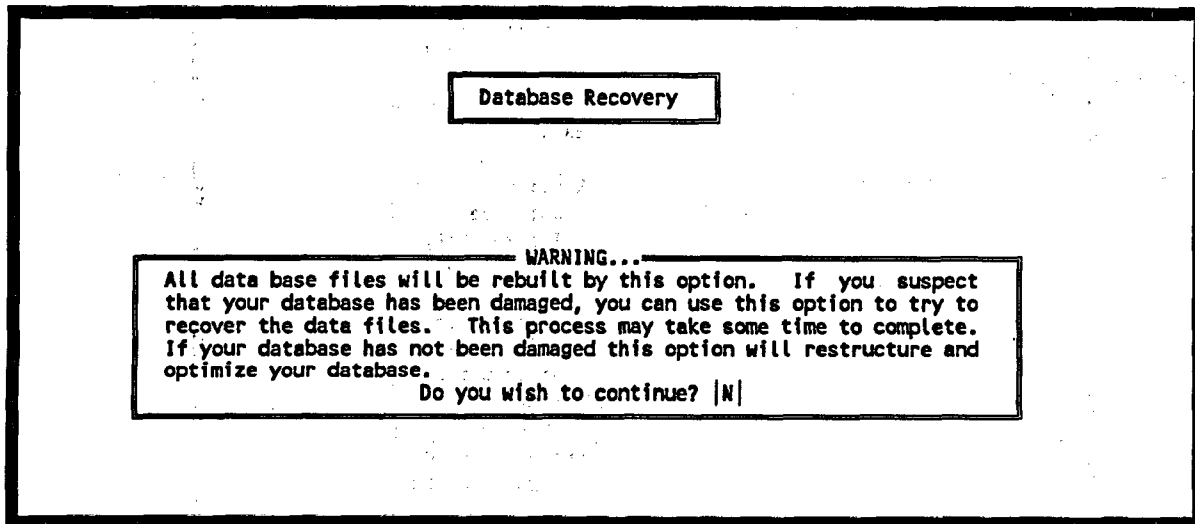


Figure 68. Database Recovery screen.

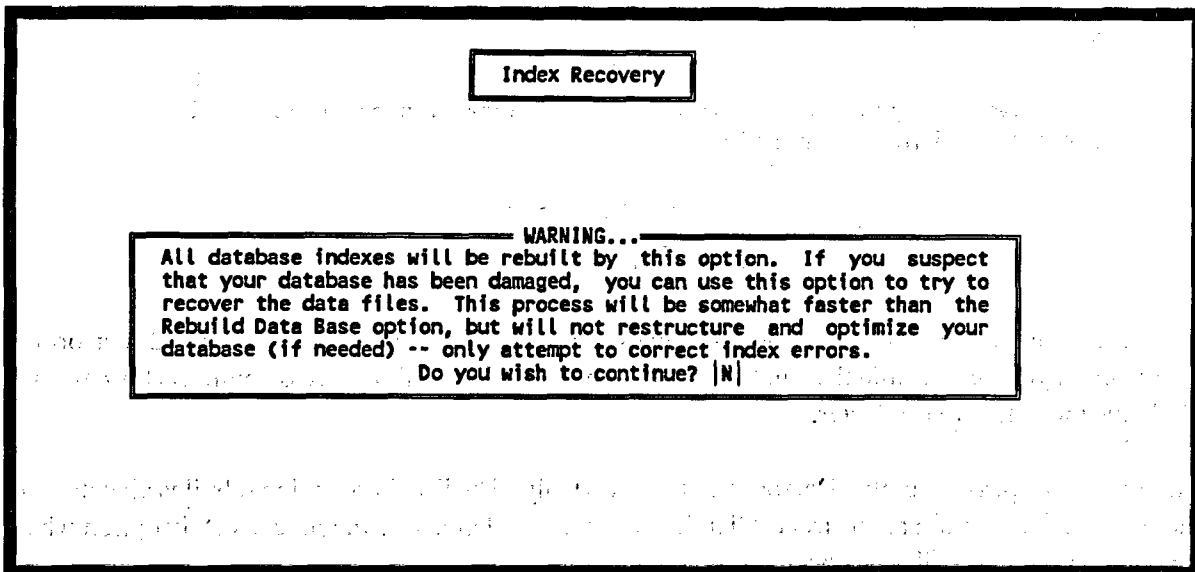


Figure 69. Index Recovery screen.

- Model** Enter an A (alpha) or M (Multiple Greek) to indicate type of modeling desired.
- Number of independent events** Enter the number of independent events associated with this application.
- CCCG level** Enter the number of redundant components in a system. This number ranges from 2 to 8.
- N1 to N8** Enter values to represent the total impact vectors for the number of events being postulated.

Calculator

Model (Alpha, Multiple Greek, Both)
 If Multiple Greek, Use Staggered? Y
 Number of independent events 0.00
 CCCG Size --

Expected Number of Events

N1	N2	N3	N4
N5	N6	N7	N8

<Esc>
Exit

<F1>
Help

<Enter>
Model

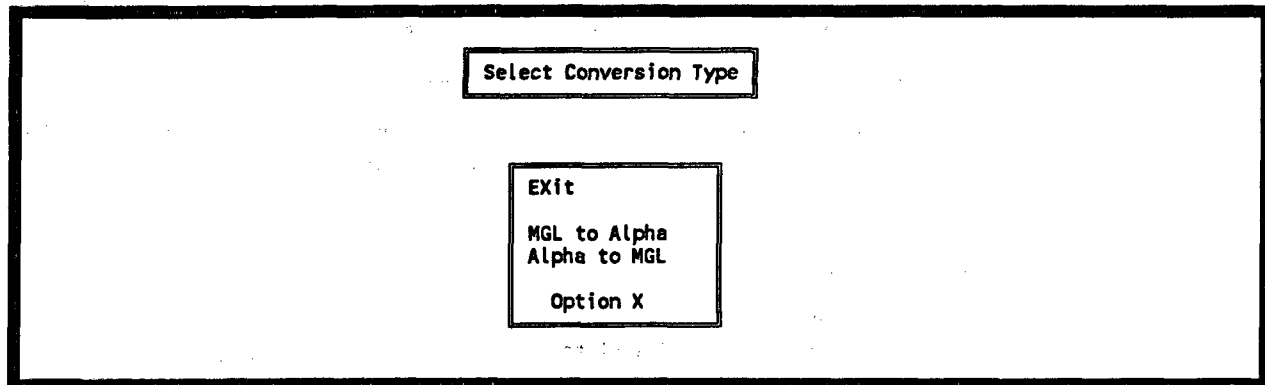
Figure 71. Calculator screen.

After you complete data entry, choose one of the following functions.

- <Esc>** Exit—Terminates the Calculator screen and returns to the Utilities menu.
- <Enter>** Model—Displays the point estimations for both models and the Bayesian Uncertainty for the Alpha-Factor Model. See Sections 3.4.1 and 3.4.2.

6.5 Conversions

Conversion allows you to convert parameters from the Multiple Greek Letter model to the equivalent parameters for the Alpha-Factor Model and vice-versa. Select Conversion by typing **O** from the utility main menu or using the up and down arrow keys to highlight the option. Press **<Enter>** to access the Select Conversion Type screen (Figure 72).



```

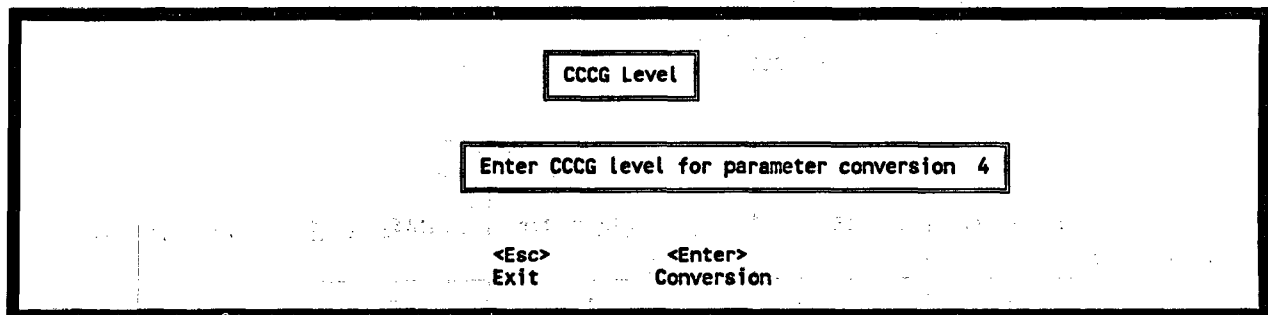
Select Conversion Type

EXIT
MGL to Alpha
Alpha to MGL
Option X

```

Figure 72. Select Conversion Type screen.

To initiate the process, type **M** for Multiple Greek Letter Distribution parameters or use the up and down arrow keys to highlight an option. Press **<Enter>** to access the CCCG Level screen (Figure 73).



```

CCCG Level

Enter CCCG level for parameter conversion 4

<Esc>      <Enter>
Exit       Conversion

```

Figure 73. CCCG Level screen.

Enter the CCCG level (from 2 to 8) for parameter conversion. Press **<Enter>** to access the conversion screen (Figure 74 or Figure 5).

MGL to ALPHA Conversion

CCCG Size 3

MGL INPUTS

Parameter	MLE
Beta	-----E-----
Gamma	-----E-----

ALPHA RESULTS

Parameter	MLE
$\alpha 1$	-----
$\alpha 2$	-----E-----
$\alpha 3$	-----E-----

Use Staggered Testing? Y

<Esc> <Enter>
 Exit Calculate

Figure 74. MGL to Alpha Conversion screen.

ALPHA to MGL Conversion

CCCG Size 3

ALPHA INPUTS

Parameter	MLE
$\alpha 1$	-----
$\alpha 2$	-----E-----
$\alpha 3$	-----E-----

MGL RESULTS

Parameter	MLE
1-Beta	-----E-----
Beta	-----E-----
Gamma	-----E-----

Use Staggered Testing? Y

<Esc> <Enter>
 Exit Calculate

Figure 75. Scaled Basic to Alpha Model Conversion screen.

Enter parameter values into the input field of the conversion screen, and press <Enter> to convert the initial parameters to Alpha-Factor Model parameters. Press <Esc> to return to the Select Conversion Type screen.

6.6 NPRDS Agreement

To view the NPRDS Agreement, press R or highlight NPRDS Agreement and press <Enter>. The NPRDS Agreement screen (Figure 76) will be displayed. Press the <Page Down> button to view the remainder of the agreement (Figure 77). Press the <Page Up> button to view the first page of the agreement (Figure 76). Press <Esc> to return to the utility menu.

6.7 Change Password

To change your password, press P or highlight Change Password and press <Enter>. Type in your current password to proceed to the Password Changing Utility screen (Figure 78). First CCF will ask you to "Type in desired password." Then press <Enter>. Next, CCF will ask you to "Retype Password to Verify." Press <Enter> to confirm your new password. CCF will confirm if it accepted your new password.

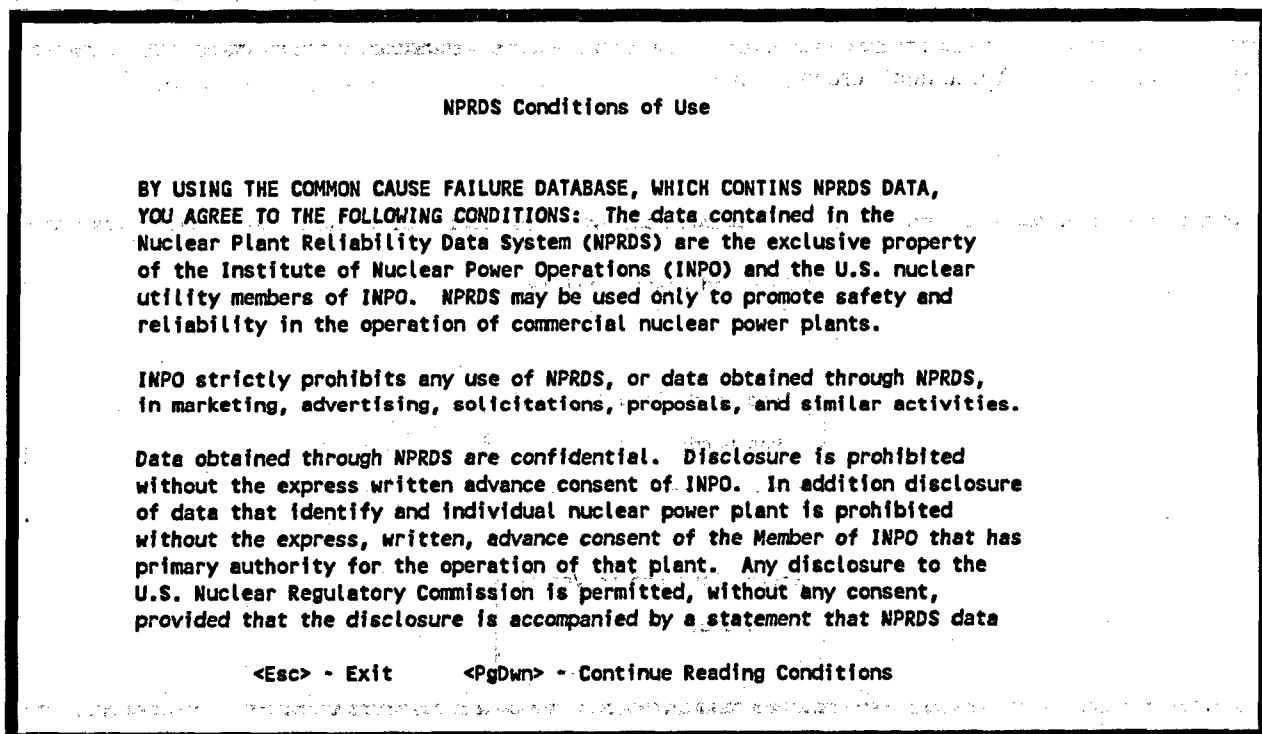


Figure 76. NPRDS Agreement screen.

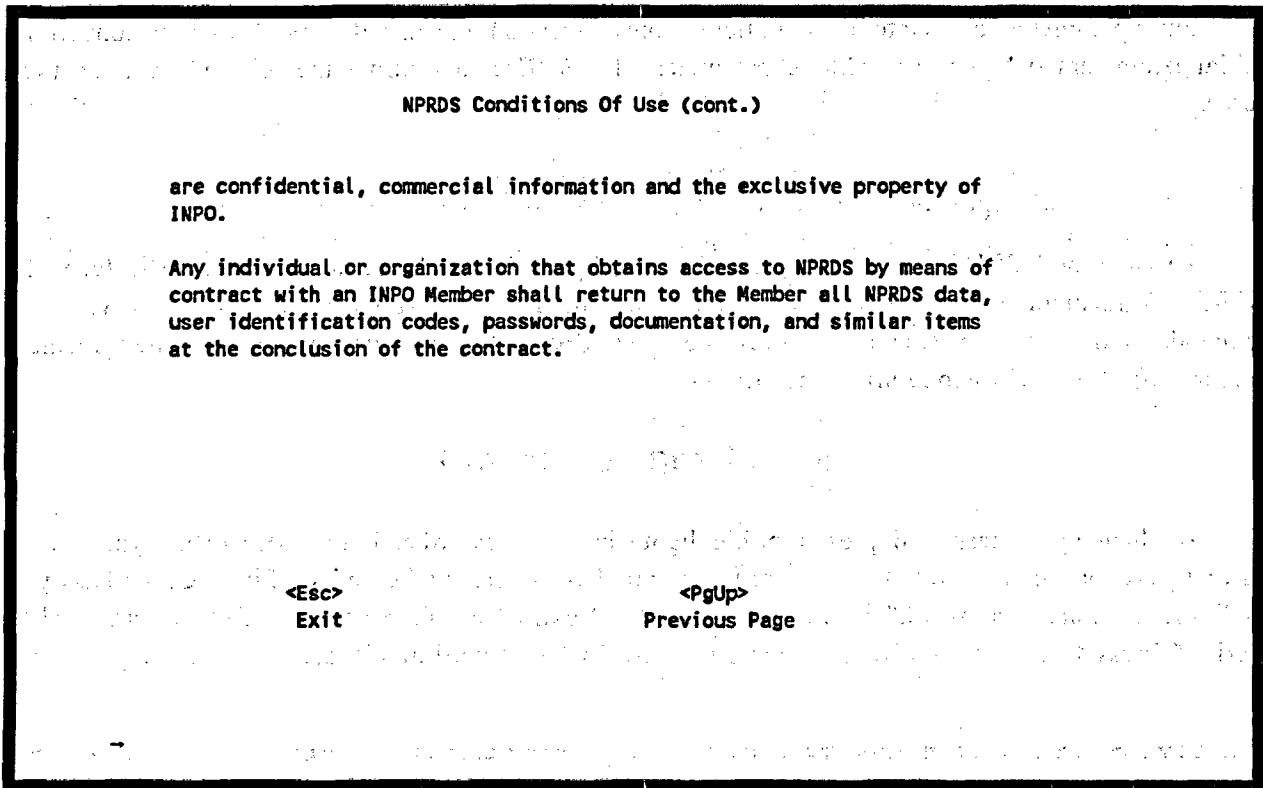


Figure 77. NPRDS Agreement screen (cont.).

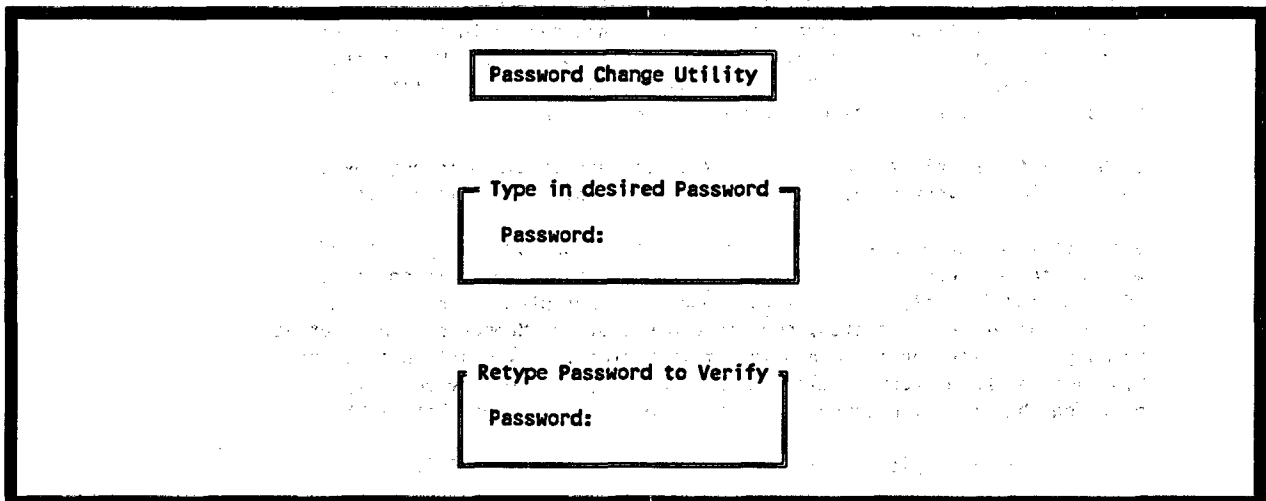


Figure 78. Password Change Utility screen.

7. REFERENCES

1. U.S. Nuclear Regulatory Commission, *Common Cause Failure Database and Analysis System, Volume 3, Data Collection and Event Coding*, NUREG/CR-6268, June 1998, INEEL/EXT-97-00696.
2. U.S. Nuclear Regulatory Commission, *Common Cause Failure Database and Analysis System Volume 2, Event Definition and Classification*, NUREG/CR-6268, June 1998, INEEL/EXT-97-00696.

SECRET-1851 A

1. The following information was obtained from a review of the files of the Central Intelligence Agency, Office of the Director, regarding the activities of the [redacted] in the [redacted] area.

2. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

3. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

4. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

5. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

6. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

7. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

8. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

9. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

10. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

11. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

12. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

13. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

14. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

15. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

16. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

17. The [redacted] was identified as a [redacted] of the [redacted] and was active in the [redacted] area during the period [redacted] to [redacted].

GLOSSARY

Application—A particular set of CCF events selected from the common cause failure database for use in a specific study.

Average Impact Vector—An average over the impact vectors for different hypotheses regarding the number of components failed in an event.

Basic Event—An event in a reliability logic model that represents the state in which a component or group of components is unavailable and does not require further development in terms of contributing causes.

Common Cause Event—A dependent failure in which two or more component fault states exist simultaneously, or within a short time interval, and are a direct result of a shared cause.

Common Cause Basic Event—In system modeling, a basic event that represents the unavailability of a specific set of components because of shared causes that are not explicitly represented in the system logic model as other basic events.

Common Cause Component Group—A group of (usually similar [in mission, manufacturer, maintenance, environment, etc.]) components that are considered to have a high potential for failure due to the same cause or causes.

Common Cause Failure Model—The basis for quantifying the frequency of common cause events. Examples include the beta factor, alpha factor, and basic parameter, and the binomial failure rate models.

Complete Common Cause Failure—A common cause failure in which all redundant components are failed simultaneously as a direct result of a shared cause; i.e., the component degradation value equals 1.0 for all components, and both the

timing factor and the shared cause factor are equal to 1.0.

Component—An element of plant hardware designed to provide a particular function.

Component Boundary—The component boundary encompasses the set of piece parts that are considered to form the component.

Component Degradation Value (p)—The assessed probability ($0.0 \leq p \leq 1.0$) that a functionally or physically degraded component would fail to complete the mission.

Component State—Component state defines the component status in regard to its intended function. Two general categories of component states are defined, *available* and *unavailable*.

- **Available**—The component is available if it is capable of performing its function according to a specified success criterion. (N.B., available is not the same as availability.)

- **Unavailable**—The component is unavailable if the component is unable to perform its intended function according to a stated success criterion. Two subsets of unavailable states are *failure* and *functionally unavailable*.

- **Failure**—The component is not capable of performing its specified operation according to a success criterion.

- **Functionally unavailable**—The component is capable of operation, but the function normally provided by the component is unavailable due to lack of proper input, lack of support function from a source outside the component (i.e., motive power, actuation signal), maintenance, testing, the improper interference of a person, etc.

• *Potentially unavailable*—The component is capable of performing its function according to a success criterion, but an incipient or degraded condition exists. (N.B., potentially unavailable is not synonymous with hypothetical.)

– *Degraded*—The component is in such a state that it exhibits reduced performance but insufficient degradation to declare the component unavailable according to the specified success criterion.

– *Incipient*—The component is in a condition that, if left unremedied, could ultimately lead to a degraded or unavailable state.

Coupling Factor/Mechanism—A set of causes and factors characterizing why and how a failure is systematically induced in several components.

Date—The date of the failure event, or date the failure was discovered.

Defense—Any operational, maintenance, and design measures taken to diminish the frequency and/or consequences of common cause failures.

Dependent Basic Events—Two or more basic events, A and B, are statistically dependent if, and only if,

$P[A \cap B] = P[B|A]P[A] = P[A|B]P[B] \neq P[A]P[B]$,
where P[X] denotes the probability of event X.

Event—An event is the occurrence of a component state or a group of component states.

Exposed Population—The set of components within the plant that are potentially affected by the common cause failure event under consideration.

Failure Mechanism—The history describing the events and influences leading to a given failure.

Failure Mode—A description of component failure in terms of the component function that was actually or potentially unavailable.

Failure Mode Applicability—The analyst's probability that the specified component failure mode for a given event is appropriate to the particular application.

Impact Vector—An assessment of the impact an event would have on a common cause component group. The impact is usually measured as the number of failed components out of a set of similar components in the common cause component group.

Independent Basic Events—Two basic events, A and B, are statistically independent if, and only if,

$$P[A \cap B] = P[A]P[B],$$

where P[X] denotes the probability of event X.

Mapping—The impact vector of an event must be "mapped up" or "mapped down" when the exposed population of the target plant is higher or lower than that of the original plant that experienced the common cause failure. The end result of mapping an impact vector is an adjusted impact vector applicable to the target plant.

Mapping Up Factor—A factor used to adjust the impact vector of an event when the exposed population of the target plan is higher than that of the original plant that experienced the common cause failure.

Potential Common Cause Failure—Any common cause event in which at least one component degradation value is less than 1.0.

Proximate Cause—A characterization of the condition that is readily identified as leading to failure of the component. It might alternatively be characterized as a symptom.

Reliability Logic Model—A logical representation of the combinations of component states that could lead to system failure. A fault tree is an example of a system logic model.

Root Cause—The most basic reason for a component failure which, if corrected, could prevent recurrence. The identified root cause may vary depending on the particular defensive strategy adopted against the failure mechanism.

Shared-Cause Factor (c)—A number that reflects the analyst's uncertainty ($0.0 \leq c \leq 1.0$) about the existence of coupling among the failures of two or more components, i.e., whether a shared cause of failure can be clearly identified.

Shock—A shock is an event that occurs at a random point in time and acts on the system; i.e., all the components in the system simultaneously.

There are two kinds of shocks distinguished by the potential impact of the shock event, i.e., *lethal* and *nonlethal*.

System—The entity that encompasses an interacting collection of components to provide a particular function or functions.

Timing Factor (q)—The probability ($0.0 \leq q \leq 1.0$) that two or more component failures (or degraded states) separated in time represent a common cause failure. This can be viewed as an indication of the strength-of-coupling in synchronizing failure times.

BIBLIOGRAPHIC DATA SHEET

(See Instructions on the reverse)

1. REPORT NUMBER
(Assigned by NRC, Add Vol.,
Supp., Rev., and Addendum
Numbers, if any.)
NUREG/CR-6268
INEEL/EXT-97-00696

2. TITLE AND SUBTITLE

Common Cause Failure Database and Analysis System
Volume 4 – Software Reference Manual

3. DATE REPORT PUBLISHED

MONTH	YEAR
June	1998

4. FIN OR GRANT NUMBER
E8247

5. AUTHOR(S)

F. M. Marshall, K. J. Kvarfordt, M. J. Cebull, S. T. Wood, and A. Mosleh, University of Maryland

6. TYPE OF REPORT
Technical

7. PERIOD COVERED (Inclusive Dates)
N/A

8. PERFORMING ORGANIZATION - NAME AND ADDRESS (If NRC, provide Division, Office or Region, U.S. Nuclear Regulatory Commission, and mailing address; if contractor, provide name and mailing address.)

Idaho National Engineering and Environmental Laboratory
Lockheed Martin Idaho Technologies Co.
P.O. Box 1625
Idaho Falls, ID 83415-3129

9. SPONSORING ORGANIZATION - NAME AND ADDRESS (If NRC, type "Same as above"; if contractor, provide NRC Division, Office or Region, U.S. Nuclear Regulatory Commission, and mailing address.)

Safety Programs Division
Office for Analysis and Evaluation of Operational Data
U.S. Nuclear Regulatory Commission
Washington, DC 20555-0001

Subcontractor:
Department of Materials and
Nuclear Engineering
University of Maryland
College Park, MD 20742-2115

10. SUPPLEMENTARY NOTES

11. ABSTRACT (200 words or less)

This volume of the Common-Cause Failure Database and Analysis System report provides an overview of common cause failure methods for use in the U.S. commercial nuclear power industry. It summarizes how data (on common cause failure events) are gathered, evaluated, and coded. It then describes the process for estimating probabilistic risk assessment (PRA) common cause failure parameters. It also references other volumes of this report for specific details.

Equipment failures that contribute to common cause failure events are identified through searches of Licensee Event Reports (LERs) and Nuclear Plant Reliability Data System (NPRDS) failure reports. Once common cause failure events are identified by reviewing reports of equipment failures, INEEL staff enters the event information into a personal computer data analysis system (CCF system) using the method presented in this and companion volumes. The events stored in the CCF system are utilized for common cause failure PRA parameter estimations using common cause failure quantification methods.

12. KEY WORDS/DESCRIPTORS (List words or phrases that will assist researchers in locating the report.)

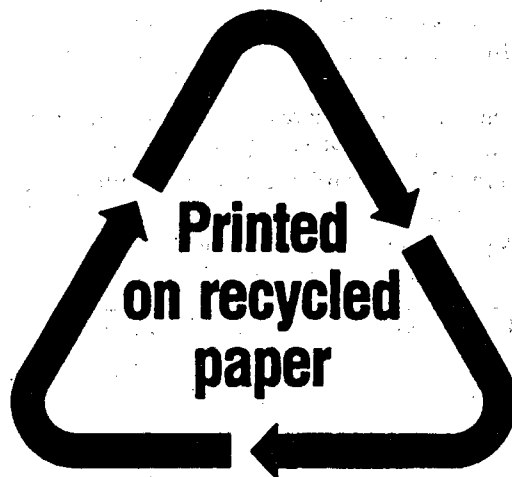
Common cause failure

13. AVAILABILITY STATEMENT
Unlimited

14. SECURITY CLASSIFICATION
(This page)
Unclassified
(This report)
Unclassified

15. NUMBER OF PAGES

16. PRICE



Federal Recycling Program

UNITED STATES
NUCLEAR REGULATORY COMMISSION
WASHINGTON, DC 20555-0001

OFFICIAL BUSINESS
PENALTY FOR PRIVATE USE, \$300

SPECIAL STANDARD MAIL
POSTAGE AND FEES PAID
USNRC
PERMIT NO. G-67